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PART 2 RF EXPOSURE EVALUATION REPORT

Applicant Name:

Samsung Electronics Co., Ltd. 129, Samsung-ro, Maetan dong, Yeongtong-gu, Suwon-si Gyeonggi-do, 16677, Korea Date of Testing: 1/21/2021 – 3/2/2021 Test Site/Location: PCTEST, Columbia, MD, USA Document Serial No.: 1M2101040001-21.A3L

FCC ID:

A3LSMA426U

APPLICANT:

SAMSUNG ELECTRONICS CO., LTD.

DUT Type: Application Type: FCC Rule Part(s): Model: Additional Model: Device Serial Numbers: Portable Handset Certification CFR §2.1093 SM-A426U SM-A426U1, SM-A426U1/DS, SM-S426DL Pre-Production Samples [13250, 13342, 01800, 51755, 01636]

I attest to the accuracy of data. All measurements reported herein were performed by me or were made under my supervision and are correct to the best of my knowledge and belief. I assume full responsibility for the completeness of these measurements and vouch for the qualifications of all persons taking them. Test results reported herein relate only to the item(s) tested.

Randy Ortanez President



FCC ID: A3LSMA426U	Poctest Proud to be part of @ element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager
Document S/N:	Test Dates:	DUT Type:		Dogo 1 of 08
1M2101040001-21.A3L	1/21/2021-3/2/2021	Portable Handset		Page 1 of 98
© 2021 PCTEST				REV 1.0

REV 1.0 04/06/2020

TABLE OF CONTENTS

1	DEVICE U	INDER TEST	.3
2	RF EXPO	SURE LIMITS	.5
3	TIME VAR	RYING TRANSMISSION TEST CASES	7
4	FCC MEA	SUREMENT PROCEDURES (FREQ < 6 GHZ)	10
5	FCC MEA	SUREMENT PROCEDURES (FREQ > 6 GHZ)	21
6	MEASURI	EMENT TEST SETUP (FREQ < 6 GHZ)	28
7	MEASURI	EMENT TEST SETUP (FREQ > 6 GHZ)	31
8	TEST CO	NFIGURATIONS (FREQ < 6 GHZ)	33
9	CONDUC	TED TX CASES (FREQ < 6 GHZ)	36
10	SYSTEM	VERIFICATION (FREQ < 6 GHZ)	64
11	SAR TES	T RESULTS (FREQ < 6 GHZ)	66
12	TEST CO	NFIGURATIONS (FREQ > 6 GHZ)	74
13	RADIATE	D POWER TX CASES (FREQ > 6 GHZ)	77
14	SYSTEM	VERIFICATION (FREQ > 6 GHZ)	89
15	POWER D	DENSITY TEST RESULTS (FREQ > 6 GHZ)	90
16	EQUIPME	NT LIST	93
17	MEASURI	EMENT UNCERTAINTIES	94
18	CONCLUS	SION	96
19	REFEREN	ICES	97
APPENI	DIX A:	VERIFICATION PLOTS	
APPENI	DIX B:	SAR TISSUE SPECIFICATIONS	
APPENI	DIX C:	SAR SYSTEM VALIDATION	
APPENI	DIX D:	TEST SETUP PHOTOGRAPHS	
APPENI	DIX E:	TEST SEQUENCES	
APPENI	DIX F:	TEST PROCEDURES FOR SUB6 NR + NR RADIO	

APPENDIX G: CALIBRATION CERTIFICATES

FCC ID: A3LSMA426U	Proud to be part of @ element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager
Document S/N:	Test Dates:	DUT Type:		Dage 2 of 00
1M2101040001-21.A3L	1/21/2021-3/2/2021	Portable Handset		Page 2 of 98
© 2021 PCTEST				REV 1.0

DEVICE UNDER TEST 1

1.1 **Device Overview**

Band & Mode	Operating Modes	Tx Frequency
CDMA/EVDO BC10 (§90S)	Voice/Data	817.90 - 823.10 MHz
CDMA/EVDO BC0 (§22H)	Voice/Data	824.70 - 848.31 MHz
PCS CDMA/EVDO	Voice/Data	1851.25 - 1908.75 MHz
GSM/GPRS/EDGE 850	Voice/Data	824.20 - 848.80 MHz
GSM/GPRS/EDGE 1900	Voice/Data	1850.20 - 1909.80 MHz
UMTS 850	Voice/Data	826.40 - 846.60 MHz
UMTS 1750	Voice/Data	1712.4 - 1752.6 MHz
UMTS 1900	Voice/Data	1852.4 - 1907.6 MHz
LTE Band 71	Voice/Data	665.5 - 695.5 MHz
LTE Band 12	Voice/Data	699.7 - 715.3 MHz
LTE Band 13	Voice/Data	779.5 - 784.5 MHz
LTE Band 14	Voice/Data	790.5 - 795.5 MHz
LTE Band 26 (Cell)	Voice/Data	814.7 - 848.3 MHz
LTE Band 5 (Cell)	Voice/Data	824.7 - 848.3 MHz
LTE Band 66 (AWS)	Voice/Data	1710.7 - 1779.3 MHz
LTE Band 4 (AWS)	Voice/Data	1710.7 - 1754.3 MHz
LTE Band 25 (PCS)	Voice/Data	1850.7 - 1914.3 MHz
LTE Band 2 (PCS)	Voice/Data	1850.7 - 1909.3 MHz
LTE Band 30	Voice/Data	2307.5 - 2312.5 MHz
LTE Band 7	Voice/Data	2502.5 - 2567.5 MHz
LTE Band 48	Voice/Data	3552.5 - 3697.5 MHz
LTE Band 41	Voice/Data	2498.5 - 2687.5 MHz
NR Band n71	Data	665.5 - 695.5 MHz
NR Band n5 (Cell)	Data	826.5 - 846.5 MHz
NR Band n66 (AWS)	Data	1712.5 - 1777.5 MHz
NR Band n25 (PCS)	Data	1852.5 - 1912.5 MHz
NR Band n2 (PCS)	Data	1852.5 - 1907.5 MHz
NR Band n41	Data	2506.02 - 2679.99 MHz
NR Band n77	Data	3750 - 3930 MHz
NR Band n260	Data	37000 - 40000 MHz
NR Band n261	Data	27500 - 28350 MHz
2.4 GHz WLAN	Voice/Data	2412 - 2472 MHz
U-NII-1	Voice/Data	5180 - 5240 MHz
U-NII-2A	Voice/Data	5260 - 5320 MHz
U-NII-2C	Voice/Data	5500 - 5720 MHz
U-NII-3	Voice/Data	5745 - 5825 MHz
Bluetooth	Data	2402 - 2480 MHz
NFC	Data	13.56 MHz

FCC ID: A3LSMA426U		PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager
Document S/N:	Test Dates:	DUT Type:		Dage 2 of 08
1M2101040001-21.A3L	1/21/2021-3/2/2021	Portable Handset		Page 3 of 98
© 2021 PCTEST				REV 1.0

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1.2 Time-Averaging Algorithm for RF Exposure Compliance

This device is enabled with Qualcomm® Smart Transmit feature. This feature performs time averaging algorithm in real time to control and manage transmitting power and ensure the time-averaged RF exposure is in compliance with FCC requirements all the time. DUT contains embedded file system (EFS) version 15 configured for the first generation (GEN1).

The Smart Transmit algorithm maintains the time-averaged transmit power, in turn, time-averaged RF exposure of SAR_design_target or PD_design_target, below the predefined time-averaged power limit (i.e., Plimit for sub-6 radio, and input.power.limit for 5G mmW NR), for each characterized technology and band.

Smart Transmit allows the device to transmit at higher power instantaneously, as high as P_{max} , when needed, but enforces power limiting to maintain time-averaged transmit power to P_{limit} for frequencies < 6 GHz and *input.power.limit* for frequencies > 6 GHz.

Note that the device uncertainty for sub-6GHz WWAN is 1.0dB for this DUT, the device uncertainty for mmW is 2.1 dB, and the reserve power margin is 3 dB.

This purpose of the Part 2 report is to demonstrate the DUT complies with FCC RF exposure requirement under Tx varying transmission scenarios, thereby validity of Qualcomm[®] Smart Transmit feature implementation in this device. It serves to compliment the Part 0 and Part 1 Test Reports to justify compliance per FCC.

1.3 Bibliography

Report Type	Report Serial Number
Part 0 SAR Test Report	1M2101040001-23.A3L
Part 1 SAR Test Report	1M2101040001-01.A3L
Part 0 Power Density Test Report	1M2101040001-26.A3L
Part 1 Power Density Test Report	1M2101040001-20.A3L
RF Exposure Compliance Summary	1M2101040001-22.A3L

FCC ID: A3LSMA426U	PCTEST* Proud to be part of @ element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager
Document S/N:	Test Dates:	DUT Type:		
1M2101040001-21.A3L	1/21/2021-3/2/2021	Portable Handset		Page 4 of 98
© 2021 PCTEST				REV 1.0

04/06/2020

2 RF EXPOSURE LIMITS

2.1 Uncontrolled Environment

UNCONTROLLED ENVIRONMENTS are defined as locations where there is the exposure of individuals who have no knowledge or control of their exposure. The general population/uncontrolled exposure limits are applicable to situations in which the general public may be exposed or in which persons who are exposed as a consequence of their employment may not be made fully aware of the potential for exposure or cannot exercise control over their exposure. Members of the general public would come under this category when exposure is not employment-related; for example, in the case of a wireless transmitter that exposes persons in its vicinity.

2.2 Controlled Environment

CONTROLLED ENVIRONMENTS are defined as locations where there is exposure that may be incurred by persons who are aware of the potential for exposure, (i.e. as a result of employment or occupation). In general, occupational/controlled exposure limits are applicable to situations in which persons are exposed as a consequence of their employment, who have been made fully aware of the potential for exposure and can exercise control over their exposure. This exposure category is also applicable when the exposure is of a transient nature due to incidental passage through a location where the exposure levels may be higher than the general population/uncontrolled limits, but the exposed person is fully aware of the potential for exposure and can exercise control over his or her exposure by leaving the area or by some other appropriate means.

2.3 RF Exposure Limits for Frequencies Below 6 GHz

HUN	1AN EXPOSURE LIMITS	
	UNCONTROLLED ENVIRONMENT General Population (W/kg) or (mW/g)	CONTROLLED ENVIRONMENT Occupational (W/kg) or (mW/g)
Peak Spatial Average SAR Head	1.6	8.0
Whole Body SAR	0.08	0.4
Peak Spatial Average SAR Hands, Feet, Ankle, Wrists, etc.	4.0	20

Table 2-1 SAR Human Exposure Specified in ANSI/IEEE C95.1-1992 and Health Canada Safety Code 6

1. The Spatial Peak value of the SAR averaged over any 1 gram of tissue (defined as a tissue volume in the shape of a cube) and over the appropriate averaging time.

2. The Spatial Average value of the SAR averaged over the whole body.

3. The Spatial Peak value of the SAR averaged over any 10 grams of tissue (defined as a tissue volume in the shape of a cube) and over the appropriate averaging time.

FCC ID: A3LSMA426U	Pour lo be part of @ element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager	
Document S/N:	Test Dates:	DUT Type:		Page 5 of 98	
1M2101040001-21.A3L	1/21/2021-3/2/2021	Portable Handset			
© 2021 PCTEST		•		REV 1.0	

REV 1.0 04/06/2020

2.4 **RF Exposure Limits for Frequencies Above 6 GHz**

Per §1.1310 (d)(3), the MPE limits are applied for frequencies above 6 GHz. Power Density is expressed in units of W/m² or mW/cm².

Peak Spatially Averaged Power Density was evaluated over a circular area of 4 cm² per interim FCC Guidance for near-field power density evaluations per October 2018 TCB Workshop notes.

Table 2-2 Human Exposure Limits Specified in FCC 47 CFR §1.1310				
Human Expos	Human Exposure to Radiofrequency (RF) Radiation Limits			
Frequency Range [MHz]Power Density [mW/cm2]Averaging Time [Minutes]				
(A) Limit	s for Occupational / Controlled I	Invironments		
1,500 - 100,000	5.0	6		
(B) Limits for General Population / Uncontrolled Environments				
1,500 – 100,000	1.0	30		

Note: 1.0 mW/cm² is 10 W/m²

2.5 **Time Averaging Windows for FCC Compliance**

Per October 2018 TCB Workshop Notes, the below time-averaging windows can be used for assessing timeaveraged exposures for devices that are capable of actively monitoring and adjusting power output over time to comply with exposure limits.

Interim Guidance	Frequency (GHz)	Maximum Averaging Time (sec)
SAR	< 3	100
SAN	3 – 6	60
	6 - 10	30
	10 - 16	14
	16 – 24	8
MPE	24 - 42	4
	42 - 95	2

FCC ID: A3LSMA426U		PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager
Document S/N:	Test Dates:	DUT Type:		Dage 6 of 00
1M2101040001-21.A3L	1/21/2021-3/2/2021	Portable Handset		Page 6 of 98
© 2021 PCTEST				REV 1.0

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3 TIME VARYING TRANSMISSION TEST CASES

To validate the time averaging feature and demonstrate the compliance in Tx varying transmission conditions, the following transmission scenarios are covered in the Part 2 test:

- 1. During a time-varying Tx power transmission: To prove that the Smart Transmit feature accounts for Tx power variations in time accurately.
- 2. During a call disconnect and re-establish scenario: To prove that the Smart Transmit feature accounts for history of past Tx power transmissions accurately.
- 3. During a technology/band handover: To prove that the Smart Transmit feature functions correctly during transitions in technology/band.
- 4. During a DSI (Device State Index) change: To prove that the Smart Transmit feature functions correctly during transition from one device state (DSI) to another.
- 5. During an antenna (or beam) switch: To prove that the Smart Transmit feature functions correctly during transitions in antenna (such as AsDiv scenario) or beams (different antenna array configurations) or beams (different antenna array configurations).
- 6. SAR vs. PD exposure switching during sub-6+mmW transmission: To prove that the Smart Transmit feature functions correctly and ensures total RF exposure compliance during transitions in SAR dominant exposure, SAR+PD exposure, and PD dominant exposure scenarios.
- 7. During time window switch: To prove that the Smart Transmit feature correctly handles the transition from one time window to another specified by FCC, and maintains the normalized time-averaged RF exposure to be less than normalized FCC limit of 1.0 at all times.
- 8. SAR exposure switching between two active radios (radio1 and radio2): To prove that the Smart Transmit feature functions correctly and ensures total RF exposure compliance when exposure varies among SAR_radio1 only, SAR_radio1 + SAR_radio2, and SAR_radio2 only scenarios.

As described in Part 0 report, the RF exposure is proportional to the Tx power for a SAR- and PD-characterized wireless device. Thus, feature validation in Part 2 can be effectively performed through conducted (for f < 6GHz) and radiated (for $f \ge 6GHz$) power measurement. Therefore, the compliance demonstration under dynamic transmission conditions and feature validation are done in conducted/radiated power measurement setup for transmission scenario 1 through 8.

To add confidence in the feature validation, the time-averaged SAR and PD measurements are also performed but only performed for transmission scenario 1 to avoid the complexity in SAR and PD measurement (such as, for scenario 3 requiring change in SAR probe calibration file to accommodate different bands and/or tissue simulating liquid).

The strategy for testing in Tx varying transmission condition is outlined as follows:

- Demonstrate the total RF exposure averaged over FCC defined time windows does not exceed FCC's SAR and PD limits, through <u>time-averaged power</u> measurements
 - Measure conducted Tx power (for f < 6GHz) versus time, and radiated Tx power (EIRP for f > 10GHz) versus time.
 - Convert it into RF exposure and divide by respective FCC limits to get normalized exposure versus time.
 - o Perform running time-averaging over FCC defined time windows.
 - Demonstrate that the total normalized time-averaged RF exposure is less than 1 for all transmission scenarios (i.e., transmission scenarios 1, 2, 3, 4, 5, 6, 7, and 8) at all times.

FCO	C ID: A3LSMA426U	Proud to be part of @ element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager
Doc	ument S/N:	Test Dates:	DUT Type:		Dage 7 of 09
1M2	101040001-21.A3L	1/21/2021-3/2/2021	Portable Handset		Page 7 of 98
@ 2024	DOTEOT				DEV/10

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REV 1.0 04/06/2020 Mathematical expression:

For < 6 GHz transmission only:

$$1g_{or_{1}0gSAR(t)} = \frac{conducted_{Tx_power(t)}}{conducted_{Tx_power_{limit}}} * 1g_{or_{1}0gSAR_{limit}}$$
(1a)

$$\frac{\frac{1}{T_{SAR}}\int_{t-T_{SAR}}^{t} 1g_or_10gSAR(t)dt}{FCC SAR limit} \le 1$$
(1b)

For sub-6+mmW transmission:

$$1g_or_10gSAR(t) = \frac{conducted_Tx_power(t)}{conducted_Tx_power_P_{limit}} * 1g_or_10gSAR_P_{limit}$$
(2a)

$$4cm^{2}PD(t) = \frac{radiated_{Tx_power(t)}}{radiated_{Tx_power_input.power.limit}} * 4cm^{2}PD_{input.power.limit}$$

$$\frac{\frac{1}{T_{SAR}}\int_{t-T_{SAR}}^{t} 1g_{-}or_{-}10gSAR(t)dt}{FCC\,SAR\,limit} + \frac{\frac{1}{T_{PD}}\int_{t-T_{PD}}^{t} 4cm^{2}PD(t)dt}{FCC\,4cm^{2}\,PD\,limit} \le 1$$
(2c)

- where, *conducted_Tx_power(t)*, *conducted_Tx_power_P_{limit}*, and 1g_or_10gSAR_P_{limit} correspond to the measured instantaneous conducted Tx power, measured conducted Tx power at *P_{limit}*, and measured 1gSAR *or 10gSAR* values at *P_{limit}* corresponding to sub-6 transmission. Similarly, *radiated_Tx_power(t)*, *radiated_Tx_power_input.power.limit*, and 4cm²PD_input.power.limit correspond to the measured instantaneous radiated Tx power, radiated Tx power at *input.power.limit* (i.e., radiated power limit), and 4cm²PD value at *input.power.limit* corresponding to mmW transmission. Both *P_{limit}* and *input.power.limit* are the parameters pre-defined in Part 0 and loaded via Embedded File System (EFS) onto the EUT. *T_{SAR}* is the FCC defined time window for sub-6 radio; *T_{PD}* is the FCC defined time window for mmW radio.
 - Demonstrate the total RF exposure averaged over FCC defined time windows does not exceed FCC's SAR and PD limits, through time-averaged SAR and PD measurements. Note as mentioned earlier, this measurement is performed for transmission scenario 1 only.
 - For sub-6 transmission only, measure instantaneous SAR versus time; for LTE+sub6 NR transmission, request low power (or all-down bits) on LTE so that measured SAR predominantly corresponds to sub6 NR.
 - For LTE + mmW transmission, measure instantaneous E-field versus time for mmW radio and instantaneous conducted power versus time for LTE radio.
 - Convert it into RF exposure and divide by respective FCC limits to obtain normalized exposure versus time.
 - Perform time averaging over FCC defined time window.
 - Demonstrate that the total normalized time-averaged RF exposure is less than 1 for transmission scenario 1 at all times.

FCC ID: A3LSMA426U	Proud to be part of @ element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager
Document S/N:	Test Dates:	DUT Type:		Daga 9 of 09
1M2101040001-21.A3L	1/21/2021-3/2/2021	Portable Handset		Page 8 of 98
© 2021 PCTEST				REV 1.0

^{04/06/2020}

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Mathematical expression:

For sub-6 transmission only:

$$1g_or_10gSAR(t) = \frac{pointSAR(t)}{pointSAR_P_{limit}} * 1g_or_10gSAR(t)_P_{limit}$$
(3a)

$$\frac{\frac{1}{T_{SAR}}\int_{t-T_{SAR}}^{t} 1g_{-}or_{-}10gSAR(t)dt}{FCC SAR limit} \le 1$$
(3b)

For LTE+mmW transmission:

$$1g_or_10gSAR(t) = \frac{conducted_Tx_power(t)}{conducted_Tx_power_P_{limit}} * 1g_or_10gSAR_P_{limit}$$
(4a)

 $4cm^2 PD(t) = \frac{[pointE(t)]^2}{[pointE_input.power.limit]^2} * 4cm^2 PD_input.power.limit$ (4b)

$$\frac{\frac{1}{T_{SAR}}\int_{t-T_{SAR}}^{t} 1g_{-}or_{-}10gSAR(t)dt}{FCC SAR limit} + \frac{\frac{1}{T_{PD}}\int_{t-T_{PD}}^{t} 4cm^{2}PD(t)dt}{FCC 4cm^{2}PD limit} \le 1$$
(4c)

where, pointSAR(t), $pointSAR_P_{limit}$, and $1g_or_10gSAR_P_{limit}$ correspond to the measured instantaneous point SAR, measured point SAR at P_{limit} , and measured 1gSARor 10gSAR values at P_{limit} corresponding to sub-6 transmission. Similarly, pointE(t), pointE_input.power.limit, and 4cm²PD_input.power.limit correspond to the measured instantaneous E-field, E-field at input.power.limit, and 4cm²PD value at input.power.limit corresponding to mmW transmission.

Note: cDASY6 measurement system by Schmid & Partner Engineering AG (SPEAG) of Zurich, Switzerland measures relative E-field, and provides ratio of $\frac{[pointE(t)]^2}{[pointE_input.power.limit]^2}$ versus time.

FCC ID: A3LSMA426U	PCTEST* Proud to be part of @ element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager
Document S/N:	Test Dates:	DUT Type:		
1M2101040001-21.A3L	1/21/2021-3/2/2021	Portable Handset		Page 9 of 98
© 2021 PCTEST				REV 1.0

04/06/2020

4 FCC MEASUREMENT PROCEDURES (FREQ < 6 GHZ)

This chapter provides the test plan and test procedure for validating Qualcomm Smart Transmit feature for sub-6 transmission. The 100 seconds time window for operating f < 3GHz is used as an example to detail the test procedures in this chapter. The same test plan and test procedures described in this chapter apply to 60 seconds time window for operating f \geq 3GHz.

4.1 Test sequence determination for validation

Following the FCC recommendation, two test sequences having time-variation in Tx power are predefined for sub-6 (f < 6 GHz) validation:

- Test sequence 1: request DUT's Tx power to be at maximum power, measured P_{max}^{\dagger} , for 80s, then requesting for half of the maximum power, i.e., measured $P_{max}/2$, for the rest of the time.
- Test sequence 2: request DUT's Tx power to vary with time. This sequence is generated relative to measured P_{max}, measured P_{limit} and calculated P_{reserve} (= measured P_{limit} in dBm - Reserve_power_margin in dB) of DUT based on measured P_{limit}.

The details for generating these two test sequences is described and listed in Appendix E.

NOTE: For test sequence generation, "measured P_{limit} " and "measured P_{max} " are used instead of the " P_{limit} " specified in EFS entry and " P_{max} " specified for the device, because the Smart Transmit feature operates against the actual power level of the " P_{limit} " that was calibrated for the DUT. The "measured P_{limit} " accurately reflects what the feature is referencing to, therefore, it should be used during feature validation testing. The RF tune up and device-to-device variation are already considered in Part 0 report prior to determining P_{limit} .

4.2 Test configuration selection criteria for validating Smart Transmit feature

For validating the Smart Transmit feature, this section provides the general guidance to select test cases.

4.2.1 Test configuration selection for time-varying Tx power transmission

The Smart Transmit time averaging feature operation is independent of bands, modes, and channels for a given technology. Hence, validation of Smart Transmit in one band/mode/channel per technology is sufficient. Two bands per technology are proposed and selected for this testing to provide high confidence in this validation.

The criteria for the selection are based on the P_{limit} values determined in Part 0 report. Select two bands^{*} in each supported technology that correspond to least^{**} and highest^{***} P_{limit} values that are less than P_{max} for validating Smart Transmit.

* If one P_{limit} level applies to all the bands within a technology, then only one band needs to be tested. In this case, within the bands having the same P_{limit} , the radio configuration (e.g., # of RBs, channel#) and device position that correspond to the highest *measured* 1gSAR at P_{limit} shown in Part 1 report is selected.

** In case of multiple bands having the same least *P*_{limit} within the technology, then select the band having the highest *measured* 1gSAR at *P*_{limit}.

*** The band having a higher P_{limit} needs to be properly selected so that the power limiting enforced by Smart Transmit can be validated using the pre-defined test sequences. If the highest P_{limit} in a technology is too high where the power limiting enforcement is not needed when testing with the pre-defined test sequences, then the

	FCC ID: A3LSMA426U	Proud to be part of (@ element	PART 2 RF EXPOSURE EVALUATION REPORT	Approved by: Quality Manager
	Document S/N:	Test Dates:	DUT Type:	Page 10 of 98
	1M2101040001-21.A3L	1/21/2021-3/2/2021	Portable Handset	Fage 10 01 98
6	DODA DOTEOT			DEVIAO

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REV 1.0 04/06/2020 next highest level is checked. This process is continued within the technology until the second band for validation testing is determined.

Test configuration selection for change in call 4.2.2

The criteria to select a test configuration for call-drop measurement is:

- Select technology/band with least Plimit among all supported technologies/bands, and select the radio configuration (e.g., # of RBs, channel#) in this technology/band that corresponds to the highest measured 1gSAR at Plimit listed in Part 1 report.
- In case of multiple bands having same least P_{limit} , then select the band having the highest measured • 1gSAR at Plimit in Part 1 report.

This test is performed with the DUT's Tx power requested to be at maximum power, the above band selection will result in Tx power enforcement (i.e., DUT forced to have Tx power at Preserve) for longest duration in one FCC defined time window. The call change (call drop/reestablish) is performed during the Tx power enforcement duration (i.e., during the time when DUT is forced to have Tx power at Preserve). One test is sufficient as the feature operation is independent of technology and band.

4.2.3 Test configuration selection for change in technology/band

The selection criteria for this measurement is, for a given antenna, to have DUT switch from a technology/band with lowest Plimit within the technology group (in case of multiple bands having the same Plimit, then select the band with highest measured 1gSAR at Plimit) to a technology/band with highest Plimit within the technology group, in case of multiple bands having the same Plimit, then select the band with lowest measured 1gSAR at Plimit in Part 1 report, or vice versa.

This test is performed with the DUT's Tx power requested to be at maximum power, the technology/band switch is performed during Tx power enforcement duration (i.e., during the time when DUT is forced to have Tx power at Preserve).

4.2.4 Test configuration selection for change in antenna

The criteria to select a test configuration for antenna switch measurement is:

- Whenever possible and supported by the DUT, first select antenna switch configuration within the same technology/band (i.e., same technology and band combination).
- Then, select any technology/band that supports multiple Tx antennas, and has the highest difference in *P*_{limit} among all supported antennas.
- In case of multiple bands having same difference in Plimit among supported antennas, then select the • band having the highest measured 1gSAR at Plimit in Part 1 report.

This test is performed with the DUT's Tx power requested to be at maximum power in selected technology/band, and antenna change is conducted during Tx power enforcement duration (i.e., during the time when DUT is forced to have Tx power at Preserve).

Test configuration selection for change in DSI 4.2.5

The criteria to select a test configuration for DSI change test is

Select a technology/band having the $P_{limit} < P_{max}$ within any technology and DSI group, and for the • same technology/band having a different Plimit in any other DSI group. Note that the selected DSI transition need to be supported by the device.

This test is performed with the DUT's Tx power requested to be at maximum power in selected technology/band, and DSI change is conducted during Tx power enforcement duration (i.e., during the time when DUT is forced to have Tx power at Preserve).

	FCC ID: A3LSMA426U	PCTEST* Proud to be part of element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager
	Document S/N:	Test Dates:	DUT Type:		Dage 11 of 09
	1M2101040001-21.A3L	1/21/2021-3/2/2021	Portable Handset		Page 11 of 98
0	2021 PCTEST				REV 1.0

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4.2.6 Test configuration selection for change in time window

FCC specifies different time window for time averaging based on operation frequency. The criteria to select a test configuration for validating Smart Transmit feature and demonstrating the compliance during the change in time window is

- Select any technology/band that has operation frequency classified in one time window defined by FCC (such as 100-seconds time window), and its corresponding P_{limit} is less than P_{max} if possible.
- Select the 2nd technology/band that has operation frequency classified in a different time window defined by FCC (such as 60-seconds time window), and its corresponding P_{limit} is less than P_{max} if possible.
- . Note it is preferred both P_{limit} values of two selected technology/band less than corresponding P_{max} , but if not possible, at least one of technologies/bands has its P_{limit} less than P_{max} .

This test is performed with the EUT's Tx power requested to be at maximum power in selected technology/band. Test for one pair of time windows selected is sufficient as the feature operation is the same.

4.2.7 Test configuration selection for SAR exposure switching

If supported, the test configuration for SAR exposure switching should cover

- 1. SAR exposure switch when two active radios are in the same time window
- 2. SAR exposure switch when two active radios are in different time windows. One test with two active radios in any two different time windows is sufficient as Smart Transmit operation is the same for RF exposure switch in any combination of two different time windows. For device supporting LTE + mmW NR, this test is covered in SAR vs PD exposure switch validation.

The Smart Transmit time averaging operation is independent of the source of SAR exposure (for example, LTE vs. Sub6 NR) and ensures total time-averaged RF exposure compliance. Hence, validation of Smart Transmit in any one simultaneous SAR transmission scenario (i.e., one combination for LTE + Sub6 NR transmission) is sufficient, where the SAR exposure varies among SAR_{radio1} only, SAR_{radio1} + SAR_{radio2}, and SAR_{radio2} only scenarios.

The criteria to select a test configuration for validating Smart Transmit feature during SAR exposure switching scenarios is

- Select any two < 6GHz technologies/bands that the EUT supports simultaneous transmission (for example, LTE+Sub6 NR).
- Among all supported simultaneous transmission configurations, the selection order is
 - 1. select one configuration where both Plimit of radio1 and radio2 is less than their corresponding P_{max} , preferably, with different P_{limits} . If this configuration is not available, then.
 - 2. select one configuration that has P_{limit} less than its P_{max} for at least one radio. If this can not be found, then,
 - select one configuration that has *P*_{limit} of radio1 and radio2 greater than *P*_{max} but with 3. least $(P_{limit} - P_{max})$ delta.

Test for one simultaneous transmission scenario is sufficient as the feature operation is the same.

FCC ID: A3LSMA426U	PCTEST* Proud to be part of @ element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager
Document S/N:	Test Dates:	DUT Type:		Page 12 of 98
1M2101040001-21.A3L	1/21/2021-3/2/2021	Portable Handset		Fage 12 01 90
© 2021 PCTEST		•		REV 1.0

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4.3 Test procedures for conducted power measurements

This section provides general conducted power measurement procedures to perform compliance test under dynamic transmission scenarios described in Section 3. In practice, an adjustment can be made in these procedures. The justification/clarification may be provided.

Time-varying Tx power transmission scenario 4.3.1

This test is performed with the two pre-defined test sequences described in Section 4.1 for all the technologies and bands selected in Section 4.2.1. The purpose of the test is to demonstrate the effectiveness of power limiting enforcement and that the time-averaged SAR (corresponding time-averaged Tx power) does not exceed the FCC limit at all times (see Eq. (1a) and (1b)).

Test procedure

- 1. Measure *P_{max}*, measure *P_{limit}* and calculate *P_{reserve}* (= measured *P_{limit}* in dBm *Reserve_power_margin* in dB) and follow Section 4.1 to generate the test sequences for all the technologies and bands selected in Section 4.2.1. Both test sequence 1 and test sequence 2 are created based on measured P_{max} and measured P_{limit} of the DUT. Test condition to measure P_{max} and P_{limit} is:
 - a. Measure P_{max} with Smart Transmit disabled and callbox set to request maximum power.
 - Measure Plimit with Smart Transmit enabled and Reserve power margin set to 0 dB, callbox set b. to request maximum power.
- 2. Set Reserve_power_margin to actual (intended) value (3dB for this DUT based on Part 1 report) and reset power on DUT to enable Smart Transmit, establish radio link in desired radio configuration, with callbox requesting the DUT's Tx power to be at pre-defined test sequence 1, measure and record Tx power versus time, and then convert the conducted Tx power into 1gSAR or 10gSAR value (see Eq. (1a)) using measured Plimit from above Step 1. Perform running time average to determine time-averaged power and 1gSAR or 10gSAR versus time as illustrated in Figure 4-1 where using 100-seconds time window as an example.

Note: In Eq.(1a), instantaneous Tx power is converted into instantaneous 1gSAR or 10gSAR value by applying the measured worst-case 1gSAR or 10gSAR value at Plimit for the corresponding technology/band/antenna/DSI reported in Part 1 report.

Note: For an easier computation of the running time average, 0 dBm can be added at the beginning of the test sequences the length of the responding time window, for example, add 0dBm for 100-seconds so the running time average can be directly performed starting with the first 100-seconds data using excel spreadsheet. This technique applies to all tests performed in this Part 2 report for easier time-averaged computation using excel spreadsheet.

FCC ID: A3LSMA426U	Proud to be part of @element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager
Document S/N:	Test Dates:	DUT Type:		Dage 12 of 00
1M2101040001-21.A3L	1/21/2021-3/2/2021	Portable Handset		Page 13 of 98
© 2021 PCTEST				

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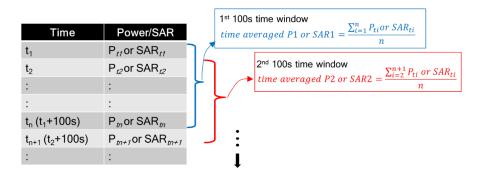


Figure 4-1 Running Average Illustration

- 3. Make one plot containing:
 - a. Instantaneous Tx power versus time measured in Step 2,
 - b. Requested Tx power used in Step 2 (test sequence 1),
 - c. Computed time-averaged power versus time determined in Step 2,
 - d. Time-averaged power limit (corresponding to FCC SAR limit of 1.6 W/kg for 1gSAR or 4.0W/kg for 10gSAR) given by

Time avearged power limit = meas. $P_{limit} + 10 \times \log(\frac{FCC SAR limit}{meas.SAR Plimit})$ (5a)

where *meas*. P_{limit} and *meas*. *SAR_Plimit* correspond to measured power at P_{limit} and measured SAR at P_{limit} .

- 4. Make another plot containing:
 - a. Computed time-averaged 1gSAR or 10gSAR versus time determined in Step 2
 - b. FCC 1gSAR_{limit} of 1.6W/kg or FCC 10gSAR_{limit} of 4.0W/kg.
- 5. Repeat Steps 2 ~ 4 for pre-defined test sequence 2 and replace the requested Tx power (test sequence 1) in Step 2 with test sequence 2.
- 6. Repeat Steps 2 ~ 5 for all the selected technologies and bands.
- 7. The validation criteria are, at all times, the time-averaged power versus time shown in Step 3 plot shall not exceed the time-averaged power limit (defined in Eq. (5a)), in turn, the time-averaged 1gSAR or 10gSAR versus time shown in Step 4 plot shall not exceed the FCC limit of 1.6 W/kg for 1gSAR or 4.0 W/kg for 10gSAR (i.e., Eq. (1b)).

4.3.2 Change in call scenario

This test is to demonstrate that Smart Transmit feature accurately accounts for the past Tx powers during time-averaging when a new call is established.

The call disconnect and re-establishment needs to be performed during power limit enforcement, i.e., when the DUT's Tx power is at $P_{reserve}$ level, to demonstrate the continuity of RF exposure management and limiting in call change scenario. In other words, the RF exposure averaged over any FCC defined time window (including the time windows containing the call change) doesn't exceed FCC limit of 1.6 W/kg for 1gSAR or 4.0 W/kg for 10gSAR.

FCC ID: A3LSMA426U	Proud to be part of @ element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager
Document S/N:	Test Dates:	DUT Type:		Page 14 of 98
1M2101040001-21.A3L	1/21/2021-3/2/2021	Portable Handset		Fage 14 01 90
© 2021 PCTEST				REV 1.0

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Test procedure

- 1. Measure *P*_{limit} for the technology/band selected in Section 4.2.2. Measure *P*_{limit} with Smart Transmit <u>enabled</u> and *Reserve_power_margin* set to 0 dB, callbox set to request maximum power.
- 2. Set *Reserve_power_margin* to actual (intended) value and reset power on DUT to enable Smart Transmit.
- 3. Establish radio link with callbox in the selected technology/band.
- 4. Request DUT's Tx power at 0 dBm for at least one time window specified for the selected technology/band, followed by requesting DUT's Tx power to be at maximum power for about ~60 seconds, and then drop the call for ~10 seconds. Afterwards, re-establish another call in the same radio configuration (i.e., same technology/band/channel) and continue callbox requesting DUT's Tx power to be at maximum power for the remaining time of at least another full duration of the specified time window. Measure and record Tx power versus time. Once the measurement is done, extract instantaneous Tx power versus time, convert the measured conducted Tx power into 1gSAR or 10gSAR value using Eq. (1a), and then perform the running time average to determine time-averaged power and 1gSAR or 10gSAR versus time.
 - NOTE: In Eq.(1a), instantaneous Tx power is converted into instantaneous 1gSAR or 10gSAR value by applying the measured worst-case 1gSAR or 10gSAR value at *P*_{limit} for the corresponding technology/band/antenna/DSI reported in Part 1 report.
- 5. Make one plot containing: (a) instantaneous Tx power versus time, (b) requested power, (c) computed time-averaged power, (d) time-averaged power limit calculated using Eq.(5a).
- 6. Make another plot containing: (a) computed time-averaged 1gSAR or 10gSAR versus time, and (b) FCC limit of 1.6 W/kg for 1gSAR or 4.0 W/kg for 10gSAR.

The validation criteria are, at all times, the time-averaged power versus time shall not exceed the timeaveraged power limit (defined in Eq.(5a)), in turn, the time-averaged 1gSAR or 10gSAR versus time shall not exceed the FCC limit of 1.6 W/kg for 1gSAR or 4.0 W/kg for 10gSAR (i.e., Eq. (1b)).

4.3.3 Change in technology and band

This test is to demonstrate the correct power control by Smart Transmit during technology switches and/or band handovers.

Similar to the change in call test in Section 4.3.2, to validate the continuity of RF exposure limiting during the transition, the technology and band handover needs to be performed when DUT's Tx power is at $P_{reserve}$ level (i.e., during Tx power enforcement) to make sure that the DUT's Tx power from previous $P_{reserve}$ level to the new $P_{reserve}$ level (corresponding to new technology/band). Since the P_{limit} could vary with technology and band, Eq. (1a) can be written as follows to convert the instantaneous Tx power in 1gSAR or 10gSAR exposure for the two given radios, respectively:

$$1g_or_10gSAR_1(t) = \frac{conducted_Tx_power_1(t)}{conducted_Tx_power_P_{limit_1}} * 1g_or_10gSAR_P_{limit_1}$$
(6a)

$$1g_or_10gSAR_2(t) = \frac{conducted_Tx_power_2(t)}{conducted_Tx_power_P_{limit_2}} * 1g_or_10gSAR_P_{limit_2}$$
(6b)

$$\frac{1}{T_{SAR}} \left[\int_{t-T_{SAR}}^{t_1} \frac{1g_or_10gSAR_1(t)}{FCC\ SAR\ limit} dt + \int_{t-T_{SAR}}^{t} \frac{1g_or_10gSAR_2(t)}{FCC\ SAR\ limit} dt \right] \le 1$$
(6c)

where, *conducted_Tx_power_1(t)*, *conducted_Tx_power_P*_{*limit_1*}, and *1g_or_10gSAR_P*_{*limit_1*} correspond to the measured instantaneous conducted Tx power, measured conducted Tx power at *P*_{*limit*}, and measured *1gSAR* or *10gSAR* value at *P*_{*limit*} of technology1/band1; *conducted_Tx_power_2(t)*,

	FCC ID: A3LSMA426U	PCTEST* Proud to be part of element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager
	Document S/N:	Test Dates:	DUT Type:		Page 15 of 98
	1M2101040001-21.A3L	1/21/2021-3/2/2021	Portable Handset		Fage 15 01 98
G	2021 DOTEST				DEV 1 0

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REV 1.0 04/06/2020

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conducted_Tx_power_ $P_{limit_2}(t)$, and 1g_or_10gSAR_ P_{limit_2} correspond to the measured instantaneous conducted Tx power, measured conducted Tx power at Plimit, and measured 1gSAR or 10gSAR value at P_{limit} of technology2/band2. Transition from technology1/band1 to the technology2/band2 happens at time-instant ' t_1 '.

Test procedure

- 1. Measure P_{limit} for both the technologies and bands selected in Section 4.2.3. Measure P_{limit} with Smart Transmit enabled and *Reserve power margin* set to 0 dB, callbox set to request maximum power.
- 2. Set Reserve_power_margin to actual (intended) value and reset power on DUT to enable Smart Transmit
- 3. Establish radio link with callbox in first technology/band selected.
- Request DUT's Tx power at 0 dBm for at least one time window specified for the selected technology/band, followed by requesting DUT's Tx power to be at maximum power for about ~60 seconds, and then switch to second technology/band selected. Continue with callbox requesting DUT's Tx power to be at maximum power for the remaining time of at least another full duration of the specified time window. Measure and record Tx power versus time for the full duration of the test.
- 5. Once the measurement is done, extract instantaneous Tx power versus time, and convert the conducted Tx power into 1gSAR or 10gSAR value using Eq. (6a) and (6b) and corresponding measured Plimit values from Step 1 of this section. Perform the running time average to determine time-averaged power and 1gSAR or 10gSAR versus time.
 - NOTE: In Eq.(6a) & (6b), instantaneous Tx power is converted into instantaneous 1gSAR or 10gSAR value by applying the measured worst-case 1gSAR or 10gSAR value at Plimit for the corresponding technology/band/antenna/DSI reported in Part 1 report.
- 6. Make one plot containing: (a) instantaneous Tx power versus time, (b) requested power, (c) computed time-averaged power, (d) time-averaged power limit calculated using Eq.(5a).
- 7. Make another plot containing: (a) computed time-averaged 1gSAR or 10gSAR versus time, and (b) FCC limit of 1.6 W/kg for 1gSAR or 4.0 W/kg for 10gSAR.

The validation criteria are, at all times, the time-averaged 1gSAR or 10gSAR versus time shall not exceed the FCC limit of 1.6 W/kg for 1gSAR or 4.0 W/kg for 10gSAR (i.e., Eq. (6c)).

4.3.4 Change in antenna

This test is to demonstrate the correct power control by Smart Transmit during antenna switches from one antenna to another. The test procedure is identical to Section 4.3.3, by replacing technology/band switch operation with antenna switch. The validation criteria are, at all times, the time-averaged 1gSAR or 10gSAR versus time shall not exceed FCC limit of 1.6 W/kg for 1gSAR or 4.0 W/kg for 10gSAR.

NOTE: If the DUT does not support antenna switch within the same technology/band, but has multiple antennas to support different frequency bands, then the antenna switch test is included as part of change in technology and band (Section 4.3.3) test.

4.3.5 Change in DSI

This test is to demonstrate the correct power control by Smart Transmit during DSI switches from one DSI to another. The test procedure is identical to Section 4.3.3, by replacing technology/band switch operation with DSI switch. The validation criteria are, at all times, the time-averaged 1gSAR or 10gSAR versus time shall not exceed FCC limit of 1.6 W/kg for 1gSAR or 4.0 W/kg for 10gSAR.

	FCC ID: A3LSMA426U	PCTEST* Proud to be part of @ element	PART 2 RF EXPOSURE EVALUATION REPORT	SAM SUNG	Approved by: Quality Manager
	Document S/N:	Test Dates:	DUT Type:		Page 16 of 98
	1M2101040001-21.A3L	1/21/2021-3/2/2021	Portable Handset		Fage 10 01 96
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4.3.6 Change in time window

This test is to demonstrate the correct power control by Smart Transmit during the change in averaging time window when a specific band handover occurs. FCC specifies time-averaging windows of 100s for Tx frequency < 3GHz, and 60s for Tx frequency between 3GHz and 6GHz.

To validate the continuity of RF exposure limiting during the transition, the band handover test needs to be performed when EUT handovers from operation band less than 3GHz to greater than 3GHz and vice versa. The equations (3a) and (3b) in Section 2 can be written as follows for transmission scenario having change in time window,

$$1gSAR_{1}(t) = \frac{conducted_Tx_power_{1}(t)}{conducted_Tx_power_{P_{limit_{1}}}} * 1g_or \ 10g_SAR_{P_{limit_{1}}}$$
(7a)
$$1gSAR_{2}(t) = \frac{conducted_Tx_power_{2}(t)}{conducted_Tx_power_{P_{limit_{2}}}} * 1g_or \ 10g_SAR_{P_{limit_{2}}}$$
(7b)

$$\frac{1}{T_{1_{SAR}}} \left[\int_{t-T_{1_{SAR}}}^{t_1} \frac{1g_{or \ 10g_{SAR_1}(t)}}{FCC \ SAR \ limit} dt \right] + \frac{1}{T_{2_{SAR}}} \left[\int_{t-T_{2_{SAR}}}^{t} \frac{1g_{or \ 10g_{SAR_2}(t)}}{FCC \ SAR \ limit} dt \right] \le 1$$
(7c)

where, conducted_Tx_power_1(t), conducted_Tx_power_ $P_{limit_1}(t)$, and 1g_ or 10g_SAR_ P_{limit_1} correspond to the instantaneous Tx power, conducted Tx power at P_{limit_1} , and compliance 1g_ or 10g_SAR values at P_{limit_1} of band1 with time-averaging window ' $T1_{SAR}$ '; conducted_Tx_power_2(t), conducted_Tx_power_ $P_{limit_2}(t)$, and 1g_ or 10g_SAR_ P_{limit_2} correspond to the instantaneous Tx power, conducted Tx power at $P_{limit_2}(t)$, and 1g_ or 10g_SAR_ P_{limit_2} correspond to the instantaneous Tx power, conducted Tx power at $P_{limit_2}(t)$, and 1g_ or 10g_SAR_ P_{limit_2} correspond to the instantaneous Tx power, conducted Tx power at P_{limit_3} and compliance 1g_ or 10g_SAR values at P_{limit_2} of band2 with time-averaging window ' $T2_{SAR}$ '. One of the two bands is less than 3GHz, another is greater than 3GHz. Transition from first band with time-averaging window ' $T1_{SAR}$ ' to the second band with time-averaging window ' $T2_{SAR}$ ' happens at time-instant ' t_1 '.

Test procedure

- 1. Measure *P*_{limit} for both the technologies and bands selected in Section 4.2.6. Measure *P*_{limit} with Smart Transmit <u>enabled</u> and *Reserve_power_margin* set to 0 dB, callbox set to request maximum power.
- 2. Set Reserve_power_margin to actual (intended) value and enable Smart Transmit

Transition from 100s time window to 60s time window, and vice versa

- 3. Establish radio link with callbox in the technology/band having 100s time window selected in Section 4.2.6.
- 4. Request EUT's Tx power to be at 0 dBm for at least 100 seconds, followed by requesting EUT's Tx power to be at maximum power for about ~140 seconds, and then switch to second technology/band (having 60s time window) selected in Section 4.2.6. Continue with callbox requesting EUT's Tx power to be at maximum power for about ~60s in this second technology/band, and then switch back to the first technology/band. Continue with callbox requesting EUT's Tx power for at least another 100s. Measure and record Tx power versus time for the entire duration of the test.
- 5. Once the measurement is done, extract instantaneous Tx power versus time, and convert the conducted Tx power into 1gSAR or 10gSAR value (see Eq. (7a) and (7b)) using corresponding technology/band Step 1 result, and then perform 100s running average to determine time-averaged 1gSAR or 10gSAR versus time. Note that in Eq.(7a) & (7b), instantaneous Tx power is converted into instantaneous 1gSAR or 10gSAR value by applying the worst-case 1gSAR or 10gSAR value tested in Part 1 for the selected technologies/bands at *P*_{limit}.
- 6. Make one plot containing: (a) instantaneous Tx power versus time measured in Step 4.
- Make another plot containing: (a) instantaneous 1gSAR versus time determined in Step 5, (b) computed time-averaged 1gSAR versus time determined in Step 5, and (c) corresponding regulatory 1gSAR_{limit} of 1.6W/kg or 10gSAR_{limit} of 4.0W/kg.

FCC ID: A3LSMA426U	Proud to be part of @ element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager
Document S/N:	Test Dates:	DUT Type:		Dogo 17 of 00
1M2101040001-21.A3L	1/21/2021-3/2/2021	Portable Handset		Page 17 of 98
© 2021 PCTEST				REV 1.0

REV 1.0 04/06/2020

Transition from 60s time window to 100s time window, and vice versa

- 8. Establish radio link with callbox in the technology/band having 60s time window selected in Section 4.2.6.
- 9. Request EUT's Tx power to be at 0 dBm for at least 60 seconds, followed by requesting EUT's Tx power to be at maximum power for about ~80 seconds, and then switch to second technology/band (having 100s time window) selected in Section 4.2.6. Continue with callbox requesting EUT's Tx power to be at maximum power for about ~100s in this second technology/band, and then switch back to the first technology/band. Continue with callbox requesting EUT's Tx power for the remaining time for a total test time of 500 seconds. Measure and record Tx power versus time for the entire duration of the test.
- 10. Repeat above Step 5~7 to generate the plots

The validation criteria is, at all times, the time-averaged 1gSAR or 10gSAR versus time shall not exceed the regulatory *1gSAR*_{limit} of 1.6W/kg or *10gSAR*_{limit} of 4.0W/kg.

4.3.7 SAR exposure switching

This test is to demonstrate that Smart Transmit feature is accurately accounts for switching in exposures among SAR from radio1 only, SAR from both radio1 and radio2, and SAR from radio2 only scenarios, and ensures total time-averaged RF exposure complies with the FCC limit. Here, radio1 represents primary radio (for example, LTE anchor in a NR non-standalone mode call) and radio2 represents secondary radio (for example, sub6 NR or mmW NR). The detailed test procedure for SAR exposure switching in the case of LTE+Sub6 NR non-standalone mode transmission scenario is provided in APPENDIX F:.

Test procedure:

- 1. Measure conducted Tx power corresponding to *P*_{*limit*} for radio1 and radio2 in selected band. Test condition to measure conducted *P*_{*limit*} is:
 - Establish device in call with the callbox for radio1 technology/band. Measure conducted Tx power corresponding to radio1 *P*_{limit} with Smart Transmit <u>enabled</u> and *Reserve_power_margin* set to 0 dB, callbox set to request maximum power.
 - Repeat above step to measure conducted Tx power corresponding to radio2 <u>*P*_{limit}</u>. If radio2 is dependent on radio1 (for example, non-standalone mode of Sub6 NR requiring radio1 LTE as anchor), then establish radio1 + radio2 call with callbox, and request all down bits for radio1 LTE. In this scenario, with callbox requesting maximum power from radio2 Sub6 NR, measured conducted Tx power corresponds to radio2 <u>*P*_{limit}</u> (as radio1 LTE is at all-down bits)
- 2. Set Reserve_power_margin to actual (intended) value, with EUT setup for radio1 + radio2 call. In this description, it is assumed that radio2 has lower priority than radio1. Establish device in radio1+radio2 call, and request all-down bits or low power on radio1, with callbox requesting EUT's Tx power to be at maximum power in radio2 for at least one time window. After one time window, set callbox to request EUT's Tx power to be at maximum power on radio1, i.e., all-up bits. Continue radio1+radio2 call with both radios at maximum power for at least one time window, and drop (or request all-down bits on) radio2. Continue radio1 at maximum power for at least one time window. Record the conducted Tx power for both radio1 and radio2 for the entire duration of this test.
- 3. Once the measurement is done, extract instantaneous Tx power versus time for both radio1 and radio2 links. Convert the conducted Tx power for both these radios into 1gSAR or 10gSAR value (see Eq. (6a) and (6b)) using corresponding technology/band P_{limit} measured in Step 1, and then perform the running time average to determine time-averaged 1gSAR or 10gSAR versus time.

FCC ID: A3LSMA426U	PCTEST [*] Proud to be part of @ element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager
Document S/N:	Test Dates:	DUT Type:		Dage 10 of 00
1M2101040001-21.A3L	1/21/2021-3/2/2021	Portable Handset		Page 18 of 98
© 2021 PCTEST				REV 1.0

REV 1.0 04/06/2020

- 4. Make one plot containing: (a) instantaneous Tx power versus time measured in Step 2.
- 5. Make another plot containing: (a) instantaneous 1gSAR versus time determined in Step 3, (b) computed time-averaged 1gSAR versus time determined in Step 3, and (c) corresponding regulatory 1gSARlimit of 1.6W/kg or 10gSARlimit of 4.0W/kg.

The validation criteria is, at all times, the time-averaged 1gSAR or 10gSAR versus time shall not exceed the regulatory 1gSARlimit of 1.6W/kg or 10gSARlimit of 4.0W/kg.

Test procedure for time-varying SAR measurements 4.4

This section provides general time-varying SAR measurement procedures to perform compliance test under dynamic transmission scenarios described in Section 3. In practice, an adjustment can be made in these procedures. The justification/clarification may be provided.

To perform the validation through SAR measurement for transmission scenario 1 described in Section 3, the "path loss" between callbox antenna and DUT needs to be calibrated to ensure that the DUT Tx power reacts to the requested power from callbox in a radiated call. It should be noted that when signaling in closed loop mode, protocol-level power control is in play, resulting in DUT not solely following callbox TPC (Tx power control) commands. In other words, DUT response has many dependencies (RSSI, quality of signal, path loss variation, fading, etc.,) other than just TPC commands. These dependencies have less impact in conducted setup (as it is a controlled environment and the path loss can be very well calibrated) but have significant impact on radiated testing in an uncontrolled environment, such as SAR test setup. Therefore, the deviation in DUT Tx power from callbox requested power is expected, however the time-averaged SAR should not exceed FCC SAR requirement at all times as Smart Transmit controls Tx power at DUT.

The following steps are for time averaging feature validation through SAR measurement:

- 1. "Path Loss" calibration: Place the DUT against the phantom in the worst-case position determined based on Section 4.2.1. For each band selected, prior to SAR measurement, perform "path loss" calibration between callbox antenna and DUT. Since the SAR test environment is not controlled and well calibrated for OTA (Over the Air) test, extreme care needs to be taken to avoid the influence from reflections. The test setup is described in Section 6.2.
- 2. Time averaging feature validation:
 - i For a given radio configuration (technology/band) selected in Section 4.2.1, enable Smart Transmit and set *Reserve power margin* to 0 dB, with callbox to request maximum power, perform area scan, conduct pointSAR measurement at peak location of the area scan. This point SAR value, pointSAR_P_{limit}, corresponds to point SAR at the measured P_{limit} (i.e., measured P_{limit} from the DUT in Step 1 of Section 4.3.1).
 - Set Reserve_power_margin to actual (intended) value and reset power on DUT to enable Smart ii Transmit. Note, if *Reserve power margin* cannot be set wirelessly, care must be taken to reposition the DUT in the exact same position relative to the SAM phantom as in above Step 2.i. Establish radio link in desired radio configuration, with callbox requesting the DUT's Tx power at power levels described by test sequence 1 generated in Step 1 of Section 4.3.1, conduct point SAR measurement versus time at peak location of the area scan determined in Step 2.i of this section. Once the measurement is done, extract instantaneous point SAR vs time data, pointSAR(t), and convert it into instantaneous 1gSAR or 10gSAR vs. time using Eq. (3a), rewritten below:

$1g_or_10gSAR(t) =$	$\frac{pointSAR(t)}{pointSAR_P_{limit}} * 1g_or_10gSAR_P_{limit}$
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FCC ID: A3LSMA426U	Proud to be part of @ element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager
Document S/N:	Test Dates:	DUT Type:		Dage 10 of 09
1M2101040001-21.A3L	1/21/2021-3/2/2021	Portable Handset		Page 19 of 98
© 2021 PCTEST				REV 1.0

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where, $pointSAR_{P_{limit}}$ is the value determined in Step 2.i, and pointSAR(t) is the instantaneous point SAR measured in Step 2.ii, $1g_or_10gSAR_P_{limit}$ is the measured 1gSAR or 10gSAR value listed in Part 1 report.

- iii Perform 100s running average to determine time-averaged 1gSAR or 10gSAR versus time.
- iv Make one plot containing: (a) time-averaged 1gSAR or 10gSAR versus time determined in Step 2.iii of this section, (b) FCC limit of 1.6 W/kg for 1gSAR or 4.0 W/kg for 10gSAR.
- Repeat 2.ii ~ 2.iv for test sequence 2 generated in Step 1 of Section 4.3.1. v
- Repeat 2.i ~ 2.v for all the technologies and bands selected in Section 4.2.1. vi

The time-averaging validation criteria for SAR measurement is that, at all times, the time-averaged 1gSAR or 10gSAR versus time shall not exceed FCC limit of 1.6 W/kg for 1gSAR or 4.0 W/kg for 10gSAR (i.e., Eq. (3b)).

FCC ID: A3LSMA426U		PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager
Document S/N:	Test Dates:	DUT Type:		Dage 20 of 00
1M2101040001-21.A3L	1/21/2021-3/2/2021	Portable Handset		Page 20 of 98
© 2021 PCTEST				REV 1.0

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5 FCC MEASUREMENT PROCEDURES (FREQ > 6 GHZ)

This section provides the test plan and test procedures for validating Qualcomm Smart Transmit feature for mmW transmission. For this EUT, millimeter wave (mmW) transmission is only in non-standalone mode, i.e., it requires an LTE link as anchor.

5.1 Test sequence for validation in mmW NR transmission

In 5G mmW NR transmission, the test sequence for validation is with the callbox requesting EUT's Tx power in 5G mmW NR at maximum power all the time.

5.2 Test configuration selection criteria for validating Smart Transmit feature

Test configuration selection for time-varying Tx power transmission 5.2.1

The Smart Transmit time averaging feature operation is independent of bands, modes, channels, and antenna configurations (beams) for a given technology. Hence, validation of Smart Transmit in any one band/mode/channel per technology is sufficient.

5.2.2 Test configuration selection for change in antenna configuration (beam)

The Smart Transmit time averaging feature operation is independent of bands, modes, channels, and antenna configurations (beams) for a given technology. Hence, validation of Smart Transmit with beam switch between any two beams is sufficient.

5.2.3 Test configuration selection for SAR vs. PD exposure switch during transmission

The Smart Transmit time averaging feature operation is independent of the nature of exposure (SAR vs. PD) and ensures total time-averaged RF exposure compliance. Hence, validation of Smart Transmit in any one band/mode/channel/beam for mmW + sub-6 (LTE) transmission is sufficient, where the exposure varies among SAR dominant scenario, SAR+PD scenario, and PD dominant scenario.

5.3 Test procedures for mmW radiated power measurements

Perform conducted power measurement (for f < 6GHz) and radiated power measurement (for f > 6GHz) for LTE + mmW transmission to validate Smart Transmit time averaging feature in the various transmission scenarios described in Section 3.

This section provides general conducted power measurement procedures to perform compliance test under dynamic transmission scenarios described in Section 3. In practice, an adjustment can be made in these procedures. The justification/clarification may be provided.

5.3.1 Time-varying Tx power scenario

The purpose of the test is to demonstrate the effectiveness of power limiting enforcement and that the time-averaged Tx power when converted into RF exposure values does not exceed the FCC limit at all times (see Eq. (2a), (2b) & (2c) in Section 3).

Test procedure:

Measure conducted Tx power corresponding to P_{limit} for LTE in selected band, and measure radiated Tx power corresponding to input.power.limit in desired mmW band/channel/beam by following below steps:

FCC ID: A3LSMA426U	Proved to be part of @ element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager
Document S/N:	Test Dates:	DUT Type:		Dage 24 of 00
1M2101040001-21.A3L	1/21/2021-3/2/2021	Portable Handset		Page 21 of 98
© 2021 PCTEST				REV 1.0

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- a. Measure radiated power corresponding to mmW *input.power.limit* by setting up the EUT's Tx power in desired band/channel/beam at *input.power.limit* in Factory Test Mode (FTM). This test is performed in a calibrated anechoic chamber. Rotate the EUT to obtain maximum radiated Tx power, keep the EUT in this position and do not disturb the position of the EUT inside the anechoic chamber for the rest of this test.
- b. Reset EUT to place in online mode and establish radio link in LTE, measure conducted Tx power corresponding to LTE *P*_{limit} with Smart Transmit enabled and *Reserve_power_margin* set to 0 dB, callbox set to request maximum power.
- Set Reserve_power_margin to actual (intended) value and reset power on EUT to enable Smart Transmit. With EUT setup for a mmW NR call in the desired/selected LTE band and mmW NR band, perform the following steps:
 - a. Establish LTE and mmW NR connection in desired band/channel/beam used in Step 1. As soon as the mmW connection is established, immediately request all-down bits on LTE link. With callbox requesting EUT's Tx power to be at maximum mmW power to test predominantly PD exposure scenario (as SAR exposure is less when LTE's Tx power is at low power).
 - b. After 120s, request LTE to go all-up bits for at least 100s. SAR exposure is dominant. There are two scenarios:
 - i If *P*_{limit} < *P*_{max} for LTE, then the RF exposure margin (provided to mmW NR) gradually runs out (due to high SAR exposure). This results in gradual reduction in the 5G mmW NR transmission power and eventually seized 5G mmW NR transmission when LTE goes to *P*_{reserve} level.
 - ii If P_{limit} ≥ P_{max} for LTE, then the 5G mmW NR transmission's averaged power should gradually reduce but the mmW NR connection can sustain all the time (assuming TxAGC uncertainty = 0dB).
 - c. Record the conducted Tx power of LTE and radiated Tx power of mmW for the full duration of this test of at least 300s.
- 3. Once the measurement is done, extract instantaneous Tx power versus time for both LTE and mmW links. Convert the conducted Tx power for LTE into 1gSAR or 10gSAR value using Eq. (2a) and P_{limit} measured in Step 1.b, and then divide by FCC limit of 1.6 W/kg for 1gSAR or 4.0 W/kg for 10gSAR to obtain instantaneous normalized 1gSAR or 10gSAR versus time. Perform 100s running average to determine normalized 100s-averaged 1gSAR or 10gSAR versus time.
 - NOTE: In Eq.(2a), instantaneous Tx power is converted into instantaneous 1gSAR or 10gSAR value by applying the measured worst-case 1gSAR or 10gSAR value at *P*_{limit} for the corresponding technology/band/antenna/DSI reported in Part 1 report.
- 4. Similarly, convert the radiated Tx power for mmW into 4cm²PD value using Eq. (2b) and the radiated Tx power limit (i.e., radiated Tx power at *input.power.limit*) measured in Step 1.a, then divide by FCC 4cm²PD limit of 10W/m² to obtain instantaneous normalized 4cm²PD versus time. Perform 4s running average to determine normalized 4s-averaged 4cm²PD versus time.
 - NOTE: In Eq.(2b), instantaneous radiated Tx power is converted into instantaneous 4cm²PD by applying the worst-case 4cm²PD value measured at *input.power.limit* for the selected band/beam in Part 1 report.
- 5. Make one plot containing: (a) instantaneous conducted Tx power for LTE versus time, (b) computed 100s-averaged conducted Tx power for LTE versus time, (c) instantaneous radiated Tx power for

FCC ID: A3LSMA426U	Proud to be part of the element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager
Document S/N:	Test Dates:	DUT Type:		Dage 22 of 00
1M2101040001-21.A3L	1/21/2021-3/2/2021	Portable Handset		Page 22 of 98
© 2021 PCTEST				REV 1.0

REV 1.0 04/06/2020

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mmW versus time, as measured in Step 2, (d) computed 4s-averaged radiated Tx power for mmW versus time, and (e) time-averaged conducted and radiated power limits for LTE and mmW radio using Eq. (5a) & (5b), respectively:

Time avearged LTE power limit = meas. $P_{limit} + 10 \times \log(\frac{FCC SAR limit}{meas.SAR_Plimit})$ (5a)

FCC PD limit Time avearged mmW NR power limit = meas. $EIRP_{input.power.limit} + 10 \times \log(\frac{FCC PD \ limit}{meas.PD_{input.power.limit}})$ (5b)

where meas. EIRP_{input.power.limit} and meas. PD_input.power.limit correspond to measured EIRP at input.power.limit and measured power density at input.power.limit.

6. Make another plot containing: (a) computed normalized 100s-averaged 1gSAR or 10gSAR versus time determined in Step 3, (b) computed normalized 4s-averaged 4cm²PD versus time determined in Step 4, and (c) corresponding total normalized time-averaged RF exposure (sum of steps (6.a) and (6.b)) versus time.

The validation criteria are, at all times, the total normalized time-averaged RF exposure versus time determined in Step 6.c shall not exceed the normalized limit of 1.0 of FCC requirement (i.e., Eq. (2c)).

5.3.2 Switch in SAR vs. PD exposure during transmission

This test is to demonstrate that Smart Transmit feature is independent of the nature of exposure (SAR vs. PD), accurately accounts for switching in exposures among SAR dominant, SAR+PD, and PD dominant scenarios, and ensures total time-averaged RF exposure compliance.

Test procedure:

- 1. Measure conducted Tx power corresponding to P_{limit} for LTE in selected band, and measure radiated Tx power corresponding to input power.limit in desired mmW band/channel/beam by following below steps:
 - Measure radiated power corresponding to *input.power.limit* by setting up the EUT's Tx power a. in desired band/channel/beam at input.power.limit in FTM. This test is performed in a calibrated anechoic chamber. Rotate the EUT to obtain maximum radiated Tx power, keep the EUT in this position and do not disturb the position of the EUT inside the anechoic chamber for the rest of this test.
 - Reset EUT to place in online mode and establish radio link in LTE, measure conducted Tx b. power corresponding to LTE Plimit with Smart Transmit enabled and Reserve_power_margin set to 0 dB, callbox set to request maximum power.
- 2. Set Reserve power margin to actual (intended) value and reset power in EUT, with EUT setup for LTE + mmW call, perform the following steps:
 - Establish LTE (sub-6) and mmW NR connection with callbox. a.
 - As soon as the mmW connection is established, immediately request all-down bits on LTE b. link. Continue LTE (all-down bits) + mmW transmission for more than 100s duration to test predominantly PD exposure scenario (as SAR exposure is negligible from all-down bits in LTE).
 - After 120s, request LTE to go all-up bits, mmW transmission should gradually run out of RF c. exposure margin if LTE's Plimit < Pmax and seize mmW transmission (SAR only scenario); or mmW transmission should gradually reduce in Tx power and will sustain the connection if LTE's $P_{limit} > P_{max}$.
 - d. After 75s, request LTE to go all-down bits, mmW transmission should start getting back RF exposure margin and resume transmission again.

FCC ID: A3LSMA426U	Proud to be part of @ element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager
Document S/N:	Test Dates:	DUT Type:		Dogo 22 of 09
1M2101040001-21.A3L	1/21/2021-3/2/2021	Portable Handset		Page 23 of 98
© 2021 PCTEST				REV 1.0

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- e. Record the conducted Tx power of LTE and radiated Tx power of mmW for the entire duration of this test of at least 300s.
- Once the measurement is done, extract instantaneous Tx power versus time for both LTE and mmW links. Convert the conducted Tx power for LTE into 1gSAR or 10gSAR value using Eq. (2a) and Plimit measured in Step 1.b, and then divide by FCC limit of 1.6 W/kg for 1gSAR or 4.0 W/kg for 10gSAR to obtain instantaneous normalized 1gSAR or 10gSAR versus time. Perform 100s running average to determine normalized 100s-averaged 1gSAR or 10gSAR versus time.
 - NOTE: In Eq.(2a), instantaneous Tx power is converted into instantaneous 1gSAR or 10gSAR value by applying the measured worst-case 1gSAR or 10gSAR value at Plimit for the corresponding technology/band/antenna/DSI reported in Part 1 report.
- 4. Similarly, convert the radiated Tx power for mmW into 4cm²PD value using Eq. (2b) and the radiated Tx power limit (i.e., radiated Tx power at *input.power.limit*) measured in Step 1.a, then divide this by FCC 4cm²PD limit of 10W/m² to obtain instantaneous normalized 4cm²PD versus time. Perform 4s running average to determine normalized 4s-averaged 4cm²PD versus time.
 - NOTE: In Eq.(2b), instantaneous radiated Tx power is converted into instantaneous 4cm²PD by applying the worst-case 4cm²PD value measured at *input.power.limit* for the selected band/beam in Part 1 report.
- 5. Make one plot containing: (a) instantaneous conducted Tx power for LTE versus time, (b) computed 100s-averaged conducted Tx power for LTE versus time. (c) instantaneous radiated Tx power for mmW versus time, as measured in Step 2, (d) computed 4s-averaged radiated Tx power for mmW versus time, and (e) time-averaged conducted and radiated power limits for LTE and mmW radio using Eq. (5a) & (5b), respectively.
- 6. Make another plot containing: (a) computed normalized 100s-averaged 1gSAR or 10gSAR versus time determined in Step 3, (b) computed normalized 4s-averaged 4cm²PD versus time determined in Step 4, and (c) corresponding total normalized time-averaged RF exposure (sum of steps (6.a) and (6.b)) versus time.

The validation criteria are, at all times, the total normalized time-averaged RF exposure versus time determined in Step 6.c shall not exceed the normalized limit of 1.0 of FCC requirement (i.e., Eq. (2c)).

5.3.3 Change in antenna configuration (beam)

This test is to demonstrate the correct power control by Smart Transmit during changes in antenna configuration (beam). Since the input.power.limit varies with beam, the Eq. (2a), (2b) and (2c) in Section 3 are written as below for transmission scenario having change in beam,

$$1g_{or_{1}0gSAR(t)} = \frac{conducted_{Tx_power(t)}}{conducted_{Tx_power_{limit}}} * 1g_{or_{1}0gSAR_{limit}}$$
(8a)

$$4cm^{2}PD_{1}(t) = \frac{radiated_{Tx}power_{1}(t)}{radiated_{Tx}power_{input}power_{limit_{1}}} * 4cm^{2}PD_{input}power_{limit_{1}}$$
(8b)

$$4cm^{2}PD_{2}(t) = \frac{radiated_{Tx}power_{2}(t)}{radiated_{Tx}power_{input}power_{inint_{2}}} * 4cm^{2}PD_{input}power_{inint_{2}}$$
(8c)

04/06/2020

FCC ID: A3LSMA426U	Proud to be part of @ element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager
Document S/N:	Test Dates:	DUT Type:		Dage 24 of 00
1M2101040001-21.A3L	1/21/2021-3/2/2021	Portable Handset		Page 24 of 98
© 2021 PCTEST				REV 1.0

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$$\frac{\frac{1}{T_{SAR}}\int_{t-T_{SAR}}^{t} 1g_{-}or_{-}10gSAR(t)dt}{FCC SAR limit} + \frac{\frac{1}{T_{PD}}\left[\int_{t-T_{PD}}^{t} 4cm^{2}PD_{1}(t)dt + \int_{t1}^{t} 4cm^{2}PD_{2}(t)dt\right]}{FCC4cm^{2}PD limit} \le 1$$
(8d)

where, *conducted_Tx_power(t)*, *conducted_Tx_power_P_{limit}*, and 1g_or_10gSAR_P_{limit} correspond to the measured instantaneous conducted Tx power, measured conducted Tx power at *P_{limit}*, and measured 1gSAR or 10gSAR values at *P_{limit}* corresponding to LTE transmission. Similarly, *radiated_Tx_power_1(t)*, *radiated_Tx_power_input.power.limit_1*, and 4cm²PD_input.power.limit_1 correspond to the measured instantaneous radiated Tx power, radiated_Tx_power_2(t), *radiated_Tx_power_limit_2*, and 4cm²PD_input.power.limit_2, and 4cm²PD_input.power.limit_2, and 4cm²PD_input.power.limit_2 correspond to the measured instantaneous radiated Tx power.limit_2 correspond to the measured instantaneous radiated Tx power, radiated Tx power at input.power.limit of beam 2 corresponding to mmW transmission.

Test procedure:

- 1. Measure conducted Tx power corresponding to *P*_{limit} for LTE in selected band, and measure radiated Tx power corresponding to *input.power.limit* in desired mmW band/channel/beam by following below steps:
 - a. Measure radiated power corresponding to mmW *input.power.limit* by setting up the EUT's Tx power in desired band/channel at *input.power.limit* of beam 1 in FTM. Do not disturb the position of the EUT inside the anechoic chamber for the rest of this test. Repeat this Step 1.a for beam 2.
 - b. Reset EUT to place in online mode and establish radio link in LTE, measure conducted Tx power corresponding to LTE *P*_{*limit*} with Smart Transmit enabled and *Reserve_power_margin* set to 0 dB, callbox set to request maximum power.
- 2. Set *Reserve_power_margin* to actual (intended) value and reset power in EUT, With EUT setup for LTE + mmW connection, perform the following steps:
 - a. Establish LTE (sub-6) and mmW NR connection in beam 1. As soon as the mmW connection is established, immediately request all-down bits on LTE link with the callbox requesting EUT's Tx power to be at maximum mmW power.
 - b. After beam 1 continues transmission for at least 20s, request the EUT to change from beam 1 to beam 2, and continue transmitting with beam 2 for at least 20s.
 - c. Record the conducted Tx power of LTE and radiated Tx power of mmW for the entire duration of this test.
- Once the measurement is done, extract instantaneous Tx power versus time for both LTE and mmW links. Convert the conducted Tx power for LTE into 1gSAR or 10gSAR value using the similar approach described in Step 3 of Section 5.3.2. Perform 100s running average to determine normalized 100s-averaged 1gSAR versus time.
- 4. Similarly, convert the radiated Tx power for mmW NR into 4cm²PD value using Eq. (8b), (8c) and the radiated Tx power limits (i.e., radiated Tx power at *input.power.limit*) measured in Step 1.a for beam 1 and beam 2, respectively, and then divide the resulted PD values by FCC 4cm²PD limit of 10W/m² to obtain instantaneous normalized 4cm²PD versus time for beam 1 and beam 2. Perform 4s running average to determine normalized 4s-averaged 4cm²PD versus time.
 - NOTE: In Eq.(8b) and (8c), instantaneous radiated Tx power of beam 1 and beam 2 is converted into instantaneous 4cm²PD by applying the worst-case 4cm²PD value measured at the *input.power.limit* of beam 1 and beam 2 in Part 1 report, respectively.

FCC ID: A3LSMA426U	Proud to be part of @ element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager
Document S/N:	Test Dates:	DUT Type:		Dage 25 of 00
1M2101040001-21.A3L	1/21/2021-3/2/2021	Portable Handset		Page 25 of 98
© 2021 PCTEST				REV 1.0

REV 1.0 04/06/2020

- 5. Since the measured radiated powers for beam 1 and beam 2 in Step 1.a were performed at an arbitrary rotation of EUT in anechoic chamber, repeat Step 1.a of this procedure by rotating the EUT to determine maximum radiated power at *input.power.limit* in FTM mode for both beams separately. Re-scale the measured instantaneous radiated power in Step 2.c by the delta in radiated power measured in Step 5 and the radiated power measured in Step 1.a for plotting purposes in next Step. In other words, this step essentially converts measured instantaneous radiated power for both beams. Perform 4s running average to compute 4s-avearged radiated Tx power. Additionally, use these EIRP values measured at *input.power.limit* at respective peak locations to determine the EIRP limits (using Eq. (5b)) for both these beams.
- 6. Make one plot containing: (a) instantaneous conducted Tx power for LTE versus time, (b) computed 100s-averaged conducted Tx power for LTE versus time, (c) instantaneous radiated Tx power for mmW versus time, as obtained in Step 5, (d) computed 4s-averaged radiated Tx power for mmW versus time, as obtained in Step 5, and (e) time-averaged conducted and radiated power limits for LTE and mmW radio, respectively.
- Make another plot containing: (a) computed normalized 100s-averaged 1gSAR versus time determined in Step 3, (b) computed normalized 4s-averaged 4cm²PD versus time determined in Step 4, and (c) corresponding total normalized time-averaged RF exposure (sum of steps (6.a) and (6.b)) versus time.

The validation criteria are, at all times, the total normalized time-averaged RF exposure versus time determined in Step 6.c shall not exceed the normalized limit of 1.0 of FCC requirement (i.e., (8d)).

5.4 Test procedure for time-varying PD measurements

The following steps are used to perform the validation through PD measurement for transmission scenario 1 described in Section 3:

- 1. Place the EUT on the cDASY6 platform to perform PD measurement in the worst-case position/surface for the selected mmW band/beam. In PD measurement, the callbox is set to request maximum Tx power from EUT all the time. Hence, "path loss" calibration between callbox antenna and EUT is not needed in this test.
- 2. Time averaging feature validation:
 - a. Measure conducted Tx power corresponding to *P*_{*limit*} for LTE in selected band, and measure point E-field corresponding to *input.power.limit* in desired mmW band/channel/beam by following the below steps:
 - i. Measure conducted Tx power corresponding to LTE *P*_{limit} with Smart Transmit <u>enabled</u> and *Reserve_power_margin* set to 0 dB, with callbox set to request maximum power.
 - ii. Measure point E-field at peak location of fast area scan corresponding to input.power.limit by setting up the EUT's Tx power in desired mmW band/channel/beam at input.power.limit in FTM. Do not disturb the position of EUT and mmW cDASY6 probe.
 - b. Set *Reserve_power_margin* to actual value (i.e., intended value) and reset power on EUT, place EUT in online mode. With EUT setup for LTE (sub-6) + mmW NR call, as soon as the mmW NR connection is established, request all-down bits on LTE link. Continue LTE (all-down bits) + mmW transmission for more than 100s duration to test predominantly PD exposure scenario. After 120s, request LTE to go all-up bits, mmW transmission should gradually reduce. Simultaneously, record the conducted Tx power of LTE transmission using power meter and point E-field (in terms of ratio of [lipointE(t)]2) of mmW transmission using cDASY6 E-field probe at peak location is for the optime duration of this test of at least 300s.

location identified in Step 2.a.ii for the entire duration of this test of at least 300s.

FCC ID: A3LSMA426U	Proud to be part of @ element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager
Document S/N:	Test Dates:	DUT Type:		Page 26 of 98
1M2101040001-21.A3L	1/21/2021-3/2/2021	Portable Handset		Fage 20 01 90
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- c. Once the measurement is done, extract instantaneous conducted Tx power versus time for LTE transmission and [pointE(t)]²/[pointE_input.power.limit]² ratio versus time from cDASY6 system for mmW transmission. Convert the conducted Tx power for LTE into 1gSAR or 10gSAR value using Eq. (4a) and P_{limit} measured in Step 2.a.i, and then divide this by FCC limit of 1.6 W/kg for 1gSAR or 4.0 W/kg for 10gSAR to obtain instantaneous normalized 1gSAR or 10gSAR versus time. Perform 100s running average to determine normalized 100s-averaged 1gSAR or 10gSAR versus time
 - NOTE: In Eq.(4a), instantaneous Tx power is converted into instantaneous 1gSAR or 10gSAR value by applying the measured worst-case 1gSAR or 10gSAR value at *P*_{limit} for the corresponding technology/band reported in Part 1 report.
- d. Similarly, convert the point E-field for mmW transmission into 4cm²PD value using Eq. (4b) and radiated power limit measured in Step 2.a.ii, and then divide this by FCC 4cm²PD limit of 10W/m² to obtain instantaneous normalized 4cm²PD versus time. Perform 4s running average to determine normalized 4s-averaged 4cm²PD versus time.
- e. Make one plot containing: (i) computed normalized 100s-averaged 1gSAR or 10gSAR versus time determined in Step 2.c, (ii) computed normalized 4s-averaged 4cm²PD versus time determined in Step 2.d, and (iii) corresponding total normalized time-averaged RF exposure (sum of steps (2.e.i) and (2.e.ii)) versus time.

The validation criteria are, at all times, the total normalized time-averaged RF exposure versus time determined in Step 2.e.iii shall not exceed the normalized limit of 1.0 of FCC requirement (i.e., Eq. (4c)).

FCC ID: A3LSMA426U	PCTEST* Proud to be part of @ element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager
Document S/N:	Test Dates:	DUT Type:		Dogo 27 of 09
1M2101040001-21.A3L	1/21/2021-3/2/2021	Portable Handset		Page 27 of 98
© 2021 PCTEST				REV 1.0

6 **MEASUREMENT TEST SETUP (FREQ < 6 GHZ)**

6.1 **Conducted Measurement Test setup**

Legacy Test Setup

The Rohde & Schwarz CMW500 callbox was used in this test. The test setup schematic is shown in Figure 6-1a (Appendix D – Test Setup Photo 1 and 2) for measurements with a single antenna of DUT, and in Figure 6-1b (Appendix D – Test Setup Photo 3) for measurements involving antenna switch. For single antenna measurement, one port (RF1 COM) of the callbox is connected to the RF port of the DUT using a directional coupler. For technology/band switch measurement, one port (RF1 COM) of the callbox used for signaling two different technologies is connected to a combiner, which is in turn connected to a directional coupler. The other end of the directional coupler is connected to a splitter to connect to two RF ports of the DUT corresponding to the two antennas of interest. In the setups, power meter is used to tap the directional coupler for measuring the conducted output power of the DUT. For all legacy conducted tests, only RF1 COM port of the callbox is used to communicate with the DUT.

Note that for this EUT, antenna switch test is included within time-window switch test as the selected technology/band combinations for the time-window switch test are on two different antennas.

All the path losses from RF port of DUT to the callbox RF COM port and to the power meter are calibrated and automatically entered as offsets in the callbox and the power meter via test scripts on the PC used to control callbox and power meter.

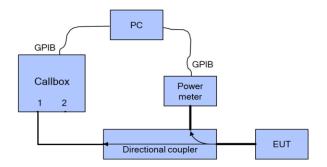
LTE+Sub6 NR test setup:

LTE conducted port and Sub6 NR conducted port are different on this EUT, therefore, the LTE and Sub6 NR signals for power meter measurement are performed on separate paths as shown below in Figure 6-1c (Appendix D – Test Setup Photo 4).

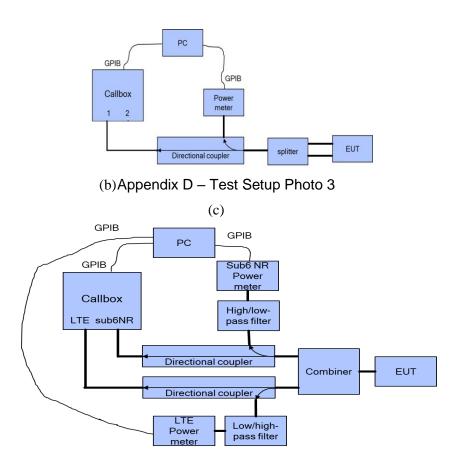
All the path losses from RF port of DUT to the callbox RF COM port and to the power meter are calibrated and automatically entered as offsets in the callbox and the power meter via test scripts on the PC used to control callbox and power meter.

FCC ID: A3LSMA426U	Proved to be part of @ element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager
Document S/N:	Test Dates:	DUT Type:		Dage 29 of 09
1M2101040001-21.A3L	1/21/2021-3/2/2021	Portable Handset		Page 28 of 98
© 2021 PCTEST				REV 1.0

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(a) Appendix D – Test Setup Photo 1 and 2



(d)Appendix D - Test Setup Photo 4

Figure 6-1 Conducted power measurement setup

FCC ID: A3LSMA426U	PCTEST* Proud to be part of @ element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager
Document S/N:	Test Dates:	DUT Type:		Dage 20 of 00
1M2101040001-21.A3L	1/21/2021-3/2/2021	Portable Handset		Page 29 of 98
© 2021 PCTEST				REV 1.0

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04/06/2020

Both the callbox and power meter are connected to the PC using GPIB cables. Two test scripts are custom made for automation, and the test duration set in the test scripts is 500 seconds.

For time-varying Tx power measurement, the PC runs the 1st test script to send GPIB commands to control the callbox's requested power versus time, while at the same time to record the conducted power measured at DUT RF port using the power meter. The commands sent to the callbox to request power are:

- 0dBm for 100 seconds
- test sequence 1 or test sequence 2 (defined in Section 4.1 and generated in Section 4.2.1), for 360 seconds
- stay at the last power level of test sequence 1 or test sequence 2 for the remaining time.

Power meter readings are periodically recorded every 100ms. A running average of this measured Tx power over 100 seconds is performed in the post-data processing to determine the 100s-time averaged power.

For call drop, technology/band/antenna switch, and DSI switch tests, after the call is established, the callbox is set to request the DUT's Tx power at 0dBm for 100 seconds while simultaneously starting the 2nd test script runs at the same time to start recording the Tx power measured at DUT RF port using the power meter. After the initial 100 seconds since starting the Tx power recording, the callbox is set to request maximum power from the DUT for the rest of the test. Note that the call drop/re-establish, or technology/band/antenna switch or DSI switch is manually performed when the Tx power of DUT is at Preserve level. See Section 4.3 for detailed test procedure of call drop test, technology/band/antenna switch test and DSI switch test.

6.2 SAR Measurement setup

The measurement setup is similar to normal SAR measurements as described in the Part 1 Test Report. The difference in SAR measurement setup for time averaging feature validation is that the callbox is signaling in close loop power control mode (instead of requesting maximum power in open loop control mode) and callbox is connected to the PC using GPIB so that the test script executed on PC can send GPIB commands to control the callbox's requested power over time (test sequence). The same test script used in conducted setup for time-varying Tx power measurements is also used in this section for running the test sequences during SAR measurements, and the recorded values from the disconnected power meter by the test script were discarded.

As mentioned in Section 4.4, for DUT to follow TPC command sent from the callbox wirelessly, the "path loss" between callbox antenna and the DUT needs to be very well calibrated. Since the SAR chamber is in uncontrolled environment, precautions must be taken to minimize the environmental influences on "path loss". Similarly, in the case of time-varying SAR measurements in Sub6 NR (with LTE as anchor), "path loss" between callbox antenna and the EUT needs to be carefully calibrated for both LTE link as well as for Sub6 NR link.

The DUT is placed in worst-case position according to Table 8-2.

FCC ID: A3LSMA426U	PCTEST* Proud to be part of @ element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager
Document S/N:	Test Dates:	DUT Type:		Page 30 of 98
1M2101040001-21.A3L	1/21/2021-3/2/2021	Portable Handset		Fage SU OI 90
© 2021 PCTEST		·		REV 1.0

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7 **MEASUREMENT TEST SETUP (FREQ > 6 GHZ)**

7.1 **Radiated Power Measurement Test setup**

The Keysight Technologies E7515B UXM callbox is used in this test. The schematic of the setup is shown in Figure 7-1. The UXM callbox has two RF radio heads to up/down convert IF to mmW frequencies, which in turn are connected to two horn antennas for V- and H-polarizations for downlink communication. In the uplink, a directional coupler is used in the path of one of the horn antennas to measure and record radiated power using a Rohde & Schwarz NRP50S power sensor. Note here that the isolation of the directional coupler may not be sufficient to attenuate the downlink signal from the callbox, which will result in high noise floor masking the recording of radiated power from EUT. In that case, either lower the downlink signal strength emanating from the RF radio heads of callbox or add an attenuator between callbox radio heads and directional coupler. Additionally, note that since the measurements performed in this validation are all relative, measurement of EUT's radiated power in one polarization is sufficient. The EUT is placed inside an anechoic chamber with V- and H-pol horn antennas to establish the radio link as shown in Figure 7-1. The callbox's LTE port is directly connected to the EUT's RF port via a directional coupler to measure the EUT's conducted Tx power using a Rohde & Schwarz NRP8S power sensor. Additionally, EUT is connected to the PC via USB connection for sending beam switch command. Care is taken to route the USB cable and RF cable (for LTE connection) away from the EUT's mmW antenna modules.

Setup in Figure 7-1 is used for the test scenario 1, 5 and 6 described in Section 3. The test procedures described in Section 5 are followed. The path losses from the EUT to both the power meters are calibrated and used as offset in the power meter.

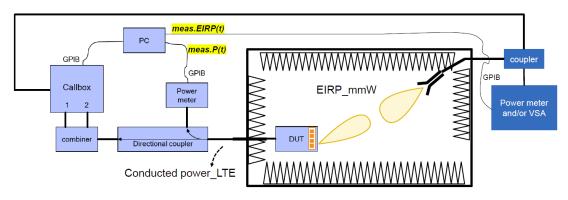


Figure 7-1 mmW NR radiated power measurement setup – Test Setup Photo 11 and 12

Both the callbox and power meters are connected to the PC using USB cables. Test scripts are custom made for automation of establishing LTE + mmW call, conducted Tx power recording for LTE and radiated Tx power recording for mmW. These tests are manually stopped after desired time duration. Test script is programmed to set LTE Tx power to all-down bits on the callbox immediately after the mmW link is established, and programmed to set toggle between all-up and all-down bits depending on the transmission scenario being evaluated. Similarly, test script is also programmed to send beam switch command manually to the EUT via USB connection. For all the tests, the callbox is set to request maximum Tx power in mmW NR radio from EUT all the time.

Test configurations for this validation are detailed in Section 5.2. Test procedures are listed in Section 5.3.

FCC ID: A3LSMA426U	PCTEST* Proud to be part of @ element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager
Document S/N:	Test Dates:	DUT Type:		Dage 21 of 09
1M2101040001-21.A3L	1/21/2021-3/2/2021	Portable Handset		Page 31 of 98
© 2021 PCTEST				REV 1.0

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7.2 Power Density Measurement Test setup

The measurement setup is similar to normal PD measurements, the EUT is positioned on cDASY6 platform, and is connected with the callbox (conducted for LTE and wirelessly for mmW). Keysight UXM callbox is set to request maximum mmW Tx power from EUT all the time. Hence, "path loss" calibration between callbox antenna and EUT is not needed in this test. The callbox's LTE port is directly connected to the EUT's RF port via a directional coupler to measure the EUT's conducted Tx power using a Rohde & Schwarz NRP8S power sensor. Additionally, EUT is connected to the PC via USB connection for toggling between FTM and online mode with Smart Transmit enabled following the test procedures described Section 5.4.

Worst-surface of EUT (for the mmW beam being tested) is positioned facing up for PD measurement with cDASY6 mmW probe. Figure 7-2 shows the schematic of this measurement setup.

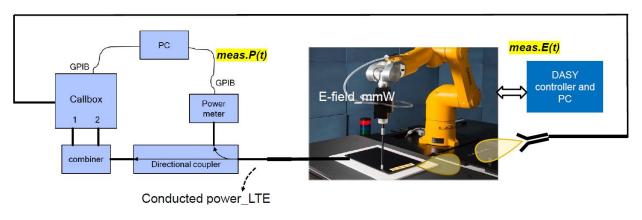


Figure 7-2 Power Density Measurement Setup – Test Setup Photo 9 and 10

Both callbox and power meters are connected to the PC using USB cables. Test scripts are custom made for automation of establishing LTE + mmW call, and for conducted Tx power recording of LTE transmission. These tests are manually stopped after desired time duration. Once the mmW link is established, LTE Tx power is programmed to toggle between all-up and all-down bits on the callbox. For all the tests, the callbox is set to request maximum Tx power in mmW NR radio from EUT all the time. Therefore, the calibration for the pathloss between the EUT and the horn antenna connected to the remote radio head of the callbox is not required.

Power meter readings are periodically recorded every 10ms on NR8S power sensor for LTE conducted Tx power. Time-averaged E-field measurements are performed using EUmmWV3 mmW probe at peak location of fast area scan. The distance between EUmmWV3 mmW probe tip to EUT surface is ~0.5 mm, and the distance between EUmmWV3 mmW probe sensor to probe tip is 1.5 mm. cDASY6 records relative point E-field (i.e., ratio $\frac{[pointE(t)]^2}{[pointE_input.power.limit]^2}$) versus time for mmW NR transmission.

FCC ID: A3LSMA426U	PCTEST [®] Proud to be part of @ element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager	
Document S/N:	Test Dates:	DUT Type:		Page 32 of 98	
1M2101040001-21.A3L	1/21/2021-3/2/2021	Portable Handset		Fage 32 01 90	
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REV 1.0 04/06/2020

8 **TEST CONFIGURATIONS (FREQ < 6 GHZ)**

WWAN (sub-6) transmission 8.1

The Plimit values, corresponding to 1.0 W/kg (1gSAR) and 2.5 W/kg (10gSAR) of SAR_design_target, for technologies and bands supported by DUT are derived in Part 0 report and summarized in Table 8-1. Note all P_{limit} power levels entered in Table 8-1 correspond to average power levels after accounting for duty cycle in the case of TDD modulation schemes.

				-		-	-	
Exposure Scenario:		Body-Worn	Phablet	Phablet	Head	Hotspot	Earjack	
Averaging Volume:		1g	10g	10g	1g	1g	10g	Maximum Tune-up
Spacing:	Antenna	15 mm	7, 10, 6 mm	0 mm	0 mm	10 mm	0 mm	Output Power*
DSI:		0	0	4, 5, 6	1	2	3	
Technology/Band			Plimit co	rresponding to 1r	nW/g (SAR_desig	n_target)		Pmax
CDMA BC10	MAIN1	28	3.9	27.0	30.7	26.1	27.0	25.0
EVDO BC10	MAIN1	28	3.9	27.0	30.7	26.1	27.0	24.0
CDMA BC0	MAIN1	29).7	29.7	30.1	25.8	29.7	25.0
EVDO BCO	MAIN1	29	9.7	29.7	30.1	25.8	29.7	24.0
CDMA BC1	MAIN1	25	5.0	19.0	32.4	19.0	19.0	25.0
EVDO BC1	MAIN1	25	5.0	19.0	32.4	19.0	19.0	24.0
GSM/GPRS/EDGE 850 MHz	MAIN1	29	9.4	29.0	30.6	27.1	29.0	25.8
GSM/GPRS/EDGE 1900 MHz	MAIN1	25	5.7	24.8	33.3	24.0	24.8	22.6
UMTS B5	MAIN1	29	9.5	28.0	31.1	27.7	28.0	24.0
UMTS B4	MAIN1	24	1.2	20.0	30.5	20.0	20.0	24.0
UMTS B2	MAIN1	27	7.0	21.0	33.5	21.0	21.0	24.0
TE FDD B71	MAIN1	29	29.1		33.8	28.5	28.5	24.5
LTE FDD B12	MAIN1	28	28.6		31.1	27.9	28.7	23.0
LTE FDD B13	MAIN1	29	29.0		32.0	26.6	26.6	23.0
LTE FDD B14	MAIN1	30).1	30.8	31.6	27.3	30.8	24.5
LTE FDD B26	MAIN1	29	9.4	28.0	30.9	27.4	28.0	24.0
LTE FDD B5	MAIN1	29).2	28.2	33.5	28.1	28.2	23.0
LTE FDD B66	MAIN1	25	5.4	21.0	30.6	21.0	21.0	23.5
LTE FDD B4	MAIN1	25	5.4	21.0	30.6	21.0	21.0	23.0
LTE FDD B25	MAIN1	24	1.0	19.0	33.0	19.0	19.0	23.5
LTE FDD B2	MAIN1	24	1.0	19.0	33.0	19.0	19.0	23.0
LTE FDD B30	MAIN2	25	5.0	18.5	18.5	18.5	18.5	22.0
LTE FDD B7	MAIN2	23	3.0	18.5	18.5	18.5	18.5	23.0
LTE TDD B48	SUB4	20).8	20.8	15.0	18.5	20.8	20.0
LTE TDD B41	MAIN2	26	5.0	18.5	18.5	18.5	18.5	21.5
TE TDD B41 (PC2)	MAIN2	26	26.0		18.5	18.5	18.5	22.4
NR FDD n71	MAIN1	29.1		29.3	33.8	28.2	29.3	24.0
NR FDD n5	MAIN1	29.9		29.9	31.7	27.1	29.9	24.0
NR FDD n66	MAIN1	24	24.1		31.5	21.0	21.0	24.0
NR FDD n25/2	MAIN1	24	24.2		31.4	21.0	21.0	24.0
NR TDD n41	MAIN2	18	18.0		14.0	18.0	18.0	23.0
NR TDD n77	SUB4	17.5		18.0 17.5	14.5	17.5	17.5	23.0

Table 8-1 Plimit for supported technologies and bands (Plimit in EFS file)

* Maximum tune up target power, Pmax, is configured in NV settings in DUT to limit maximum transmitting power. This power is converted into peak power in NV settings for TDD schemes. The DUT maximum allowed output power is equal to $P_{max} + 1$ dB device uncertainty.

Based on selection criteria described in Section 4.2.1, the selected technologies/bands for testing time-varying test sequences are highlighted in yellow in Table 8-1. Per the manufacturer, the Reserve_power_margin (dB) is set to 3dB in EFS and is used in Part 2 test.

The radio configurations used in Part 2 test for selected technologies, bands, DSIs and antennas are listed in Table 8-2. The corresponding worst-case radio configuration 1gSAR values for selected technology/band/DSI are extracted from Part 1 report and are listed in the last column of Table 8-2.

FCC ID: A3LSMA426U	Proud to be part of @ element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager
Document S/N:	Test Dates:	DUT Type:		Dogo 22 of 09
1M2101040001-21.A3L	1/21/2021-3/2/2021	Portable Handset		Page 33 of 98
© 2021 PCTEST				REV 1.0

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Based on equations (1a), (2a), (3a) and (4a), it is clear that Part 2 testing outcome is normalized quantity, which implies that it can be applied to any radio configuration within a selected technology/band/DSI. Thus, as long as applying the worst-case SAR obtained from the worst radio configuration in Part 1 testing to calculate time-varying SAR exposure in equations (1a), (2a), (3a) and (4a), the accuracy in compliance demonstration remains the same. Therefore, there may be some differences between the radio configuration selected for Part 2 testing and the radio configuration associated with worst-case SAR obtained in the Part 1 evaluation.

Test Case #	Test Scenario	Tech	Band	Antenna	DSI	Channel	Frequency [MHz]	RB/RB Offset/Bandwidth (MHz)	Mode	SAR Exposure Scenario	SAR Exposure Scenario	Part 1 Worst Case Measured SAR at Plimit (W/kg)					
1	Test Sequence 1		66	MAIN1	2	132322	1745	1/50/20 MHz BW	QPSK	Hotspot	back, 10 mm	0.506					
I	Test Sequence 2	LTE	00	IVIAIINT	2	132322	1745	1/50/20 MHz BW	QPSK	Hotspot	Dack, TU mm	0.506					
2	Test Sequence 1		48	SUB4	1	56207	3646.7	1/50/20 MHz BW	QPSK	Head	right, tilt	0.901					
2	Test Sequence 2		40	3064	1	56207	3646.7	1/50/20 MHz BW	QPSK	neau	rigrit, uit	0.901					
3	Test Sequence 1		2	MAIN1	2	9400	1880	-	RMC	Hotspot	back. 10 mm	0.395					
3	Test Sequence 2	WCDMA	2	IVIAIINT	2	9400	1880	-	RMC	Ногарог	Dack, TO MIN	0.395					
4	Test Sequence 1	WCDINA	4	MAIN1	2	1412	1732	-	RMC	Hotspot	back. 10 mm	0.825					
4	Test Sequence 2		4	WAINT	2	1412	1732	-	RMC	Hotspot	Dack, TO MIN	0.625					
5	Test Sequence 1	CDMA	PCS	MAIN1	2	600	1880	-	1x EvDO Rev.0	Hotspot	back, 10 mm	0.302					
5	Test Sequence 2	CDIVIA	FUS	IVIAIINT	2	600	1880	-	TX EVDO Nev.0	Ногарог	Dack, TO MIN	0.302					
6	Test Sequence 1			n25/NSA	MAIN1	2	176500	1882.5	1/1/20 MHz BW	DFT-S-OFDM, QPSK	Hotspot	back. 10 mm	0.554				
0	Test Sequence 2	Sub6 NR	1120/110A	IVIAIINT	2	176500	1882.5	1/1/20 MHz BW	DFT-S-OFDM, QPSK	Hotspot	Dack, TO MIN	0.554					
7	Test Sequence 1	SUDO INR	n66/NSA	MAIN1	2	349000	1745	1/1/20 MHz BW	DFT-S-OFDM, QPSK	Hotspot	back. 10 mm	0.427					
'	Test Sequence 2		100/100	N/AINI	2	349000	1745	1/1/20 MHz BW	DFT-S-OFDM, QPSK	Потарот	back, romin	0.427					
8	Call Drop	LTE	48	SUB4	1	56207	3646.7	1/50/20 MHz BW	QPSK	Head	right, tilt	0.901					
9	Tech Switch	LTE	66	MAIN1	2	132322	1745	1/50/20 MHz BW	QPSK	Hotspot	back, 10 mm	0.506					
3	Tech Switch	WCDMA	4	MAIN1	2	1412	1732	-	RMC	Hotspot	back, 10 mm	0.825					
10	Time Window/Antenna	LTE	66	MAIN1	2	132322	1745	1/50/20 MHz BW	QPSK	Hotspot	back, 10 mm	0.506					
10	Switch		48	SUB4	2	56207	3646.7	1/50/20 MHz BW	QPSK	Hotspot	top, 10 mm	0.780					
11	DSI Switch	I TE	ITE	LTE	ITE	ITE	LTE	48	SUB4	1	56207	3646.7	1/50/20 MHz BW	QPSK	Head	right, tilt	0.901
11	DOI OWNER		40	0004	2	56207	3646.7	1/50/20 MHz BW	QPSK	Hotspot	top, 10 mm	0.780					
12	SAR1 vs SAR2	LTE	5	MAIN1	2	20525	836.5	1/0/10 MHz BW	QPSK	Hotspot	back, 10 mm	0.333					
12		Sub6 NR	n66/NSA	MAIN1	2	349000	1745	1/1/20 MHz BW	DFT-S-OFDM, QPSK	Hotspot	back, 10mm	0.427					

Table 8-2 Radio Configurations Selected for Part 2 Tests

Table 8-3
DSI and Corresponding Exposure Scenarios

Scenario	Description	SAR Test Cases
Head (DSI = 1)	 Device positioned next to head Receiver Active 	Head SAR per KDB Publication 648474 D04
Hotspot mode (DSI = 2)	 Device transmits in hotspot mode near body Hotspot Mode Active 	Hotspot SAR per KDB Publication 941225 D06
Phablet Grip (DSI=3, 4, 5, or 6)	 Device is held with hand and grip sensor is triggered Grip sensor triggered or earjack is active 	Phablet SAR per KDB Publication 648474 D04 & KDB Publication 616217 D04
Phablet (DSI = 0)	 Device is held with hand and grip sensor is not triggered Distance grip sensor not triggered 	Phablet SAR per KDB Publication 648474 D04 & KDB Publication 616217 D04
Body-worn (DSI = 0)	 Device being used with a body-worn accessory 	Body-worn SAR per KDB Publication 648474 D04

FCC ID: A3LSMA426U	PCTEST* Proud to be part of @ element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager
Document S/N:	Test Dates:	DUT Type:		Dage 24 of 08
1M2101040001-21.A3L	1/21/2021-3/2/2021	Portable Handset		Page 34 of 98
© 2021 PCTEST				REV 1.0

Based on the selection criteria described in Section 4.2, the radio configurations for the Tx varying transmission test cases listed in Section 3 are:

- 1. <u>Technologies and bands for time-varying Tx power transmission</u>: The test case 1~7 listed in Table 8-2 are selected to test with the test sequences defined in Section 4.1 in both time-varying conducted power measurement and time-varying SAR measurement.
- <u>Technology and band for change in call test</u>: LTE Band 48, having the lowest *P_{limit}* among all technologies and bands (test case 8 in Table 8-2), is selected for performing the call drop test in conducted power setup.
- 3. <u>Technologies and bands for change in technology/band test</u>: Following the guidelines in Section 4.2.3, test case 9 in Table 8-2 is selected for handover test from a technology/band within one technology group (LTE Band 66, DSI=2, MAIN1 Antenna), to a technology/band in the same DSI within another technology group (WCDMA Band 4, DSI=2, MAIN1 Antenna) in conducted power setup.
- <u>Technologies and bands for change in time-window/antenna</u>: Based on selection criteria in Section 4.2.6, for a given DSI=2, test case 10 in Table 8-2 is selected for time window switch between 60s window (LTE Band 48, SUB4 Antenna) and 100s window (LTE band 66, MAIN1 Antenna) in conducted power setup.
- <u>Technologies and bands for change in DSI</u>: Based on selection criteria in Section 4.2.5, for a given technology and band, test case 11 in Table 8-2 is selected for DSI switch test by establishing a call in LTE Band 48 in DSI=2, and then handing over to DSI= 1 exposure scenario in conducted power setup.
- 6. <u>Technologies and bands for switch in SAR exposure</u>: Based on selection criteria in Section 4.2.7 Scenario 1, test case 12 in Table 8-2 is selected for SAR exposure switching test in one of the supported simultaneous WWAN transmission scenario, i.e., LTE + Sub6 NR active in the same 100s time window, in conducted power setup. Since this device supports LTE+mmW NR, test for Section 4.2.7 Scenario 2 for RF exposure switch is covered in Sections 13.1 and 13.2 between LTE (100s window) and mmW NR (4s window).

FCC ID: A3LSMA426U	Proud to be part of @ element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager
Document S/N:	Test Dates:	DUT Type:		Dogo 25 of 08
1M2101040001-21.A3L	1/21/2021-3/2/2021	Portable Handset		Page 35 of 98
© 2021 PCTEST				REV 1.0

REV 1.0 04/06/2020

8.2 *Plimit* and *Pmax* measurement results

The measured *P*_{limit} for all the selected radio configurations given in Table 8-2 are listed in below Table 8-4. *P_{max}* was also measured for radio configurations selected for testing time-varying Tx power transmission scenarios in order to generate test sequences following the test procedures in Section 4.1.

Test Case #	Test Scenario	Tech	Band	Antenna	DSI	Channel	Frequency [MHz]	RB/RB Offset/Bandwidth (MHz)	Mode	SAR Exposure Scenario	EFS Plimit [dBm]	Tune-up Pmax [dBm]	Measured Plimit [dBm]	Measured Pmax [dBm]					
1	Test Sequence 1		66	MAIN1	2	132322	1745	1/50/20 MHz BW	QPSK	Hotspot	21.0	23.5	20.88	23.04					
	Test Sequence 2	LTE	00	IVI/ATINT	2	132322	1745	1/50/20 MHz BW	QPSK	Hoispoi	21.0	23.5	20.88	23.04					
2	Test Sequence 1		48	SUB4	1	56207	3646.7	1/50/20 MHz BW	QPSK	Head	15.0	20.0	15.17	20.38					
2	Test Sequence 2		40	3004		56207	3646.7	1/50/20 MHz BW	QPSK	Tiedu	15.0	20.0	15.17	20.38					
3	Test Sequence 1		2	MAIN1	2	9400	1880	-	RMC	Hotspot	21.0	24.0	21.07	24.06					
3	Test Sequence 2	WCDMA	2	IVI/ATINT	2	9400	1880	-	RMC	Hoispoi	21.0	24.0	21.07	24.06					
4	Test Sequence 1	WODINA	4	MAIN1	2	1412	1732	-	RMC	Hotspot	20.0	24.0	20.85	23.89					
4	Test Sequence 2		4		2	1412	1732	-	RMC	Потарот	20.0	24.0	20.85	23.89					
5	Test Sequence 1	CDMA	PCS	MAIN1	2	600	1880	-	1x EvDO Rev.0	Hotspot	19.0	24.0	19.77	23.94					
5	Test Sequence 2	CDIVIA	100		2	600	1880	-	TX EVDO Nev.0	Потарот	19.0	24.0	19.77	23.94					
6	Test Sequence 1		DOE/NICA	n25/NGA	n25/NSA	n25/NSA	n25/NSA	n25/NSA	MAIN1	2	176500	1882.5	1/1/20 MHz BW	DFT-S-OFDM, QPSK	Hotspot	21.0	24.0	21.75	23.69
0	Test Sequence 2	Sub6 NR	123/1137	NI-ALI NI	2	176500	1882.5	1/1/20 MHz BW	DFT-S-OFDM, QPSK	Поізрої	21.0	24.0	21.75	23.69					
7	Test Sequence 1	Subornit	n66/NSA	MAIN1	2	349000	1745	1/1/20 MHz BW	DFT-S-OFDM, QPSK	Hotspot	21.0	24.0	21.68	23.53					
'	Test Sequence 2		1100/140/1	NV ALAL	2	349000	1745	1/1/20 MHz BW	DFT-S-OFDM, QPSK	Tiotopot	21.0	24.0	21.68	23.53					
8	Call Drop	LTE	48	SUB4	1	56207	3646.7	1/50/20 MHz BW	QPSK	Head	15.0	20.0	15.17	20.38					
9	Tech Switch	LTE	66	MAIN1	2	132322	1745	1/50/20 MHz BW	QPSK	Hotspot	21.0	23.5	20.88	23.04					
3	Tech Switch	WCDMA	4	MAIN1	2	1412	1732	-	RMC	Hotspot	20.0	24.0	20.85	23.89					
10	Time Window/Antenna	LTE	66	MAIN1	2	132322	1745	1/50/20 MHz BW	QPSK	Hotspot	21.0	23.5	20.88	23.04					
10	Switch		48	SUB4	2	56207	3646.7	1/50/20 MHz BW	QPSK	Hotspot	18.5	20.0	19.16	20.38					
11	DSI Switch	LTE 4	48	SUB4	1	56207	3646.7	1/50/20 MHz BW	QPSK	Head	15.0	20.0	15.17	20.38					
**	DOI OWIICH		LIE	-0	0004	2	56207	3646.7	1/50/20 MHz BW	QPSK	Hotspot	18.5	20.0	19.16	20.38				
12	SAR1 vs SAR2	LTE	5	MAIN1	2	20525	836.5	1/0/10 MHz BW	QPSK	Hotspot	28.1	23.0	22.67	22.67					
12	ONIT 18 OANZ	Sub6 NR	n66/NSA	MAIN1	2	349000	1745	1/1/20 MHz BW	DFT-S-OFDM, QPSK	Hotspot	21.0	24.0	21.68	23.53					

Table 8-4 Measured Plimit and Pmax of Selected Radio Configurations

Note: The device uncertainty of P_{max} is +/- 1 dB as provided by manufacturer.

8.3 **EFS v15 Verification**

Per Qualcomm's 80-w2112-5 document, embedded file system (EFS) version 15 products are required to be verified for Smart Tx generation for relevant MCC settings. It was confirmed that this DUT contains embedded file system (EFS) version 15 configured for Smart Tx first generation (GEN1) with MCC settings for the US market.

EFS v15 Generation	мсс
GEN1	311

FCC ID: A3LSMA426U		PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager	
Document S/N:	Test Dates:	DUT Type:		Page 36 of 98	
1M2101040001-21.A3L	1/21/2021-3/2/2021	Portable Handset			
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9 CONDUCTED TX CASES (FREQ < 6 GHZ)

FCC SAR limit

9.1 **Time-varying Tx Power Case**

The measurement setup is shown in Figure 6-1. The purpose of the time-varying Tx power measurement is to demonstrate the effectiveness of power limiting enforcement and that the time-averaged Tx power when represented in time-averaged 1gSAR or 10gSAR values does not exceed FCC limit as shown in Eq. (1a) and (1b), rewritten below:

$$1g_or_10gSAR(t) = \frac{conducted_Tx_power(t)}{conducted_Tx_power_P_{limit}} * 1g_or_10gSAR_P_{limit}$$
(1a)
$$\frac{\frac{1}{T_{SAR}}\int_{t=T_{SAR}}^{t} 1g_or_10gSAR(t)dt}{T_{SAR}} \leq 1$$
(1b)

where, $conducted_Tx_power(t)$, $conducted_Tx_power_P_{limit}$, and $1g_or_10gSAR_P_{limit}$ correspond to the measured instantaneous conducted Tx power, measured conducted Tx power at Plimit, and measured 1gSAR and 10gSAR values at Plimit reported in Part 1 test (listed in Table 8-2 of this report as well).

Following the test procedure in Section 4.3, the conducted Tx power measurement for all selected configurations are reported in this section. In all the conducted Tx power plots, the dotted line represents the requested power by callbox (test sequence 1 or test sequence 2), the blue curve represents the instantaneous conducted Tx power measured using power meter, the green curve represents time-averaged power and red line represents the conducted power limit that corresponds to FCC limit of 1.6 W/kg for 1gSAR or 4.0 W/kg for 10gSAR.

Similarly, in all the 1g or 10gSAR plots (when converted using Eq. (1a)), the green curve represents the 100s/60s-time averaged 1gSAR or 10gSAR value calculated based on instantaneous 1gSAR or 10gSAR; and the red line limit represents the FCC limit of 1.6 W/kg for 1gSAR or 4.0 W/kg for 10gSAR.

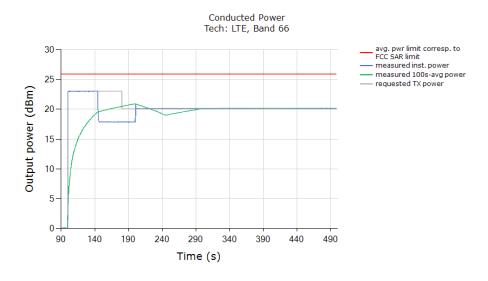
Time-varying Tx power measurements were conducted on test cases $\#1 \sim \#7$ in Table 8-2, by generating test sequence 1 and test sequence 2 given in APPENDIX E: using measured Plimit and measured Pmax (last two columns of Table 8-4) for each of these test cases. Measurement results for test cases #1 ~ #7 are given in Sections 9.1.1-9.1.7.

FCC ID: A3LSMA426U	Proud to be part of @ element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager	
Document S/N:	Test Dates:	DUT Type:		Da ra 07 at 00	
1M2101040001-21.A3L	1/21/2021-3/2/2021	Portable Handset		Page 37 of 98	
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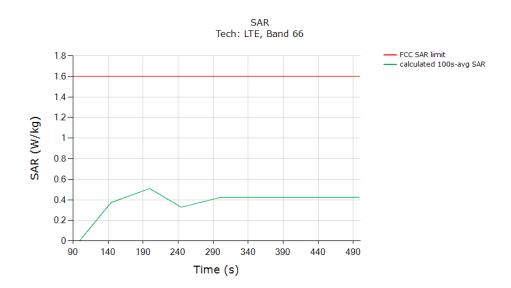
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Test result for test sequence 1:



Above time-averaged conducted Tx power is converted/calculated into time-averaged 1gSAR using Equation (1a) and plotted below to demonstrate that the time-averaged 1gSAR versus time does not exceed the FCC limit of 1.6 W/kg for 1gSAR:

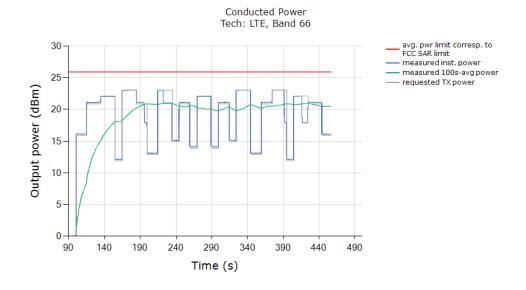


	(W/kg)
FCC 1gSAR limit	1.6
Max 100s-time averaged 1gSAR (green curve)	0.510
Validated: Max time averaged SAR (green curve) is within 1 dB device uncertainty of measured SAR at <i>P</i> _{limit} (last column in Table 8-2).	

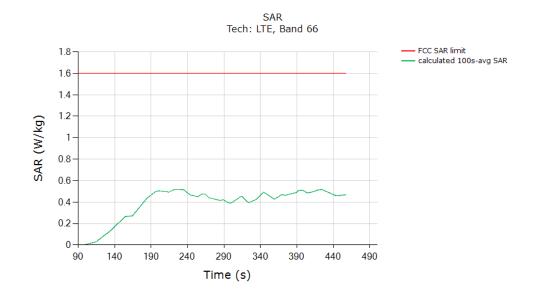
FCC ID: A3LSMA426U	Proud to be part of @ element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager
Document S/N:	Test Dates:	DUT Type:		Daga 28 of 09
1M2101040001-21.A3L	1/21/2021-3/2/2021	Portable Handset		Page 38 of 98
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REV 1.0 04/06/2020

Test result for test sequence 2:



Above time-averaged conducted Tx power is converted/calculated into time-averaged 1gSAR using Equation (1a) and plotted below to demonstrate that the time-averaged 1gSAR versus time does not exceed the FCC limit of 1.6 W/kg for 1gSAR:



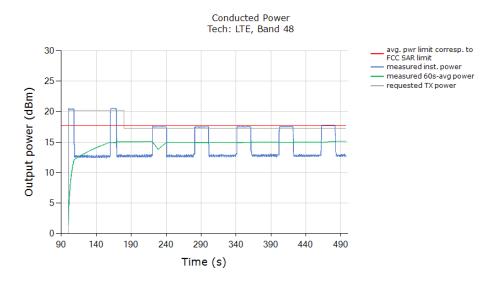
	(W/kg)	
FCC 1gSAR limit	1.6	
Max 100s-time averaged 1gSAR (green curve)	0.517	
Validated: Max time averaged SAR (green curve) is within 1 dB device uncertainty of measured SAR at <i>P</i> _{limit} (last column in Table 8-2).		

FCC ID: A3LSMA426U	Proud to be part of @ element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager
Document S/N:	Test Dates:	DUT Type:		Daga 20 of 09
1M2101040001-21.A3L	1/21/2021-3/2/2021	Portable Handset		Page 39 of 98
© 2021 PCTEST				REV 1.0

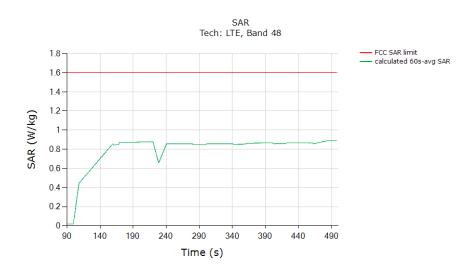
REV 1.0 04/06/2020



Test result for test sequence 1:



Above time-averaged conducted Tx power is converted/calculated into time-averaged 1gSAR using Equation (1a) and plotted below to demonstrate that the time-averaged 1gSAR versus time does not exceed the FCC limit of 1.6 W/kg for 1gSAR:

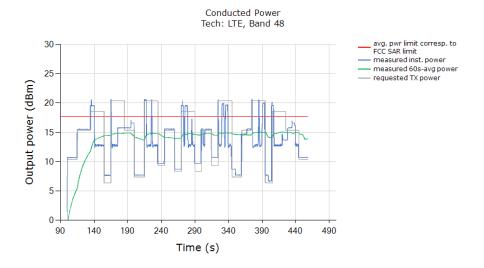


	(W/kg)
FCC 1gSAR limit	1.6
Max 60s-time averaged 1gSAR (green curve)	0.892
Validated: Max time averaged SAR (green curve) is within 1 dB device uncertair SAR at <i>P</i> _{limit} (last column in Table 8-2).	nty of measured

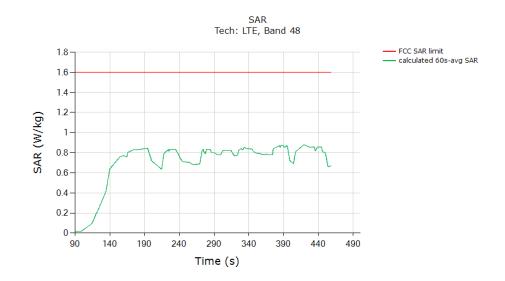
FCC ID: A3LSMA426U	Poctest* Proud to be part of @ element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager
Document S/N:	Test Dates:	DUT Type:		Dage 40 of 00
1M2101040001-21.A3L	1/21/2021-3/2/2021	Portable Handset		Page 40 of 98
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REV 1.0 04/06/2020

Test result for test sequence 2:



Above time-averaged conducted Tx power is converted/calculated into time-averaged 1gSAR using Equation (1a) and plotted below to demonstrate that the time-averaged 1gSAR versus time does not exceed the FCC limit of 1.6 W/kg for 1gSAR:

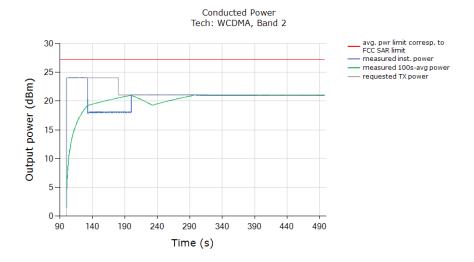


	(W/kg)
FCC 1gSAR limit	1.6
Max 60s-time averaged 1gSAR (green curve)	0.878
Validated: Max time averaged SAR (green curve) is within 1 dB device uncertainty of measured SAR at <i>Plimit</i> (last column in Table 8-2).	

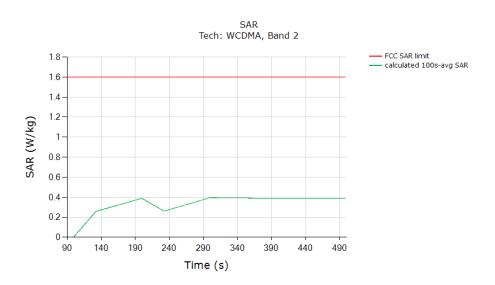
FCC ID: A3LSMA426U	Proud to be part of @ element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager	
Document S/N:	Test Dates:	DUT Type:		Dana 44 of 00	
1M2101040001-21.A3L	1/21/2021-3/2/2021	Portable Handset		Page 41 of 98	
© 2021 PCTEST		•		REV 1.0	

9.1.3 WCDMA B2

Test result for test sequence 1:



Above time-averaged conducted Tx power is converted/calculated into time-averaged 1gSAR using Equation (1a) and plotted below to demonstrate that the time-averaged 1gSAR versus time does not exceed the FCC limit of 1.6 W/kg for 1gSAR:

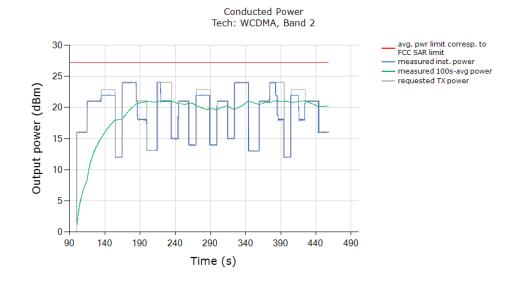


	(W/kg)
FCC 1gSAR limit	1.6
Max 100s-time averaged 1gSAR (green curve)	0.395
Validated: Max time averaged SAR (green curve) is within 1 dB device uncertainty of measured SAR at <i>P</i> _{limit} (last column in Table 8-2).	

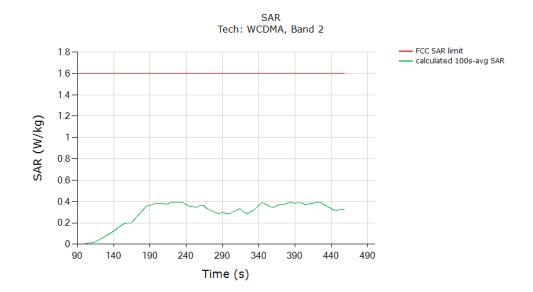
FCC ID: A3LSMA426U	Proud to be part of @ element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager
Document S/N:	Test Dates:	DUT Type:		Dage 42 of 00
1M2101040001-21.A3L	1/21/2021-3/2/2021	Portable Handset		Page 42 of 98
© 2021 PCTEST				REV 1.0

REV 1.0 04/06/2020

Test result for test sequence 2:



Above time-averaged conducted Tx power is converted/calculated into time-averaged 1gSAR using Equation (1a) and plotted below to demonstrate that the time-averaged 1gSAR versus time does not exceed the FCC limit of 1.6 W/kg for 1gSAR:

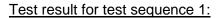


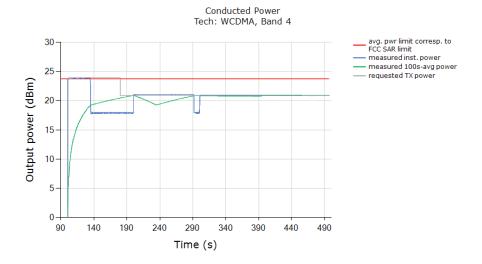
	(W/kg)
FCC 1gSAR limit	1.6
Max 100s-time averaged 1gSAR (green curve)	0.394
Validated: Max time averaged SAR (green curve) is within 1 dB device uncertainty of measured SAR at <i>Plimit</i> (last column in Table 8-2).	

FCC ID: A3LSMA426U	PCTEST* Proud to be part of @ element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager
Document S/N:	Test Dates:	DUT Type:		Dage 42 of 09
1M2101040001-21.A3L	1/21/2021-3/2/2021	Portable Handset		Page 43 of 98
© 2021 PCTEST	•			REV 1.0

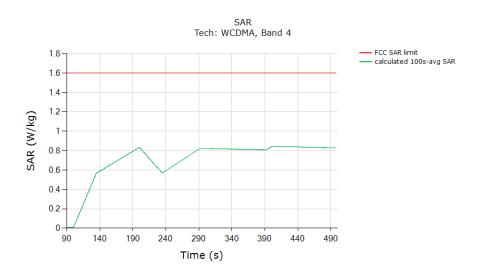
REV 1.0 04/06/2020

9.1.4 WCDMA B4





Above time-averaged conducted Tx power is converted/calculated into time-averaged 1gSAR using Equation (1a) and plotted below to demonstrate that the time-averaged 1gSAR versus time does not exceed the FCC limit of 1.6 W/kg for 1gSAR:

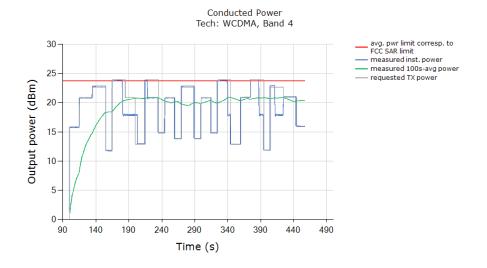


	(W/kg)
FCC 1gSAR limit	1.6
Max 100s-time averaged 1gSAR (green curve)	0.843
Validated: Max time averaged SAR (green curve) is within 1 dB device uncertain SAR at <i>Plimit</i> (last column in Table 8-2).	nty of measured

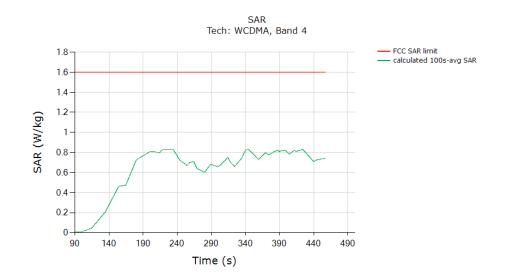
FCC ID: A3LSMA426U	PCTEST Proud to be part of @ element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager
Document S/N:	Test Dates:	DUT Type:		Page 44 of 98
1M2101040001-21.A3L	1/21/2021-3/2/2021	Portable Handset		Page 44 01 98
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REV 1.0 04/06/2020

Test result for test sequence 2:



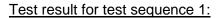
Above time-averaged conducted Tx power is converted/calculated into time-averaged 1gSAR using Equation (1a) and plotted below to demonstrate that the time-averaged 1gSAR versus time does not exceed the FCC limit of 1.6 W/kg for 1gSAR:

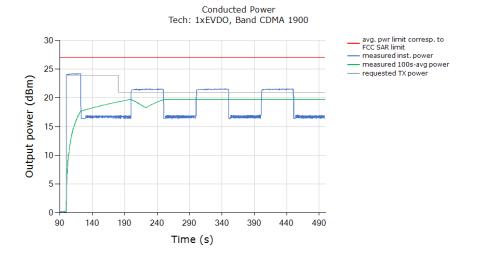


	(W/kg)
FCC 1gSAR limit	1.6
Max 100s-time averaged 1gSAR (green curve)	0.831
Validated: Max time averaged SAR (green curve) is within 1 dB device uncertain SAR at <i>Plimit</i> (last column in Table 8-2).	nty of measured

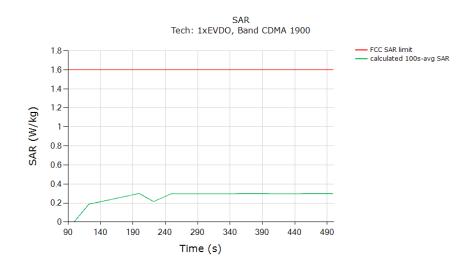
FCC ID: A3LSMA426U	Proud to be part of @ element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager
Document S/N:	Test Dates:	DUT Type:		Dage 45 of 09
1M2101040001-21.A3L	1/21/2021-3/2/2021	Portable Handset		Page 45 of 98
© 2021 PCTEST				REV 1.0

9.1.5 CDMA/EVDO BC1





Above time-averaged conducted Tx power is converted/calculated into time-averaged 1gSAR using Equation (1a) and plotted below to demonstrate that the time-averaged 1gSAR versus time does not exceed the FCC limit of 1.6 W/kg for 1gSAR:

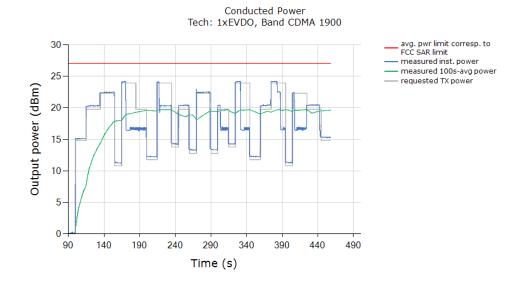


	(W/kg)
FCC 1gSAR limit	1.6
Max 100s-time averaged 1gSAR (green curve)	0.300
Validated: Max time averaged SAR (green curve) is within 1 dB device uncertain SAR at <i>Plimit</i> (last column in Table 8-2).	nty of measured

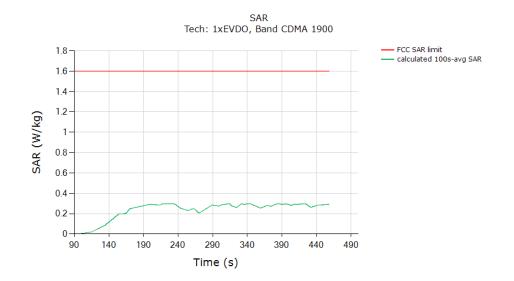
FCC ID: A3LSMA426U	Poctest* Proud to be part of @ element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager
Document S/N:	Test Dates:	DUT Type:		Dage 46 of 00
1M2101040001-21.A3L	1/21/2021-3/2/2021	Portable Handset		Page 46 of 98
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REV 1.0 04/06/2020

Test result for test sequence 2:



Above time-averaged conducted Tx power is converted/calculated into time-averaged 1gSAR using Equation (1a) and plotted below to demonstrate that the time-averaged 1gSAR versus time does not exceed the FCC limit of 1.6 W/kg for 1gSAR:

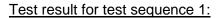


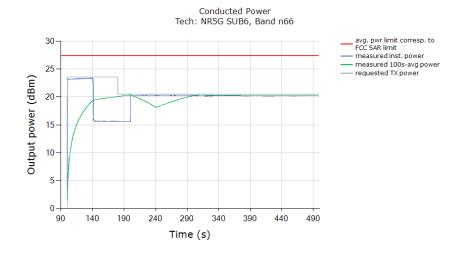
	(W/kg)
FCC 1gSAR limit	1.6
Max 100s-time averaged 1gSAR (green curve)	0.298
Validated: Max time averaged SAR (green curve) is within 1 dB device uncertain SAR at <i>Plimit</i> (last column in Table 8-2).	nty of measured

FCC ID: A3LSMA426U	PCTEST* Proud to be part of @ element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager
Document S/N:	Test Dates:	DUT Type:		Dage 47 of 00
1M2101040001-21.A3L	1/21/2021-3/2/2021	Portable Handset		Page 47 of 98
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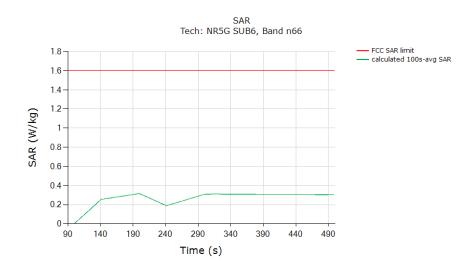
REV 1.0 04/06/2020

9.1.6 NR n66





Above time-averaged conducted Tx power is converted/calculated into time-averaged 1gSAR using Equation (1a) and plotted below to demonstrate that the time-averaged 1gSAR versus time does not exceed the FCC limit of 1.6 W/kg for 1gSAR:

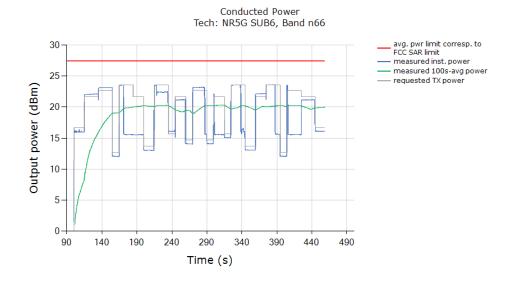


	(W/kg)	
FCC 1gSAR limit	1.6	
Max 100s-time averaged 1gSAR (green curve)	0.315	
Validated: Max time averaged SAR (green curve) is within 1dB device uncertainty of 75% (with 3dB <i>Reserve_power_margin</i> setting) of the measured SAR at <i>Plimit</i> (last column in Table 8-2).		

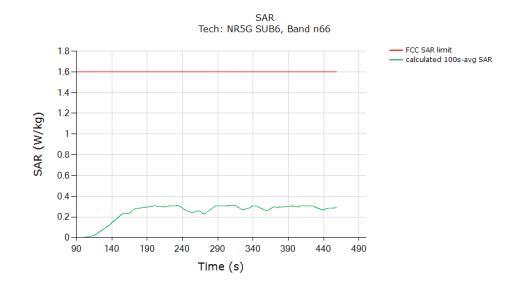
FCC ID: A3LSMA426U		PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager
Document S/N:	Test Dates:	DUT Type:		Daga 49 of 09
1M2101040001-21.A3L	1/21/2021-3/2/2021	Portable Handset		Page 48 of 98
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REV 1.0 04/06/2020

Test result for test sequence 2:



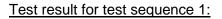
Above time-averaged conducted Tx power is converted/calculated into time-averaged 1gSAR using Equation (1a) and plotted below to demonstrate that the time-averaged 1gSAR versus time does not exceed the FCC limit of 1.6 W/kg for 1gSAR:

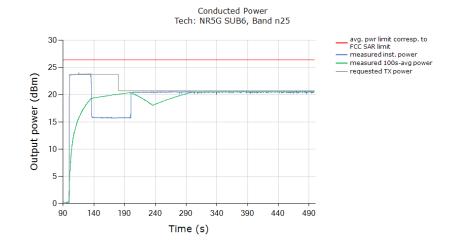


	(W/kg)	
FCC 1gSAR limit	1.6	
Max 100s-time averaged 1gSAR (green curve)	0.313	
Validated: Max time averaged SAR (green curve) is within 1dB device uncertainty of 75% (with 3dB <i>Reserve_power_margin</i> setting) of the measured SAR at <i>Plimit</i> (last column in Table 8-2).		

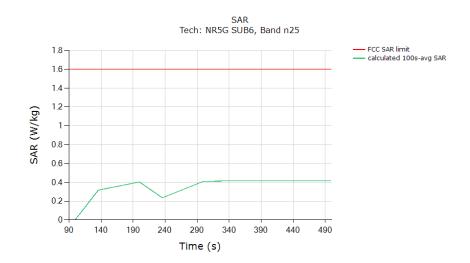
FCC ID: A3LSMA426U	Proud to be part of @ element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager
Document S/N:	Test Dates:	DUT Type:		Dage 40 of 00
1M2101040001-21.A3L	1/21/2021-3/2/2021	Portable Handset		Page 49 of 98
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REV 1.0 04/06/2020





Above time-averaged conducted Tx power is converted/calculated into time-averaged 1gSAR using Equation (1a) and plotted below to demonstrate that the time-averaged 1gSAR versus time does not exceed the FCC limit of 1.6 W/kg for 1gSAR:

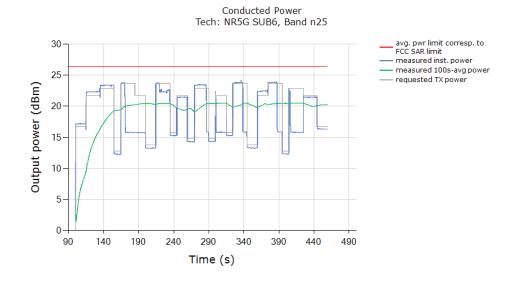


	(W/kg)	
FCC 1gSAR limit	1.6	
Max 100s-time averaged 1gSAR (green curve)	0.415	
Validated: Max time averaged SAR (green curve) is within 1dB device uncertainty of 75% (with 3dB <i>Reserve_power_margin</i> setting) of the measured SAR at <i>Plimit</i> (last column in Table 8-2).		

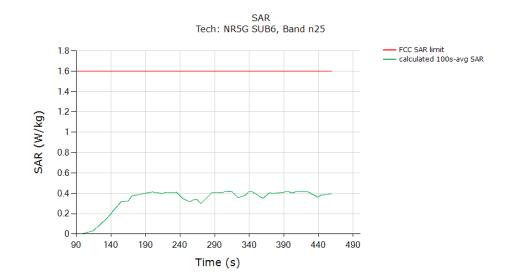
FCC ID: A3LSMA426U	Pour lo be part of @ element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager
Document S/N:	Test Dates:	DUT Type:		Daga 50 of 00
1M2101040001-21.A3L	1/21/2021-3/2/2021	Portable Handset		Page 50 of 98
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REV 1.0 04/06/2020

Test result for test sequence 2:



Above time-averaged conducted Tx power is converted/calculated into time-averaged 1gSAR using Equation (1a) and plotted below to demonstrate that the time-averaged 1gSAR versus time does not exceed the FCC limit of 1.6 W/kg for 1gSAR:



	(W/kg)
FCC 1gSAR limit	1.6
Max 100s-time averaged 1gSAR (green curve)	0.419
Validated: Max time averaged SAR (green curve) is within 1dB device uncertain 3dB <i>Reserve_power_margin</i> setting) of the measured SAR at <i>Plimit</i> (last column	

FCC ID: A3LSMA426U	Proud to be part of @ element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager
Document S/N:	Test Dates:	DUT Type:		Daga 51 of 00
1M2101040001-21.A3L	1/21/2021-3/2/2021	Portable Handset		Page 51 of 98
© 2021 PCTEST				REV 1.0

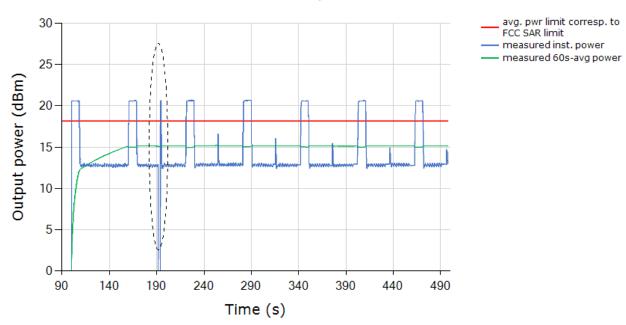
REV 1.0 04/06/2020

9.2 Call Drop Test Case

This test was measured LTE Band 48, SUB4 Antenna, DSI=1, and with callbox requesting maximum power. The call drop was manually performed when the DUT is transmitting at $P_{reserve}$ level as shown in the plot below (dotted black region). The measurement setup is shown in Figure 6-1. The detailed test procedure is described in Section 4.3.2.

Call drop test result:

Plot 1: Measured Tx power (dBm) versus time shows that the transmitting power kept the same $P_{reserve}$ level of LTE Band 48 after the call was re-established:



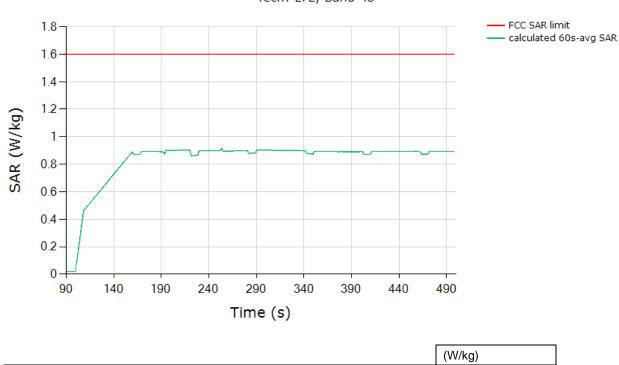
Conducted Power Tech: LTE, Band 48

Plot Notes: The power level after the change in call kept the same *P*_{reserve} level of LTE Band 48. The conducted power plot shows expected Tx transition.

FCC ID: A3LSMA426U	Pour lo be part of @ element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager
Document S/N:	Test Dates:	DUT Type:		Dage 52 of 02
1M2101040001-21.A3L	1/21/2021-3/2/2021	Portable Handset		Page 52 of 98
© 2021 PCTEST				REV 1.0

04/06/2020

Plot 2: Above time-averaged conducted Tx power is converted/calculated into time-averaged 1gSAR using Equation (1a) and plotted below to demonstrate that the time-averaged 1gSAR versus time does not exceed the FCC limit of 1.6 W/kg for 1gSAR:



	SA	R	
Tech:	LTE,	Band	48

	(W/kg)
FCC 1gSAR limit	1.6
Max 60s-time averaged 1gSAR (green curve)	0.916
Validated	

The test result validated the continuity of power limiting in call change scenario.

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Document S/N:	Test Dates:	DUT Type:		Dage 52 of 08
1M2101040001-21.A3L	1/21/2021-3/2/2021	Portable Handset		Page 53 of 98
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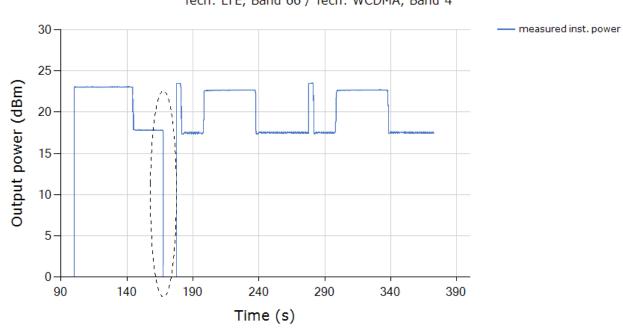
REV 1.0 04/06/2020

9.3 Change in Technology/Band Test Case

This test was conducted with callbox requesting maximum power, and with a technology switch from LTE Band 66, MAIN1 Antenna, DSI = 2 to WCDMA Band 4, MAIN1 Antenna, DSI = 2. Following procedure detailed in Section 4.3.3, and using the measurement setup shown in Figure 6-1, the technology/band switch was performed when the DUT is transmitting at $P_{reserve}$ level as shown in the plot below (dotted black region).

Test result for change in technology/band:

Plot 1: Measured Tx power (dBm) versus time shows that the transmitting power changed from LTE Band 66, MAIN1 Antenna, DSI =2 $P_{reserve}$ level to WCDMA Band 4, MAIN1 Antenna, DSI = 2 $P_{reserve}$ level (within 1 dB device uncertainty):



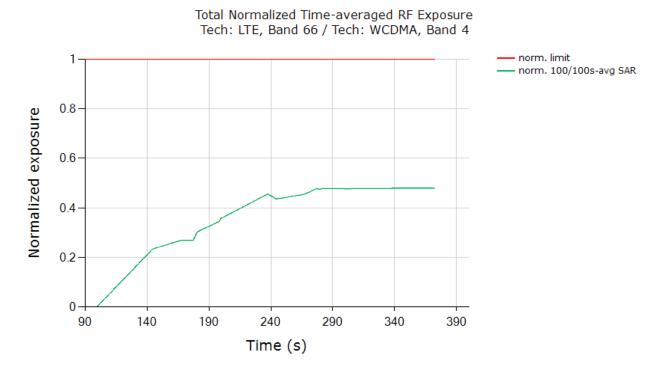
Conducted Power Tech: LTE, Band 66 / Tech: WCDMA, Band 4

Note: As per the manufacturer, *Reserve_power_margin* = 3 dB. Based on Table 8-1, EFS *Plimit* = 21.0dBm for LTE Band 66 (DSI=2), and EFS *Plimit* = 20.0dBm for WCDMA Band 4 (DSI=2), it can be seen from above plot that the difference in *Preserve* (= *Plimit* – 3dB *Reserve_power_margin*) power level corresponds to the expected difference in *Plimit* levels of 1.0 dB (within 1dB of sub6 radio design related uncertainty). Therefore, the conducted power plot shows expected transition in Tx power.

FCC ID: A3LSMA426U	PCTEST* Proud to be part of @element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager
Document S/N:	Test Dates:	DUT Type:		Page 54 of 98
1M2101040001-21.A3L	1/21/2021-3/2/2021	Portable Handset		Fage 54 01 96
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REV 1.0 04/06/2020

Plot 2: All the time-averaged conducted Tx power measurement results were converted into time-averaged normalized SAR values using Equation (6a), (6b) and (6c), and plotted below to demonstrate that the time-averaged normalized SAR versus time does not exceed the normalized FCC limit of 1.0:



	(W/kg)
FCC normalized SAR limit	1.0
Max 100s-time averaged normalized SAR (green curve)	0.480
Validated	

The test result validated the continuity of power limiting in technology/band switch scenario.

FCC ID: A3LSMA426U	Proud to be part of @ element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager
Document S/N:	Test Dates:	DUT Type:		Dage 55 of 09
1M2101040001-21.A3L	1/21/2021-3/2/2021	Portable Handset		Page 55 of 98
© 2021 PCTEST				REV 1.0

REV 1.0 04/06/2020

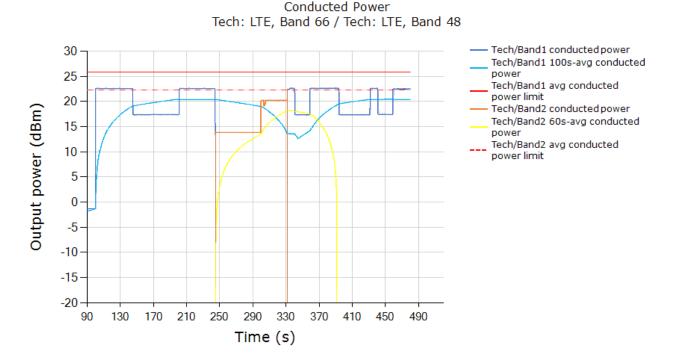
9.4 Change in Time window / antenna switch test results

This test was conducted with callbox requesting maximum power, and with timewindow/antenna switch between LTE Band 66, MAIN1 Antenna, DSI = 2 (100s window) and LTE Band 48, SUB4 Antenna, DSI = 2 (60s window). Following procedure detailed in Section 4.3.6, and using the measurement setup shown in Figure 6-1(b), the time-window switch via tech/band/antenna switch was performed when the EUT is transmitting at $P_{reserve}$ level.

9.4.1 Test case 1: transition from LTE B66 to LTE B48 (i.e., 100s to 60s), then back to LTE B66

Test result for change in time-window (from 100s to 60s to 100s):

Plot 1: Measured Tx power (dBm) versus time shows that the transmitting power changed when LTE Band 66 switches to LTE Band 48 (~250 seconds timestamp) and switches back to LTE Band 66 (~330s seconds timestamp):

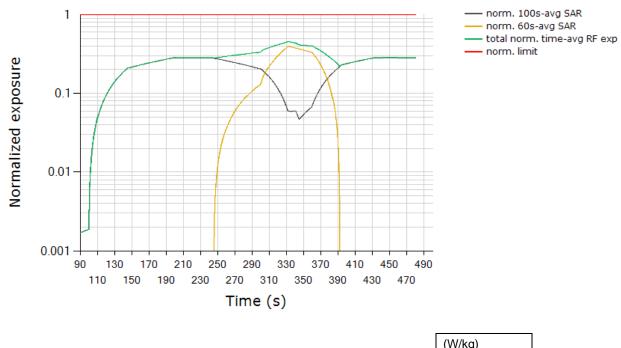


Plot Notes: As per the manufacturer, *Reserve_power_margin* = 3dB. Based on Table 8-1, EFS P_{limit} = 21.0dBm for LTE Band 66 DSI = 2 (100s window), and EFS P_{limit} = 18.5 dBm (P_{max} = 20.0dBm) for LTE Band 48 DSI = 2 (60s window). The conducted power plot shows expected transitions in Tx power at ~250 seconds (100s-to-60s transition) and at ~330 seconds (60s-to-100s transition) in order to maintain total time-averaged RF exposure compliance across time windows, as show in next plot.

FCC ID: A3LSMA426U	PCTEST* Proud to be part of @ element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager	
Document S/N:	Test Dates:	DUT Type:		Daga 56 of 00	
1M2101040001-21.A3L	1/21/2021-3/2/2021	Portable Handset		Page 56 of 98	
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REV 1.0 04/06/2020

Plot 2: All the conducted Tx power measurement results were converted into time-averaged normalized SAR values using Equation (7a), (7b) and (7c), and plotted below to demonstrate that the time-averaged normalized SAR versus time does not exceed the FCC limit of 1 unit. Equation (7a) is used to convert the Tx power of device to obtain 100s-averaged normalized SAR in LTE Band 66 as shown in black curve. Similarly, equation (7b) is used to obtain 60s-averaged normalized SAR in LTE Band 48 as shown in orange curve. Equation (7c) is used to obtain total time-averaged normalized SAR as shown in green curve (i.e., sum of black and orange curves).



Total Normalized Time-averaged RF Exposure Tech: LTE, Band 66 / Tech: LTE, Band 48

	(W/kg)
FCC normalized total exposure limit	1.0
Max time averaged normalized SAR (green curve)	0.456
Validated	

Plot Notes: Maximum power is requested by callbox for the entire duration of the test, with tech/band switches from 100s-to-60s window at ~250s time stamp, and from 60s-to-100s window at ~330s time stamp. Smart Transmit controls the Tx power during these time-window switches to ensure total time-averaged RF exposure, i.e., sum of black and orange curves given by equation (7c), is always compliant. In time-window switch test, at all times the total time-averaged normalized RF exposure (green curve) should not exceed normalized SAR_design_target + 1dB device uncertainty. In this test, with a maximum normalized SAR of 0.456 being ≤ 0.79 (= 1.0/1.6 + 1dB device uncertainty), the above test result validated the continuity of power limiting in time-window switch scenario.

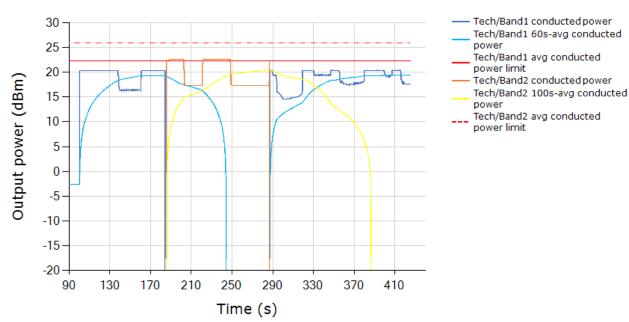
FCC ID: A3LSMA426U	PCTEST* Proud to be part of @ element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager	
Document S/N:	Test Dates:	DUT Type:		Dogo 57 of 00	
1M2101040001-21.A3L	1/21/2021-3/2/2021	Portable Handset		Page 57 of 98	
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REV 1.0 04/06/2020

9.4.2 Test case 2: transition from LTE B48 to LTE B66 (i.e., 60s to 100s), then back to LTE B48

Test result for change in time-window (from 60s to 100s to 60s):

Plot 1: Measured Tx power (dBm) versus time shows that the transmitting power changed when LTE Band 48 switches to LTE Band 66 (~185 seconds timestamp) and switches back to LTE Band 48 (~285 seconds timestamp):



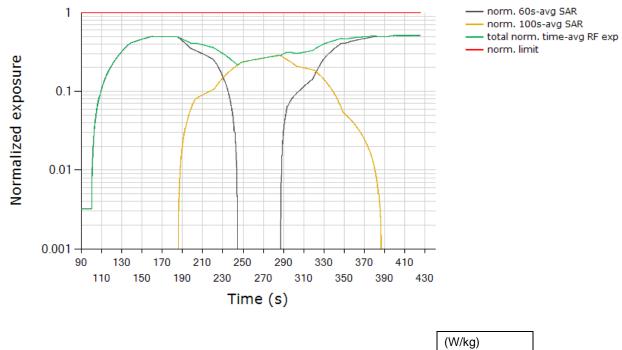
Conducted Power Tech: LTE, Band 48 / Tech: LTE, Band 66

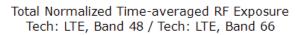
Note: As per the manufacturer, *Reserve_power_margin* = 3dB. Based on Table 8-1, EFS *Plimit* = 18.5dBm (*Pmax* = 20.0dBm) for LTE Band 48 DSI = 2 (60s window), and EFS *Plimit* = 21.0dBm for LTE Band 66 DSI = 2 (100s window).The conducted power plot shows expected transitions in Tx power at ~185s (60s-to-100s transition) and at ~285s (100s-to-60s transition) in order to maintain total time-averaged RF exposure compliance across time windows, as show in next plot.

FCC ID: A3LSMA426U	PCTEST [*] Proud to be part of ® element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager	
Document S/N:	Test Dates:	DUT Type:		Daga 59 of 09	
1M2101040001-21.A3L	1/21/2021-3/2/2021	Portable Handset		Page 58 of 98	
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REV 1.0 04/06/2020

Plot 2: All the conducted Tx power measurement results were converted into time-averaged normalized SAR values using Equation (7a), (7b) and (7c), and plotted below to demonstrate that the time-averaged normalized SAR versus time does not exceed the FCC limit of 1 unit. Equation (7a) is used to convert the Tx power of device to obtain 60s-averaged normalized SAR in LTE Band 48 as shown in black curve. Similarly, equation (7b) is used to obtain 100s-averaged normalized SAR in LTE Band 66 as shown in orange curve. Equation (7c) is used to obtain total time-averaged normalized SAR as shown in green curve (i.e., sum of black and orange curves).





	(W/kg)
FCC normalized total exposure limit	1.0
Max time averaged normalized SAR (green curve)	0.513
Validated	

Plot Notes: Maximum power is requested by callbox for the entire duration of the test, with tech/band switches from 60s-to-100s window at ~185 time stamp, and from 100s-to-60s window at ~285s time stamp. Smart Transmit controls the Tx power during these time-window switches to ensure total time-averaged RF exposure, i.e., sum of black and orange curves given by equation (7c), is always compliant. In time-window switch test, at all times the total time-averaged normalized RF exposure (green curve) should not exceed normalized SAR_design_target + 1dB device uncertainty. In this test, with a maximum normalized SAR of 0.513 being ≤ 0.79 (= 1.0/1.6 + 1dB device uncertainty), the above test result validated the continuity of power limiting in time-window switch scenario.

FCC ID: A3LSMA426U	PCTEST [®] Proud to be part of @ element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager	
Document S/N:	Test Dates:	DUT Type:		Page 59 of 98	
1M2101040001-21.A3L	1/21/2021-3/2/2021 Portable Handset			Fage 59 01 96	
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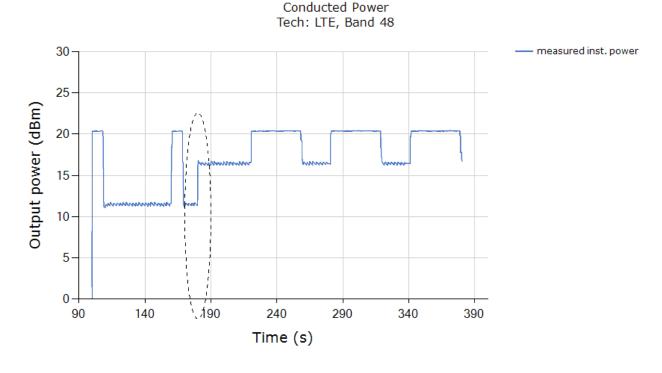
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9.5 DSI Switch Test Case

This test was conducted with callbox requesting maximum power, and with DSI switch from LTE Band 48 DSI = 1 (head) to DSI = 2 (hotspot). Following procedure detailed in Section 4.3.5 using the measurement setup shown in Figure 6-1, the DSI switch was performed when the DUT is transmitting at $P_{reserve}$ level as shown in the plot below (dotted black circle).

Test result for change in DSI:

Plot 1: Measured Tx power (dBm) versus time shows that the transmitting power changed when DSI = 1 switches to DSI = 2:

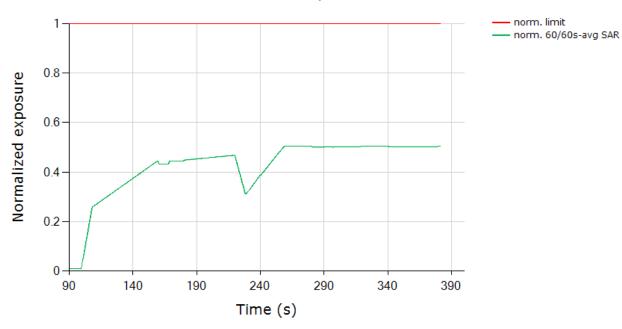


Note: As per the manufacturer, *Reserve_power_margin* = 3dB. Based on Table 8-1, EFS P_{limit} = 15.0 dBm for LTE Band 48 Head DSI = 1, and EFS P_{limit} = 18.5 dBm for DSI = 2.The difference in $P_{reserve}$ (= P_{limit} - 3dB Reserve_power_margin) level corresponds to the expected different in P_{limit} levels of 3.5 dB (within 1dB of sub6 radio design related uncertainty). Therefore, the conducted power plot shows expected transition in Tx power.

FCC ID: A3LSMA426U	PCTEST* Proud to be part of @ element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager	
Document S/N:	Test Dates:	DUT Type:		Daga 60 at 09	
1M2101040001-21.A3L	1/21/2021-3/2/2021 Portable Handset			Page 60 of 98	
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REV 1.0 04/06/2020

Plot 2: All the time-averaged conducted Tx power measurement results were converted into timeaveraged normalized SAR values using Equation (6a), (6b) and (6c), and plotted below to demonstrate that the time-averaged normalized SAR versus time does not exceed the FCC limit of 1 unit.



Total Normalized Time-averaged RF Exposure Tech: LTE, Band 48

	(W/kg)
FCC normalized total exposure limit	1.0
Max 60s-time averaged normalized SAR (green curve)	0.506
Validated	

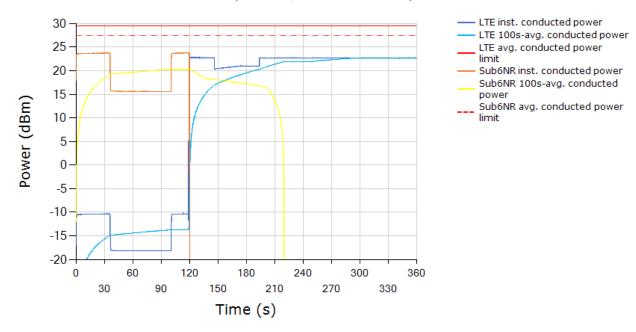
The test result validated the continuity of power limiting in DSI switch scenario.

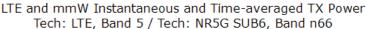
FCC ID: A3LSMA426U	PCTEST* Proud to be part of @element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager	
Document S/N:	Test Dates:	DUT Type:		Dage 61 of 09	
1M2101040001-21.A3L	1/21/2021-3/2/2021	Portable Handset		Page 61 of 98	
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REV 1.0 04/06/2020

9.6 Switch in SAR exposure test results

This test was conducted with callbox requesting maximum power, and with the EUT in LTE Band 5 + Sub6 NR Band n66 call. Following procedure detailed in Section 4.3.7 and Appendix F.2, and using the measurement setup shown in Figure 6-1(c) since LTE and Sub6 NR are sharing the same antenna port, the SAR exposure switch measurement is performed with the EUT in various SAR exposure scenarios, i.e., in SAR_{sub6NR} only scenario (t =0s ~120s), SAR_{su6NR} + SAR_{LTE} scenario (t =120s ~ 210s) and SAR_{LTE} only scenario (t > 210s).

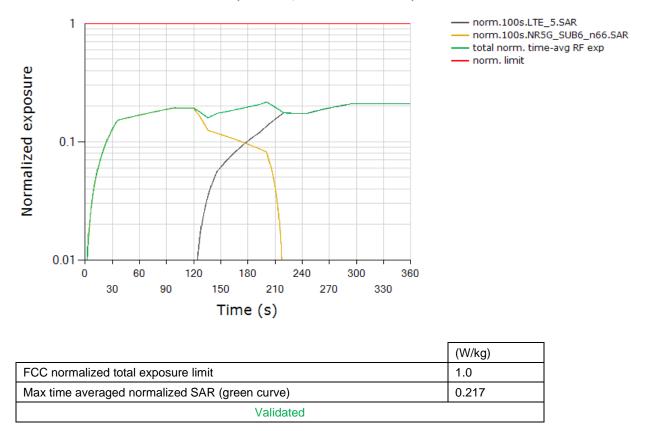




Plot Notes: All the conducted Tx power measurement results were converted into time-averaged normalized SAR values using Equation (7a), (7b) and (7c), and plotted below to demonstrate that the time-averaged normalized SAR versus time does not exceed the FCC limit of 1 unit. Equation (7a) is used to convert the LTE Tx power of device to obtain 100s-averaged normalized SAR in LTE Band 5 as shown in black curve. Similarly, equation (7b) is used to obtain 100s-averaged normalized SAR in Sub6 NR n66 as shown in orange curve. Equation (7c) is used to obtain total time-averaged normalized SAR as shown in green curve (i.e., sum of black and orange curves).

FCC ID: A3LSMA426U	PCTEST* Proud to be part of @ element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager	
Document S/N:	Test Dates:	DUT Type:		Dage 62 of 09	
1M2101040001-21.A3L	1/21/2021-3/2/2021	Portable Handset		Page 62 of 98	
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REV 1.0 04/06/2020



Total Normalized Time-averaged RF Exposure Tech: LTE, Band 5 / Tech: NR5G SUB6, Band n66

<u>Plot Notes:</u> Device starts predominantly in Sub6 NR SAR exposure scenario between 0s and 120s, and in LTE SAR + Sub6 NR SAR exposure scenario between 120s and 210s, and in predominantly in LTE SAR exposure scenario after t=210s. Here, Smart Transmit allocates a maximum of 75% of exposure margin (based on 3dB reserve margin setting) for Sub6 NR. This corresponds to a normalized 1gSAR exposure value = 75% * 0.427 W/kg measured SAR at Sub6 NR *Plimit* / 1.6W/kg limit = 0.200 ± 1dB device related uncertainty (see orange curve between 0s~120s). For predominantly LTE SAR exposure scenario, maximum normalized 1gSAR exposure should correspond to 100% exposure margin = 0.333 W/kg measured SAR at LTE *Plimit* / 1.6W/kg limit = 0.208 ± 1dB device related uncertainty (see black curve after t = 210s). Additionally, in SAR exposure switch test, at all times the total time-averaged normalized RF exposure (green curve) should not exceed normalized *SAR_design_target* + 1dB device uncertainty. In this test, with a maximum normalized SAR of 0.217 being ≤ 0.79 (= 1.0/1.6 + 1dB device uncertainty), the above test result validated the continuity of power limiting in SAR exposure switch scenario.

FCC ID: A3LSMA426U	Poctest* Proud to be part of @ element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager	
Document S/N:	Test Dates:	DUT Type:		Daga 62 of 09	
1M2101040001-21.A3L	1/21/2021-3/2/2021	Portable Handset		Page 63 of 98	
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REV 1.0 04/06/2020

10 SYSTEM VERIFICATION (FREQ < 6 GHZ)

10.1 **Tissue Verification**

	Measured Tissue Properties								
Calibrated for Tests Performed on:	Tissue Type	Tissue Temp During Calibration (°C)	Measured Frequency (MHz)	Measured Conductivity, σ (S/m)	Measured Dielectric Constant, ε	TARGET Conductivity, σ (S/m)	TARGET Dielectric Constant, ε	% dev σ	% dev ε
			1710	1.439	53.457	1.463	53.537	-1.64%	-0.15%
			1720	1.446	53.422	1.469	53.511	-1.57%	-0.17%
1/22/2021	1750 Body	21.5	1745	1.466	53.345	1.485	53.445	-1.28%	-0.19%
1/22/2021	1750 000y	21.5	1750	1.47	53.337	1.488	53.432	-1.21%	-0.18%
			1770	1.486	53.33	1.501	53.379	-1.00%	-0.09%
			1790	1.499	53.339	1.514	53.326	-0.99%	0.02%
			1710	1.449	54.196	1.463	53.537	-0.96%	1.23%
			1720	1.457	54.176	1.469	53.511	-0.82%	1.24%
1/29/2021	1750 Body	20.2	1745	1.479	54.129	1.485	53.445	-0.40%	1.28%
1/25/2021	1750 000y	20.2	1750	1.484	54.121	1.488	53.432	-0.27%	1.29%
			1770	1.501	54.101	1.501	53.379	0.00%	1.35%
			1790	1.516	54.088	1.514	53.326	0.13%	1.43%
			1710	1.445	53.771	1.463	53.537	-1.23%	0.44%
			1720	1.452	53.742	1.469	53.511	-1.16%	0.43%
2/10/2021	1750 Body	20.1	1745	1.475	53.669	1.485	53.445	-0.67%	0.42%
2/ 10/ 2021	1750 2004		1750	1.48	53.661	1.488	53.432	-0.54%	0.43%
			1770	1.497	53.632	1.501	53.379	-0.27%	0.47%
			1790	1.511	53.613		53.326	-0.20%	0.54%
		20.0	1850	1.514	55.677	1.52	53.3	-0.39%	4.46%
			1860	1.522	55.659	1.52	53.3	0.13%	4.43%
2/2/2021	1900 Body		1880	1.538	55.643	1.52	53.3	1.18%	4.40%
2/2/2021	1900 Dody		1900	1.553	55.634	1.52	53.3	2.17%	4.38%
			1905	1.557	55.632	1.52	53.3	2.43%	4.38%
			1910	1.56	55.627	1.52	53.3	2.63%	4.37%
			1850	1.537	52.337	1.52	53.3	1.12%	-1.81%
			1860	1.545	52.315	1.52	53.3	1.64%	-1.85%
2/5/2021	1900 Body	20.3	1880	1.562	52.29	1.52	53.3	2.76%	-1.89%
2/ 3/ 2021	1900 2003	20.0	1900	1.577	52.27	1.52	53.3	3.75%	-1.93%
			1905	1.58	52.266	1.52	53.3	3.95%	-1.94%
			1910	1.583	52.258		53.3	4.14%	-1.95%
			1850	1.546	52.008		53.3	1.71%	-2.42%
			1860	1.553	51.993	1.52	53.3	2.17%	-2.45%
2/15/2021	1900 Body	22.4	1880	1.567	51.975	1.52	53.3	3.09%	-2.49%
2, 20, 2022	2000 2004		1900	1.581	51.963	1.52	53.3	4.01%	-2.51%
			1905	1.584	51.958		53.3	4.21%	-2.52%
			1910	1.587	51.951	1.52	53.3	4.41%	-2.53%
			3600	2.971	38.089	3.015	37.814	-1.46%	0.73%
			3650	3.015	37.982	3.066	37.757	-1.66%	0.60%
2/25/2021	3700 Head	21.0	3690	3.057	37.939	3.107	37.711	-1.61%	0.60%
2/23/2021	5700 Hedu	21.0	3700	3.069	37.912	3.117	37.7	-1.54%	0.56%
			3750	3.118	37.813	3.169	37.643	-1.61%	0.45%
			3900	3.272	37.55	3.323	37.471	-1.53%	0.21%

Table 10-1

The above measured tissue parameters were used in the DASY software. The DASY software was used to perform interpolation to determine the dielectric parameters at the SAR test device frequencies (per KDB Publication 865664 D01v01r04 and IEEE 1528-2013 6.6.1.2). The tissue parameters listed in the SAR test plots may slightly differ from the table above due to significant digit rounding in the software.

FCC ID: A3LSMA426U		PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager
Document S/N:	Test Dates:	DUT Type:		Page 64 of 98
1M2101040001-21.A3L	1/21/2021-3/2/2021	Portable Handset		Fage 04 01 90
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.0 04/06/2020

10.2 Test System Verification

Prior to SAR assessment, the system is verified to $\pm 10\%$ of the SAR measurement on the reference dipole at the time of calibration by the calibration facility. Full system validation status and result summary can be found in Appendix C.

(System Verification Results – 1g											
	System Verification											
	TARGET & MEASURED											
SAR System #	Tissue Frequency (MHz)	Tissue Type	Date	Amb. Temp (°C)	Liquid Temp (°C)	Input Power (W)	Source SN	Probe SN	Measured SAR _{1g} (W/kg)	1 W Target SAR _{1g} (W/kg)	1 W Normalized SAR1g (W/kg)	Deviation _{1g} (%)
М	1750	BODY	1/22/2021	23.1	21.5	0.100	1148	7570	3.470	36.300	34.700	-4.41%
М	1750	BODY	1/29/2021	21.4	20.2	0.100	1148	7570	3.600	36.300	36.000	-0.83%
N	1750	BODY	2/10/2021	20.5	20.1	0.100	1148	7526	3.680	36.300	36.800	1.38%
М	1900	BODY	2/2/2021	21.2	20.0	0.100	5d148	7570	4.070	39.100	40.700	4.09%
М	1900	BODY	2/5/2021	22.6	20.3	0.100	5d148	7570	3.810	39.100	38.100	-2.56%
М	1900	BODY	2/15/2021	21.4	22.4	0.100	5d148	7570	3.930	39.100	39.300	0.51%
М	3700	HEAD	2/25/2021	23.1	21.0	0.100	1067	7570	6.550	67.200	65.500	-2.53%



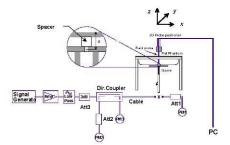


Figure 10-1 System Verification Setup Diagram



Figure 10-2 System Verification Setup Photo

FCC ID: A3LSMA426U	PCTEST* Proud to be part of @element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager
Document S/N:	Test Dates:	DUT Type:		Daga 65 of 00
1M2101040001-21.A3L	1/21/2021-3/2/2021	Portable Handset		Page 65 of 98
© 2021 PCTEST				REV 1.0

REV 1.0 04/06/2020

11 SAR TEST RESULTS (FREQ < 6 GHZ)

Time-varying Tx Power Case 11.1

Following Section 4.4 procedure, time-averaged SAR measurements are conducted using a SAR probe at peak location of area scan over 500 seconds. cDASY6 system verification for SAR measurement is provided in Section 10, and the associated SPEAG certificates are attached in Appendix G.

SAR probe integration times depend on the communication signal being tested as defined in the probe calibration parameters.

Since the sampling rate used by cDASY6 for pointSAR measurements is not in user control, the number of points in 100s interval is determined from the scan duration setting in cDASY6 timeaverage pointSAR measurement by (100s cDASY6_scan_duration * total number of pointSAR values recorded). Running average is performed over these number of points in excel spreadsheet to obtain 100s averaged point SAR.

Following Section 4.4, for each of selected technology/band (listed in Table 8-2):

- 7. With Reserve_power_margin set to 0 dB, area scan is performed at Plimit, and time-averaged pointSAR measurements are conducted to determine the pointSAR at P_{limit} at peak location, denoted as *point*SAR_{Plimit}.
- 8. With Reserve power margin set to actual (intended) value, two more time-averaged pointSAR measurements are performed at the same peak location for test sequences 1 and 2.

To demonstrate compliance, all the pointSAR measurement results were converted into 1gSAR or 10gSAR values by using Equation (3a), rewritten below:

$$1g_{or}_{10gSAR(t)} = \frac{pointSAR(t)}{pointSAR_{P_{limit}}} * 1g_{or}_{10gSAR_{P_{limit}}}$$
(3a)

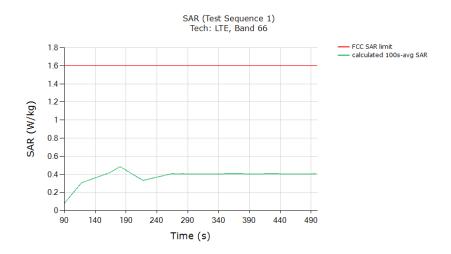
where, pointSAR(t), $pointSAR_{limit}$, and $1g_{or}_{10}gSAR_{limit}$ correspond to the measured instantaneous point SAR, measured point SAR at Plimit from above step 1 and 2, and measured 1gSAR or 10gSAR values at Plimit obtained from Part 1 report and listed in Table 8-2 of this report.

FCC ID: A3LSMA426U	Proved to be part of @ element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager
Document S/N:	Test Dates:	DUT Type: Portable Handset		Page 66 of 98
1M2101040001-21.A3L	1/21/2021-3/2/2021			Page 66 01 98
© 2021 PCTEST				REV 1.0

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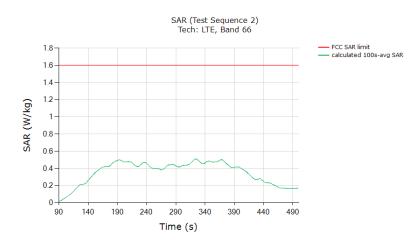
11.1.1 LTE Band 66

SAR test results for test sequence 1:



	(W/kg)
FCC 1gSAR limit	1.6
Max 100s-time averaged point 1gSAR (green curve)	0.484
Validated: Max time averaged SAR (green curve) is within 1 dB device uncertain SAR at <i>P</i> _{limit} (last column in Table 8-2).	nty of measured

SAR test results for test sequence 2:



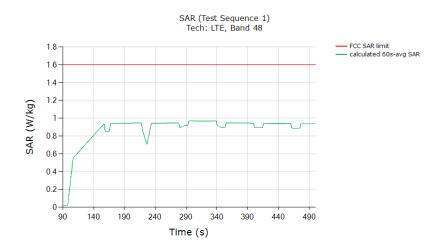
	(W/kg)
FCC 1gSAR limit	1.6
Max 100s-time averaged 1gSAR (green curve)	0.509
Validated: Max time averaged SAR (green curve) is within 1 dB device uncertain SAR at <i>P</i> _{limit} (last column in Table 8-2).	ty of measured

FCC ID: A3LSMA426U	Proud to be part of @ element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager
Document S/N:	Test Dates:	DUT Type:		Daga 67 af 00
1M2101040001-21.A3L	1/21/2021-3/2/2021	Portable Handset		Page 67 of 98
© 2021 PCTEST				REV 1.0

REV 1.0 04/06/2020

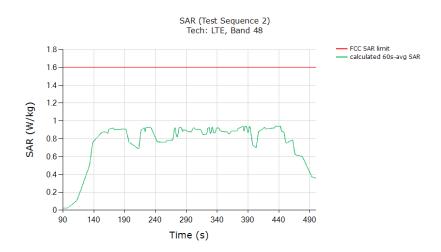
11.1.2 LTE Band 48

SAR test results for test sequence 1:



	(W/kg)
FCC 1gSAR limit	1.6
Max 60s-time averaged point 1gSAR (green curve)	0.970
Validated: Max time averaged SAR (green curve) is within 1 dB device uncertain SAR at <i>P</i> _{limit} (last column in Table 8-2).	nty of measured

SAR test results for test sequence 2:



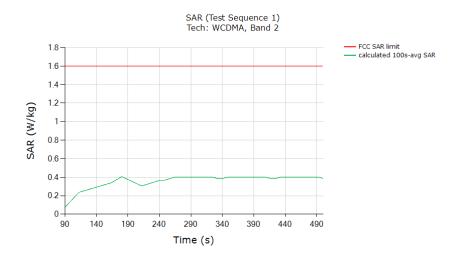
	(W/kg)
FCC 1gSAR limit	1.6
Max 60s-time averaged 1gSAR (green curve)	0.941
Validated: Max time averaged SAR (green curve) is within 1 dB device uncertain SAR at <i>P</i> _{limit} (last column in Table 8-2).	nty of measured

	FCC ID: A3LSMA426U	Proud to be part of @ element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager
	Document S/N:	Test Dates:	DUT Type:		Dage CR of OR
	1M2101040001-21.A3L	1/21/2021-3/2/2021	Portable Handset		Page 68 of 98
0	2021 PCTEST				REV 1.0

REV 1.0 04/06/2020

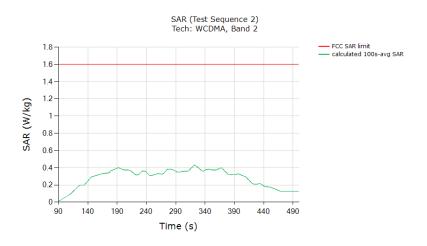
11.1.1 WCDMA B2

SAR test results for test sequence 1:



	(W/kg)
FCC 1gSAR limit	1.6
Max 100s-time averaged point 1gSAR (green curve)	0.404
Validated: Max time averaged SAR (green curve) is within 1 dB device uncertain SAR at <i>Plimit</i> (last column in Table 8-2).	nty of measured

SAR test results for test sequence 2:



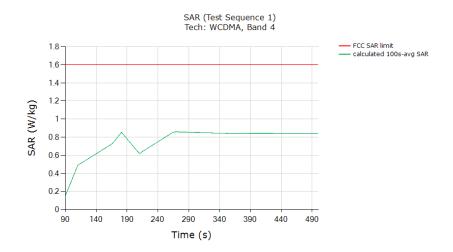
	(W/kg)
FCC 1gSAR limit	1.6
Max 100s-time averaged 1gSAR (green curve)	0.431
Validated: Max time averaged SAR (green curve) is within 1 dB device uncertain SAR at <i>P</i> _{limit} (last column in Table 8-2).	nty of measured

	FCC ID: A3LSMA426U	PCTEST*	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager
	Document S/N:	Test Dates:	DUT Type:		
	1M2101040001-21.A3L	1/21/2021-3/2/2021	Portable Handset		Page 69 of 98
0	2021 PCTEST				REV 1.0

REV 1.0 04/06/2020

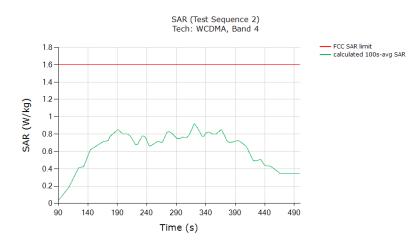
11.1.2 WCDMA B4

SAR test results for test sequence 1:



	(W/kg)		
FCC 1gSAR limit	1.6		
Max 100s-time averaged point 1gSAR (green curve)	0.858		
Validated: Max time averaged SAR (green curve) is within 1 dB device uncertainty of r SAR at <i>P</i> _{limit} (last column in Table 8-2).			

SAR test results for test sequence 2:



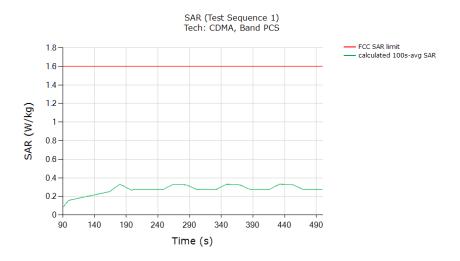
	(W/kg)	
FCC 1gSAR limit	1.6	
Max 100s-time averaged 1gSAR (green curve) 0.918		
/alidated: Max time averaged SAR (green curve) is within 1 dB device uncertainty of measured SAR at <i>P_{limit}</i> (last column in Table 8-2).		

	FCC ID: A3LSMA426U	PCTEST*	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager
	Document S/N:	Test Dates:	DUT Type:		Dage 70 of 09
	1M2101040001-21.A3L	1/21/2021-3/2/2021	Portable Handset		Page 70 of 98
© 2021 PCTEST				REV 1.0	

REV 1.0 04/06/2020

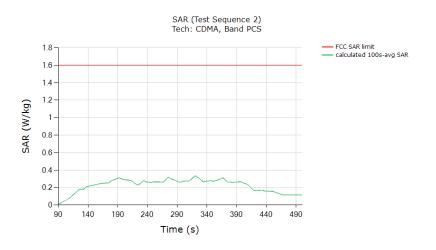
11.1.3 **CDMA/EVDO BC1**

SAR test results for test sequence 1:



	(W/kg)	
FCC 1gSAR limit	1.6	
Max 100s-time averaged point 1gSAR (green curve)	0.331	
Validated: Max time averaged SAR (green curve) is within 1 dB device uncertainty of measured SAR at <i>P</i> _{limit} (last column in Table 8-2).		

SAR test results for test sequence 2:



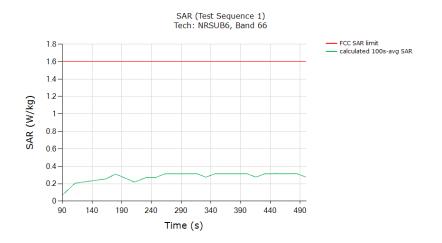
	(W/kg)	
FCC 1gSAR limit	1.6	
Max 100s-time averaged 1gSAR (green curve)	0.332	
/alidated: Max time averaged SAR (green curve) is within 1 dB device uncertainty of measured SAR at <i>Plimit</i> (last column in Table 8-2).		

	FCC ID: A3LSMA426U	PCTEST* Proud to be part of @ element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager
	Document S/N:	Test Dates:	DUT Type:		Dogo 71 of 08
	1M2101040001-21.A3L	1/21/2021-3/2/2021	Portable Handset		Page 71 of 98
© 2021 PCTEST					REV 1.0

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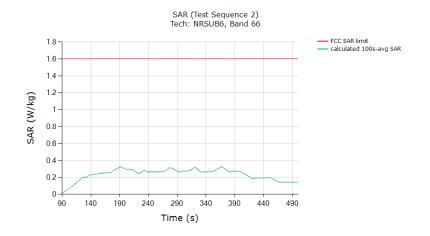
11.1.4 NR n66

SAR test results for test sequence 1:



	(W/kg)
FCC 1gSAR limit	1.6
Max 100s-time averaged point 1gSAR (green curve)	0.316
alidated: Max time averaged SAR (green curve) is within 1dB device uncertainty of 75% (with dB <i>Reserve_power_margin</i> setting) of the measured SAR at <i>Plimit</i> (last column in Table 8-2).	

SAR test results for test sequence 2:



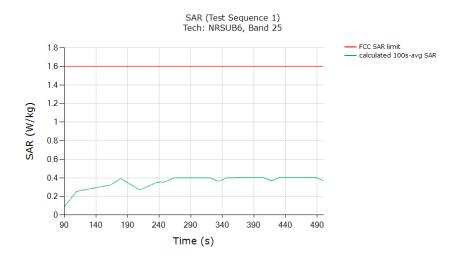
	(W/kg)	
FCC 1gSAR limit	1.6	
Max 100s-time averaged 1gSAR (green curve)	0.325	
Validated: Max time averaged SAR (green curve) is within 1dB device uncertainty of 75% (with 3dB Reserve_power_margin setting) of the measured SAR at <i>Plimit</i> (last column in Table 8-2).		

FCC ID: A3LSMA426U	Poctest* Proud to be part of @ element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager
Document S/N:	Test Dates:	DUT Type:		Daga 72 of 00
1M2101040001-21.A3L	1/21/2021-3/2/2021	Portable Handset		Page 72 of 98
© 2021 PCTEST				REV 1.0

REV 1.0 04/06/2020

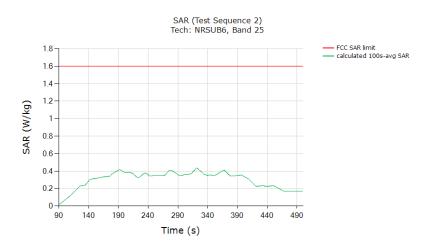
11.1.5 **NR n25**

SAR test results for test sequence 1:



	(W/kg)		
FCC 1gSAR limit	1.6		
Max 100s-time averaged point 1gSAR (green curve)	0.405		
Validated: Max time averaged SAR (green curve) is within 1dB device uncertainty of 75% (with 3dB <i>Reserve_power_margin</i> setting) of the measured SAR at <i>Plimit</i> (last column in Table 8-2).			

SAR test results for test sequence 2:



	(W/kg)		
FCC 1gSAR limit	1.6		
Max 100s-time averaged 1gSAR (green curve)	0.435		
Validated: Max time averaged SAR (green curve) is within 1dB device uncertainty of 75% (with 3dB <i>Reserve_power_margin</i> setting) of the measured SAR at <i>Plimit</i> (last column in Table 8-2).			

FCC ID: A3LSMA426U	Proud to be part of @element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager
Document S/N:	Test Dates:	DUT Type:		Dage 72 of 09
1M2101040001-21.A3L	1/21/2021-3/2/2021	Portable Handset		Page 73 of 98
© 2021 PCTEST				REV 1.0

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12 **TEST CONFIGURATIONS (FREQ > 6 GHZ)**

12.1 LTE + mmW NR transmission

Based on the selection criteria described in Section 4.2, the selections for LTE and mmW NR validation test are listed in Table 12-1. The radio configurations used in this test are listed in Table 12-2.

Table 12-1
Selections for LTE + mmW NR validation measurements

Transmission Scenario	Test	Technology and Band	mmWave Beam
Time-varying Tx power test	1. Cond. & Rad. Power meas.	LTE Band 2 and n261	Beam ID 15
Time-varying TX power test	2. PD meas.	LTE Band 2 and n260	Beam ID 30
	1. Cond. & Rad. Power meas.	LTE Band 2 and n261	Beam ID 15
Switch in SAR vs. PD		LTE Band 2 and n260	Beam ID 30
	1 Cand 8 Dad Davis man	LTE Band 2 and n261	Beam ID 15 to Beam ID 1
Beam switch test	1. Cond. & Rad. Power meas.	LTE Band 2 and n260	Beam ID 30 to Beam ID 3

Table 12-2 Test configuration for LTE + mmW NR validation

Tech	Band	Antenna	DSI	Channel	Freq (MHz)	RB/RB Offset/Bandwidth (MHz)	Mode	UL Duty Cycle
LTE	2	MAIN1	2	18900	1880	1/0/20 MHz BW	QPSK	100%
mmW NR	n261	L	-	2071821	27559.32	66/0/100 MHz BW	CP-OFDM, QPSK	75.6%*
	n260	R	-	2254147	38498.88	66/0/100 MHz BW	CP-OFDM, QPSK	75.6%*

12.2 mmW NR radiated power test results

To demonstrate the compliance, the conducted Tx power of LTE Band 2 in DSI = 2 is converted to 1gSAR exposure by applying the corresponding worst-case 1g SAR value at Plimit as reported in Part 1 report and listed in Table 8-2 of this report.

Similarly, following Step 4 in Section 5.3.1, radiated Tx power of mmW Band n261 and n260 for the beams tested is converted by applying the corresponding measured worst-case 4cm²PD values, and listed in below Table 12-3. Qualcomm Smart Transmit feature operates based on time-averaged Tx power reported on a per symbol basis, which is independent of modulation, channel and bandwidth (RBs), therefore the worst-case 4cm²PD was conducted with the EUT in FTM mode, with CW modulation and 100% duty cycle. cDASY6 system verification for power density measurement is provided in Section 14, and the associated SPEAG certificates are attached in Appendix G.

Both the worst-case 1gSAR and 4cm²PD values used in this section are listed in Table 12-3. The measured EIRP at input.power.limit for the beams tested in this section are also listed in Table 12-3.

FCC ID: A3LSMA426U	PCTEST [*] Proud to be part of @ element	PART 2 RF EXPOSURE EVALUATION REPORT	Approved by: Quality Manager	
Document S/N:	Test Dates:	DUT Type:		Page 74 of 98
1M2101040001-21.A3L	1/21/2021-3/2/2021	Portable Handset		Fage 74 01 90
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Table 12-3Worst-case 1gSAR, 4cm² avg. PD and EIRP measured at input.power.limit for the selected
configurations

Tech	Band	Antenna	Beam ID	input.power.limit		ed psPD at ower.limit	Measured EIRP at
rech	Banu	Antenna	BeamD	(dBm)	4cm ² psPD (W/m ²)	Test Position	input.power.limit (dBm)
mmW NR	n261	L	15	2.2	4.96	right	14.47
	. 11201	L	1	7.5	4.51	right	12.18
mmW NR	R 30		30	3.9	4.62	left	14.31
	NR n260	R	3	7.5	5.66	left	10.60
Tech			SI Measured Plimit (dBr	•	red 1g SAR at Pli //kg) Test Pos		

		LTE	2	MAIN1	2	18.8	0.363	bottom
--	--	-----	---	-------	---	------	-------	--------

The 4cm² psPD distributions for the highest PD value per band, as listed in Table 12-3, are plotted below.

	FCC ID: A3LSMA426U	Proud to be part of @ element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager
	Document S/N:	Test Dates:	DUT Type:		Daga 75 of 00
	1M2101040001-21.A3L	1/21/2021-3/2/2021	Portable Handset		Page 75 of 98
0	2021 PCTEST				REV 1.

REV 1.0 04/06/2020

Figure 12-1 4cm² psPD distribution measured at *input.power.limit* of 2.2 dBm on the right edge for n261 beam 15

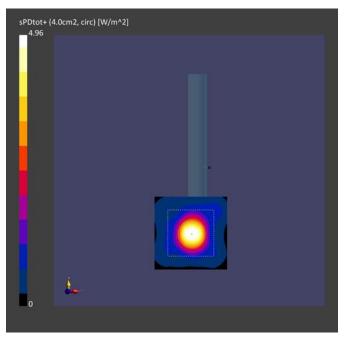
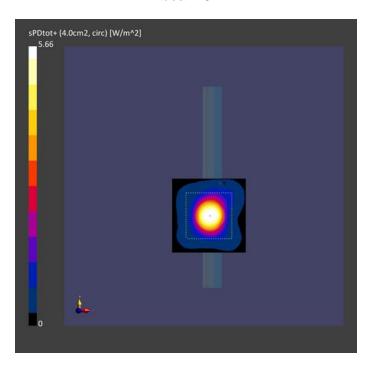


Figure 12-2 4cm² psPD distribution measured at input.power.limit of 7.5 dBm on the left edge for n260 beam 3



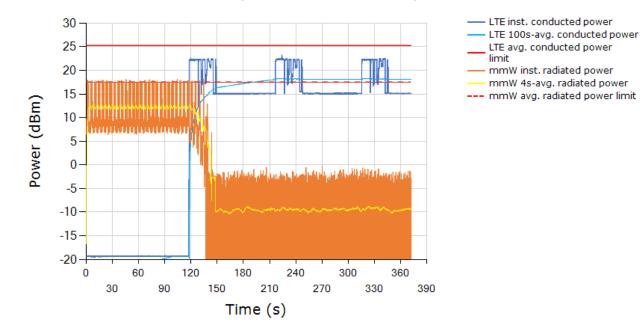
FCC ID: A3LSMA426U	PCTEST* Proud to be part of @ element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager
Document S/N:	Test Dates:	DUT Type:		Page 76 of 98
1M2101040001-21.A3L	1/21/2021-3/2/2021	Portable Handset		Page 76 01 98
© 2021 PCTEST				REV 1.0

13 RADIATED POWER TX CASES (FREQ > 6 GHZ)

13.1 Maximum Tx power test results for n261

This test was measured with LTE Band 2 and mmW Band n261 Beam ID 15, by following the detailed test procedure described in Section 5.3.1.

Instantaneous and 100s-averaged conducted LTE Tx power versus time, instantaneous and 4saveraged radiated mmW Tx power versus time, time-averaged conducted LTE Tx power limit and time-averaged radiated mmW Tx power limit:

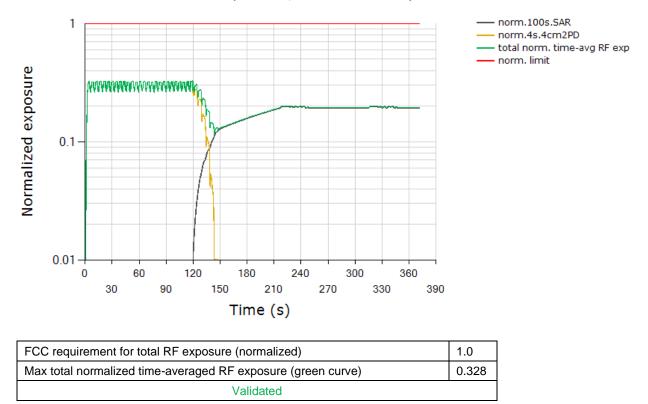


LTE and mmW Instantaneous and Time-averaged TX Power Tech: LTE, Band 2 / Tech: NR5G MMW, Band n261

Above time-averaged conducted Tx power for LTE Band 2 and radiated Tx power for mmW NR n261 beam 15 are converted into time-averaged 1gSAR and time-averaged 4cm²PD using Equation (2a) and (2b), which are divided by FCC 1gSAR limit of 1.6 W/kg and 4cm²PD limit of 10 W/m², respectively, to obtain normalized exposures versus time. Below plot shows (a) normalized time-averaged 1gSAR versus time, (b) normalized time-averaged 4cm2-avg.PD versus time, (c) sum of normalized time-averaged 1gSAR and normalized time-averaged 4cm²avg.PD:

FCC ID: A3LSMA426U	PCTEST* Proud to be part of @ element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager
Document S/N:	Test Dates:	DUT Type:		Daga 77 of 00
1M2101040001-21.A3L	1/21/2021-3/2/2021	Portable Handset		Page 77 of 98
© 2021 PCTEST		•		REV 1.0

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Total Normalized Time-averaged RF Exposure Tech: LTE, Band 2 / Tech: NR5G MMW, Band n261

Plot notes: As soon as 5G mmW NR call was established, LTE was placed in all-down bits immediately. Between 0s~120s, mmW exposure is the dominant contributor. Here, Smart Transmit feature allocates a maximum of 75% for mmW (based on the 3dB reserve setting in Part 1 report). From Table 12-3, this corresponds to a normalized 4cm²PD exposure value for Beam ID 15 of $(75\% * 4.96 \text{ W/m}^2)/(10 \text{ W/m}^2) = 37.2\% \pm 2.1 \text{dB}$ device related uncertainty (see green/orange curve between 0s~120s). At ~120s time mark, LTE is set to all-up bits, taking away margin from mmW exposure gradually. Towards the end of test, LTE is the dominant contributor towards RF exposure, i.e., corresponding normalized 1gSAR exposure value of $(100\% * 0.363 W/kg)/(1.6 W/kg) = 22.7\% \pm 1dB$ design related uncertainty (see black curve approaching this level towards end of the test).

As can be seen, the power limiting enforcement is effective and the total normalized timeaveraged RF exposure does not exceed 1.0. Therefore, Qualcomm[®] Smart Transmit time averaging feature is validated.

FCC ID: A3LSMA426U	Proud to be part of @ element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager
Document S/N:	Test Dates:	DUT Type:		Page 78 of 98
1M2101040001-21.A3L	1/21/2021-3/2/2021	Portable Handset		Fage 70 01 90
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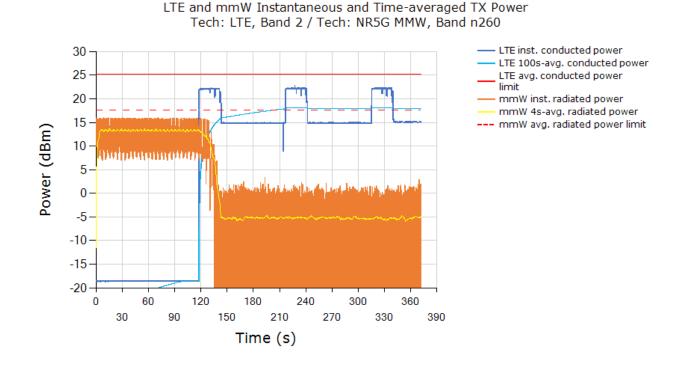
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04/06/2020

13.2 Maximum Tx power test results for n260

This test was measured with LTE Band 2 and mmW Band n260 Beam ID 30, by following the detailed test procedure described in Section 5.3.1.

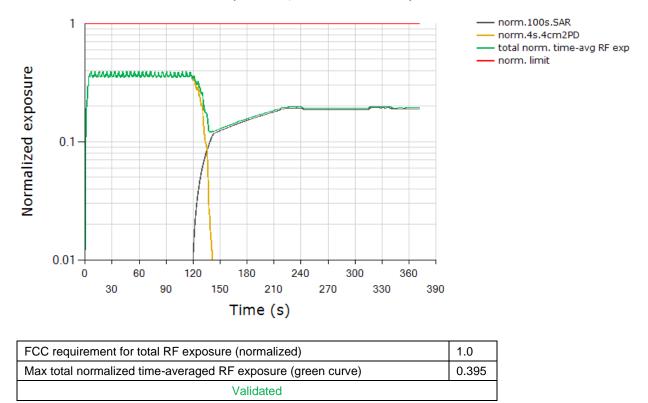
Instantaneous and 100s-averaged conducted LTE Tx power versus time, instantaneous and 4saveraged radiated mmW Tx power versus time, time-averaged conducted LTE Tx power limit and time-averaged radiated mmW Tx power limit:



Above time-averaged conducted Tx power for LTE Band 2 and radiated Tx power for mmW NR n260 beam 30 are converted into time-averaged 1gSAR and time-averaged 4cm²PD using Equation (2a) and (2b), which are divided by FCC 1gSAR limit of 1.6 W/kg and 4cm²PD limit of 10 W/m², respectively, to obtain normalized exposures versus time. Below plot shows (a) normalized time-averaged 1gSAR versus time, (b) normalized time-averaged 4cm2-avg.PD versus time, (c) sum of normalized time-averaged 1gSAR and normalized time-averaged 4cm²avg.PD:

FCC ID: A3LSMA426U	PCTEST [*] Proud to be part of @ element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager
Document S/N:	Test Dates:	DUT Type:		Daga 70 of 00
1M2101040001-21.A3L	1/21/2021-3/2/2021	Portable Handset		Page 79 of 98
© 2021 PCTEST		•		REV 1.0

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Total Normalized Time-averaged RF Exposure Tech: LTE, Band 2 / Tech: NR5G MMW, Band n260

<u>Plot notes:</u> As soon as 5G mmW NR call was established, LTE was placed in all-down bits immediately. Between 0s~120s, mmW exposure is the dominant contributor. Here, Smart Transmit feature allocates a maximum of 75% for mmW (based on the 3dB reserve setting in Part 1 report). From Table 12-3, this corresponds to a normalized $4\text{cm}^2\text{PD}$ exposure value for Beam ID 30 of $(75\% * 4.62 \text{ W/m}^2)/(10 \text{ W/m}^2) = 34.7\% \pm 2.1\text{dB}$ device related uncertainty (see green/orange curve between 0s~120s). At ~120s time mark, LTE is set to all-up bits, taking away margin from mmW exposure gradually. Towards the end of test, LTE is the dominant contributor towards RF exposure, i.e., corresponding normalized 1gSAR exposure value of $(100\% * 0.363 \text{ W/kg})/(1.6 \text{ W/kg}) = 22.7\% \pm 1\text{dB}$ design related uncertainty (see black curve approaching this level towards end of the test).

As can be seen, the power limiting enforcement is effective and the total normalized timeaveraged RF exposure does not exceed 1.0. Therefore, Qualcomm[®] Smart Transmit time averaging feature is validated.

FCC ID: A3LSMA426U	Proud to be part of @ element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager
Document S/N:	Test Dates:	DUT Type:		Page 80 of 98
1M2101040001-21.A3L	1/21/2021-3/2/2021	Portable Handset		Fage 60 01 96
@ 2021 PCTEST				DEV/10

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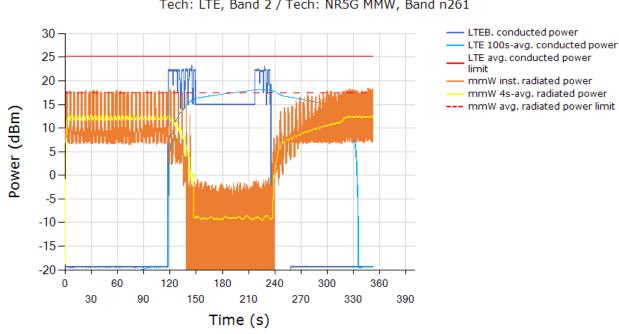
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REV 1.0 04/06/2020

13.3 Switch in SAR vs. PD exposure test results for n261

This test was measured with LTE Band 2 (DSI =2) and mmW Band n261 Beam ID 15, by following the detailed test procedure is described in Section 5.3.2.

Instantaneous and 100s-averaged conducted LTE Tx power versus time, instantaneous and 4saveraged radiated mmW Tx power versus time, time-averaged conducted LTE Tx power limit and time-averaged radiated mmW Tx power limit:



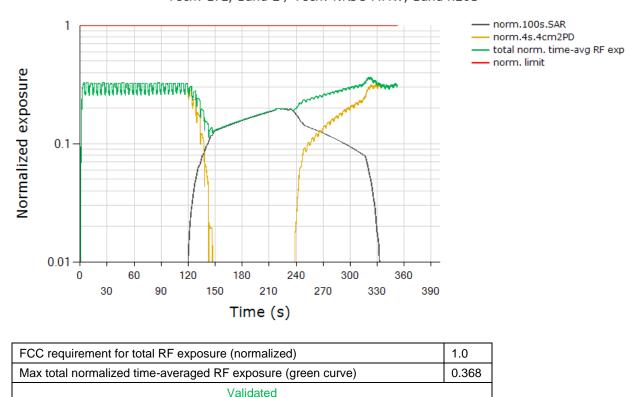
LTE and mmW Instantaneous and Time-averaged TX Power Tech: LTE, Band 2 / Tech: NR5G MMW, Band n261

From the above plot, it is predominantly instantaneous PD exposure between $0s \sim 120s$, it is instantaneous SAR+PD exposure between 120s ~ 140s, it is predominantly instantaneous SAR exposure between 140s ~ 200s, and above 200s, it is predominantly instantaneous PD exposure.

Normalized time-averaged exposures for LTE (1gSAR) and mmW (4cm²PD), as well as total normalized time-averaged exposure versus time:

FCC ID: A3LSMA426U	PCTEST* Proud to be part of @ element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager
Document S/N:	Test Dates:	DUT Type:		Dage 81 of 09
1M2101040001-21.A3L	1/21/2021-3/2/2021	Portable Handset		Page 81 of 98
© 2021 PCTEST		•		REV 1.0

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Total Normalized Time-averaged RF Exposure Tech: LTE, Band 2 / Tech: NR5G MMW, Band n261

Plot notes: As soon as 5G mmW NR call was established, LTE was placed in all-down bits immediately. Between 0s~120s, mmW exposure is the dominant contributor. Here, Smart Transmit feature allocates a maximum of 75% for mmW (based on 3dB reserve setting in Part 1 report). From Table 12-3, this corresponds to a normalized 4cm²PD exposure value for Beam ID 15 of (75% * 4.96 W/m²)/(10 W/m²) = 37.2% ± 2.1dB device related uncertainty (see orange/green curve between 0s~120s). At ~120s time mark, LTE is set to all-up bits, taking away margin from mmW exposure gradually (orange curve for mmW exposure goes down while black curve for LTE exposure goes up). At ~240s time mark, LTE is set to all-down bits, which results in mmW getting back RF margin slowly as seen by gradual increase in mmW exposure (orange curve for mmW exposure goes up while black curve for LTE exposure goes down). The calculated maximum RF exposure from LTE corresponds to normalized 1gSAR exposure value of (100% * 0.363 W/kg)/(1.6 W/kg) = 22.7% ± 1dB design related uncertainty (note that this level will be achieved by green and black curves if LTE remains in all-up bits for longer time duration which was already demonstrated in maximum Tx power test in Section 13.1). Total normalized time-averaged exposure (green curve) for this test should be within the calculated range between $37.2\% \pm 2.1$ dB device related uncertainty (only PD exposure) and $22.7\% \pm 1$ dB design related uncertainty (only SAR exposure).

FCC ID: A3LSMA426U	PCTEST [®] Proud to be part of @ element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager
Document S/N:	Test Dates:	DUT Type:		Page 82 of 98
1M2101040001-21.A3L	1/21/2021-3/2/2021	Portable Handset		Fage 02 01 90
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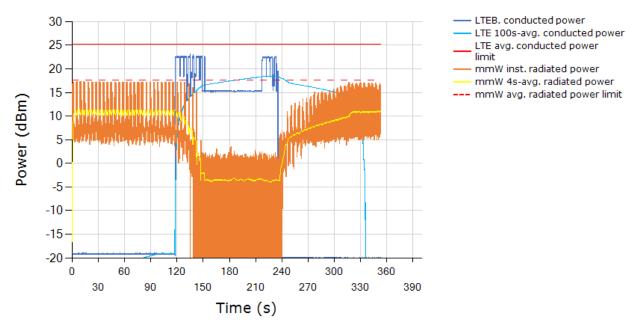
REV 1.0 04/06/2020

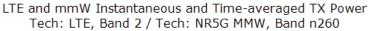
As can be seen, the power limiting enforcement is effective during transmission when SAR and PD exposures are switched, and the total normalized time-averaged RF exposure does not exceed 1.0. Therefore, Qualcomm[®] Smart Transmit time averaging feature is validated.

13.4 Switch in SAR vs. PD exposure test results for n260

This test was measured with LTE Band 2 (DSI =2) and mmW Band n260 Beam ID 30, by following the detailed test procedure is described in Section 5.3.2.

Instantaneous and 100s-averaged conducted LTE Tx power versus time, instantaneous and 4saveraged radiated mmW Tx power versus time, time-averaged conducted LTE Tx power limit and time-averaged radiated mmW Tx power limit:



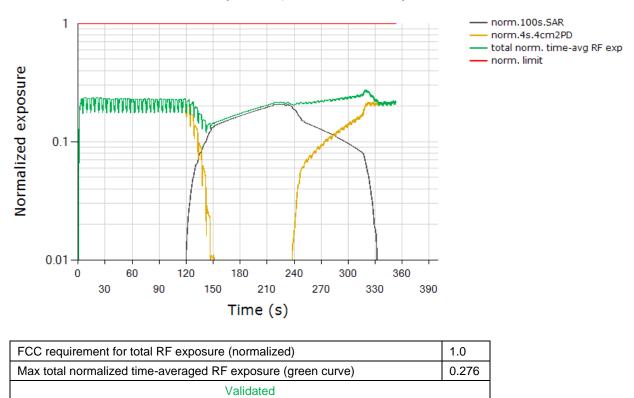


From the above plot, it is predominantly instantaneous PD exposure between $0s \sim 120s$, it is instantaneous SAR+PD exposure between 120s ~ 140s, it is predominantly instantaneous SAR exposure between 140s ~ 200s, and above 200s, it is predominantly instantaneous PD exposure

Normalized time-averaged exposures for LTE (1gSAR) and mmW (4cm²PD), as well as total normalized time-averaged exposure versus time:

FCC ID: A3LSMA426U	Pour lo be part of @element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager		
Document S/N:	Test Dates:	DUT Type:				
1M2101040001-21.A3L	1/21/2021-3/2/2021	Portable Handset		Page 83 of 98		
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Total Normalized Time-averaged RF Exposure Tech: LTE, Band 2 / Tech: NR5G MMW, Band n260

Plot notes: As soon as 5G mmW NR call was established, LTE was placed in all-down bits immediately. Between 0s~120s, mmW exposure is the dominant contributor. Here, Smart Transmit feature allocates a maximum of 75% for mmW (based on 3dB reserve setting in Part 1 report). From Table 12-3, this corresponds to a normalized 4cm²PD exposure value for Beam ID 30 of (75% * 4.62 W/m²)/(10 W/m²) = 34.7% ± 2.1dB device related uncertainty (see orange/green curve between 0s~120s). At ~120s time mark, LTE is set to all-up bits, taking away margin from mmW exposure gradually (orange curve for mmW exposure goes down while black curve for LTE exposure goes up). At ~240s time mark, LTE is set to all-down bits, which results in mmW getting back RF margin slowly as seen by gradual increase in mmW exposure (orange curve for mmW exposure goes up while black curve for LTE exposure goes down). The calculated maximum RF exposure from LTE corresponds to normalized 1gSAR exposure value of (100% * 0.363 W/kg)/(1.6 W/kg) = 22.7% ± 1dB design related uncertainty (note that this level will be achieved by green and black curves if LTE remains in all-up bits for longer time duration which was already demonstrated in maximum Tx power test in Section 13.1). Total normalized time-averaged exposure (green curve) for this test should be within the calculated range between 34.7% ± 2.1dB device related uncertainty (only PD exposure) and 22.7% ± 1dB design related uncertainty (only SAR exposure).

FCC ID: A3LSMA426U	PCTEST* Proud to be part of @ element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager
Document S/N:	Test Dates:	DUT Type:		Dage 84 of 00
1M2101040001-21.A3L	1/21/2021-3/2/2021	Portable Handset		Page 84 of 98
© 2021 PCTEST		•		REV 1.0

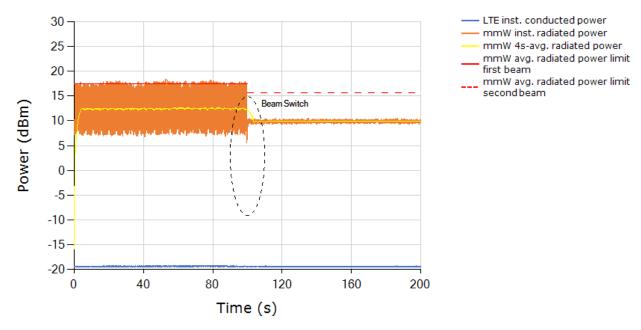
REV 1.0 04/06/2020

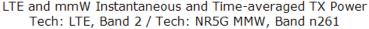
As can be seen, the power limiting enforcement is effective during transmission when SAR and PD exposures are switched, and the total normalized time-averaged RF exposure does not exceed 1.0. Therefore, Qualcomm[®] Smart Transmit time averaging feature is validated.

13.5 Change in Beam test results for n261

This test was measured with LTE Band 2 (DSI = 2) and mmW Band n261, with beam switch from Beam ID 15 to Beam ID 1, by following the test procedure is described in Section 5.3.3.

Instantaneous conducted LTE Tx power versus time, instantaneous and 4s-averaged radiated mmW Tx power versus time, time-averaged radiated mmW Tx power limits for beam 15 and beam 1:

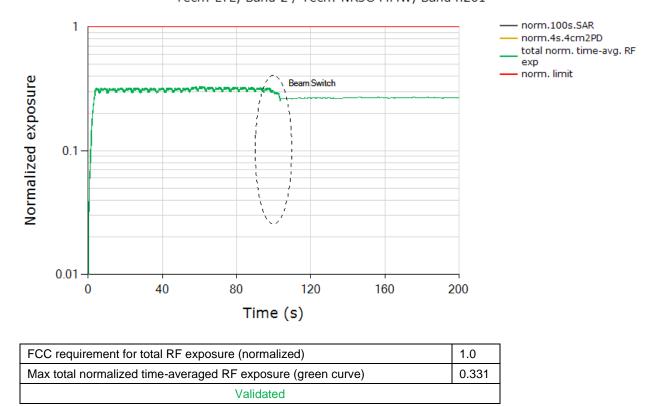




FCC ID: A3LSMA426U	PCTEST* Proud to be part of @ element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager
Document S/N:	Test Dates:	DUT Type:		Daga 95 of 09
1M2101040001-21.A3L	1-21.A3L 1/21/2021-3/2/2021 Portable Handset			Page 85 of 98
© 2021 PCTEST				REV 1.0

REV 1.0 04/06/2020

Normalized time-averaged exposures for LTE and mmW (4cm²PD), as well as total normalized time-averaged exposure versus time:



Total Normalized Time-averaged RF Exposure Tech: LTE, Band 2 / Tech: NR5G MMW, Band n261

<u>Plot notes:</u> 5G mmW NR call was established at ~1s time mark and LTE was placed in all-down bits immediately after 5G mmW NR call was established. For the rest of this test, mmW exposure is the dominant contributor as LTE is left in all-down bits. Here, Smart Transmit feature allocates a maximum of 75% for mmW (based on 3dB reserve setting in Part 1 report). From Table 12-3, exposure between 1s ~100s corresponds to a normalized 4cm²PD exposure value for Beam ID 15 of (75% * 4.96 W/m²)/(10 W/m²) = 37.2% ± 2.1dB device related uncertainty. At ~100s time mark (shown in black dotted ellipse), beam was switched to Beam ID 1. From Table 12-3, exposure between 100s ~200s corresponds to a normalized 4cm²PD exposure value for 75% * 4.51 W/m²)/(10 W/m²) = 33.8% ± 2.1dB device related uncertainty. At ~100s time mark (shown in black dotted ellipse), beam was switched to Beam ID 1. From Table 12-3, exposure between 100s ~200s corresponds to a normalized 4cm²PD exposure value for Beam ID 1 of (75% * 4.51 W/m²)/(10 W/m²) = 33.8% ± 2.1dB device related uncertainty. Additionally, during the switch, the ratio between the averaged radiated powers of the two beams (yellow curve) should correspond to the difference in EIRPs measured at each corresponding *input.power.limit* for these beams listed in Table 12-3, i.e., 2.3 dB ± 2.1dB device uncertainty.

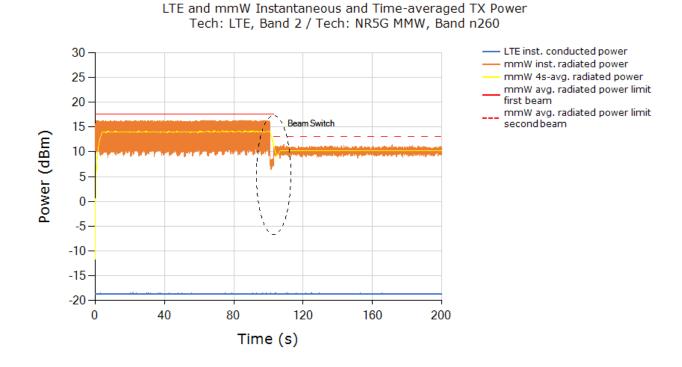
FCC ID: A3LSMA426U	PCTEST* Proud to be part of @ element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager
Document S/N:	Test Dates:	DUT Type:		Dage 96 of 09
1M2101040001-21.A3L	1/21/2021-3/2/2021	/2/2021 Portable Handset		Page 86 of 98
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REV 1.0 04/06/2020

13.6 Change in Beam test results for n260

This test was measured with LTE Band 2 (DSI = 2) and mmW Band n260, with beam switch from Beam ID 30 to Beam ID 3, by following the test procedure is described in Section 5.3.3.

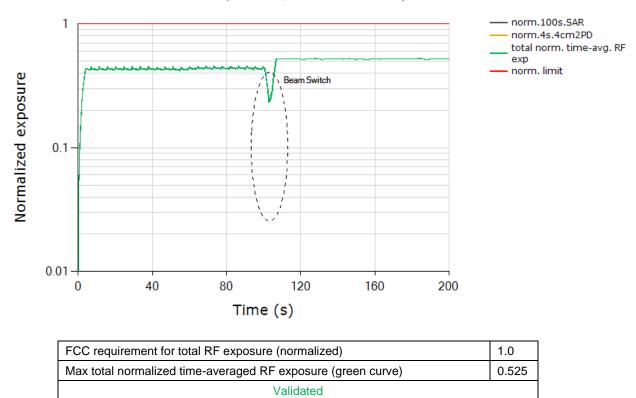
Instantaneous conducted LTE Tx power versus time, instantaneous and 4s-averaged radiated mmW Tx power versus time, time-averaged radiated mmW Tx power limits for beam 30 and beam 3:



FCC ID: A3LSMA426U		PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager
Document S/N:	Test Dates:	DUT Type:		Dage 97 of 09
1M2101040001-21.A3L	1/21/2021-3/2/2021	Portable Handset		Page 87 of 98
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REV 1.0 04/06/2020

Normalized time-averaged exposures for LTE and mmW (4cm²PD), as well as total normalized time-averaged exposure versus time:



Total Normalized Time-averaged RF Exposure Tech: LTE, Band 2 / Tech: NR5G MMW, Band n260

<u>Plot notes:</u> 5G mmW NR call was established at ~1s time mark and LTE was placed in all-down bits immediately after 5G mmW NR call was established. For the rest of this test, mmW exposure is the dominant contributor as LTE is left in all-down bits. Here, Smart Transmit feature allocates a maximum of 75% for mmW (based on 3dB reserve setting in Part 1 report). From Table 12-3, exposure between 1s ~100s corresponds to a normalized 4cm²PD exposure value for Beam ID 30 of (75% * 4.62 W/m²)/(10 W/m²) = 34.7% ± 2.1dB device related uncertainty. At ~100s time mark (shown in black dotted ellipse), beam was switched to Beam ID 3. From Table 12-3, exposure between 100s ~200s corresponds to a normalized 4cm²PD exposure value for 75% * 5.66 W/m²)/(10 W/m²) = 42.5% ± 2.1dB device related uncertainty. At ratio between the averaged radiated powers of the two beams (yellow curve) should correspond to the difference in EIRPs measured at each corresponding *input.power.limit* for these beams listed in Table 12-3, i.e., 3.7dB ± 2.1dB device uncertainty.

FCC ID: A3LSMA426U	PCTEST* Proud to be part of @ element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager
Document S/N:	Test Dates:	DUT Type:		Dogo 80 of 00
1M2101040001-21.A3L	1/21/2021-3/2/2021	Portable Handset		Page 88 of 98
© 2021 PCTEST		•		REV 1.0

REV 1.0 04/06/2020

14 SYSTEM VERIFICATION (FREQ > 6 GHZ)

The system was verified to be within ±0.66 dB of the power density targets on the calibration certificate according to the test system specification in the user's manual and calibration facility recommendation. The 0.66 dB deviation threshold represents the expanded uncertainty for system performance checks using SPEAG's mmWave verification sources. The same spatial resolution and measurement region used in the source calibration was applied during the system check.

The measured power density distribution of verification source was also confirmed through visual inspection to have no noticeable differences, both spatially (shape) and numerically (level) from the distribution provided by the manufacturer, per November 2017 TCBC Workshop Notes.

	System Verification									
Syst.	Freq. (GHz)	Date	Source SN	Probe SN	Normal psPD (W/m ² over 4 cm ²) Deviation (dB) Total psPD (W/m ² over 4 cm ²)		Normal psPD (W/m ² over 4 cm ²)		Deviation (dB)	
					measured	target		measured	target	
Ν	30.00	2/11/2021	1045	9364	34.10	32.70	0.18	34.50	33.20	0.17
Ν	30.00	2/15/2021	1045	9364	34.40	32.70	0.22	34.80	33.20	0.20
Ν	30.00	2/23/2021	1045	9364	34.10	32.70	0.18	34.50	33.20	0.17
Ν	30.00	2/25/2021	1045	9364	33.90	32.70	0.16	34.30	33.20	0.14

Table 14-1 System Verification Results

Note: A 10 mm distance spacing was used from the reference horn antenna aperture to the probe element. This includes 4.45 mm from the reference antenna horn aperture to the surface of the verification source plus 5.55 mm from the surface to the probe. The SPEAG software requires a setting of "5.55 mm" for the correct set up.

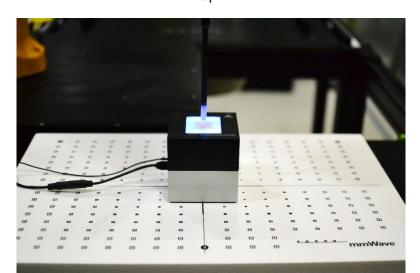


Figure 14-1 System Verification Setup Photo

FCC ID: A3LSMA426U	PCTEST* Proud to be part of @ element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager		
Document S/N:	Test Dates:	DUT Type:		Dage 20 of 00		
1M2101040001-21.A3L	1/21/2021-3/2/2021	Portable Handset		Page 89 of 98		
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15 **POWER DENSITY TEST RESULTS (FREQ > 6 GHZ)**

PD measurement results for maximum power transmission scenario 15.1

The following configurations were measured by following the detailed test procedure is described in Section 5.4:

- 1. LTE Band 2 (DSI =3) and mmW Band n261 Beam ID 15
- 2. LTE Band 2 (DSI =3) and mmW Band n260 Beam ID 30

The measured conducted Tx power of LTE and ratio of $\frac{[pointE(t)]^2}{[pointE_input.power.limit]^2}$ of mmW is converted into 1gSAR and 4cm²PD value, respectively, using Eq. (4a) and (4b), rewritten below:

$$1g_{or_{1}0gSAR(t)} = \frac{conducted_{Tx_power(t)}}{conducted_{Tx_power_{limit}}} * 1g_{or_{1}0gSAR_{limit}}$$
(4a)

 $4cm^2 PD(t) = \frac{[pointE(t)]^2}{[pointE_input.power.limit]^2} * 4cm^2 PD_input.power.limit$ (4b)

$$\frac{\frac{1}{T_{SAR}}\int_{t-T_{SAR}}^{t} 1g_{-}or_{-}10gSAR(t)dt}{FCC SAR limit} + \frac{\frac{1}{T_{PD}}\int_{t-T_{PD}}^{t} 4cm^{2}PD(t)dt}{FCC 4cm^{2}PD limit} \le 1$$
(4c)

where, $conducted_Tx_power(t)$, $conducted_Tx_power_P_{limit}$, and $1g_or_10gSAR_P_{limit}$ correspond to the measured instantaneous conducted Tx power, measured conducted Tx power at Plimit, and measured 1gSAR or 10gSAR values at P_{limit} corresponding to LTE transmission. Similarly, pointE(t), pointE_input.power.limit, and 4cm²PD@input.power.limit correspond to the measured instantaneous E-field, E-field at input power limit, and 4cm²PD value at input power limit. corresponding to mmW transmission.

NOTE: cDASY6 system measures relative E-field, and provides ratio of $\frac{[pointE(t)]^2}{[pointE_input.power.limit]^2}$ versus time.

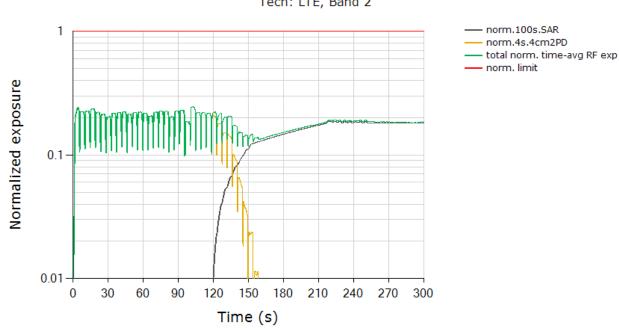
The radio configurations tested are described in Table 12-1 and Table 12-2. The 1gSAR at Plimit for LTE 2 DSI = 2, the measured 4cm²PD at *input.power.limit* of mmW n261 beam 15 and n260 beam 30, are all listed in Table 12-3.

FCC ID: A3LSMA426U	Proud to be part of @element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager
Document S/N:	Test Dates:	DUT Type:		Dage 00 of 00
1M2101040001-21.A3L	1/21/2021-3/2/2021	Portable Handset		Page 90 of 98
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15.1.1 PD test results for n261

Step 2.e plot (in Section 5.4) for normalized instantaneous and time-averaged exposures for LTE and mmW n261 beam 15.



Total Normalized Time-averaged RF Exposure Tech: LTE, Band 2

FCC limit for total RF exposure (normalized)	1.0				
Max total normalized time-averaged RF exposure (green curve)	0.245				
Validated					

Plot notes: LTE was placed in all-down bits immediately after 5G mmW NR call was established. Between 0s~120s, mmW exposure is the dominant contributor. Here, Smart Transmit feature allocates a maximum of 75% for mmW (based on the 3dB reserve setting in Part 1 report). From Table 12-3, this corresponds to a normalized 4cm²PD exposure value for Beam ID 15 of $(75\% * 4.96 \text{ W/m}^2)/(10 \text{ W/m}^2) = 37.2\% \pm$ 2.1dB device related uncertainty (see orange/green curve between 0s~120s). Around 120s time mark, LTE is set to all-up bits, taking away margin from mmW exposure gradually. Towards the end of the test, LTE is the dominant contributor towards RF exposure, i.e., corresponding normalized 1gSAR exposure value of (100% * 0.363 W/kg)/(1.6 W/kg) = 22.7% ± 1dB design related uncertainty (see black curves approaching this level towards end of the test).

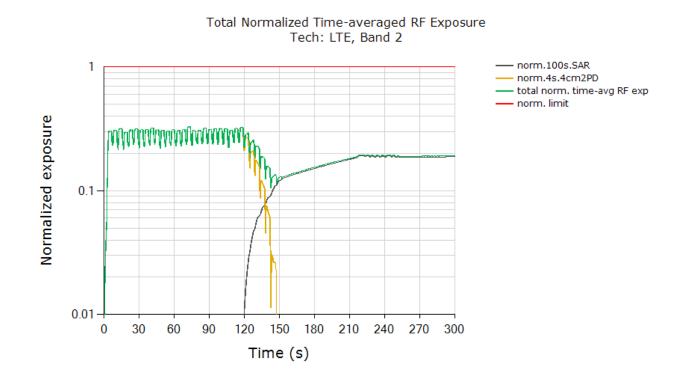
As can be seen, the power limiting enforcement is effective and the total normalized time-averaged RF exposure does not exceed 1.0. Therefore, Qualcomm® Smart Transmit time averaging feature is validated.

FCC ID: A3LSMA426U	Proud to be part of @element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager
Document S/N:	Test Dates:	DUT Type:		Dage 01 of 00
1M2101040001-21.A3L	1/21/2021-3/2/2021	Portable Handset		Page 91 of 98
© 2021 PCTEST				REV 1.0

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15.1.2 PD test results for n260

Step 2.e plot (in Section 5.4) for normalized instantaneous and time-averaged exposures for LTE and mmW n260 beam 30.



FCC limit for total RF exposure	1.0
Max total normalized time-averaged RF exposure (green curve)	0.331
Validated	

<u>Plot notes</u>: LTE was placed in all-down bits immediately after 5G mmW NR call was established. Between 0s~120s, mmW exposure is the dominant contributor. Here, Smart Transmit feature allocates a maximum of 75% for mmW (based on the 3dB reserve setting in Part 1 report). From Table 12-3, this corresponds to a normalized $4cm^2PD$ exposure value for Beam ID 30 of $(75\% * 4.62 \text{ W/m}^2)/(10 \text{ W/m}^2) = 34.7\% \pm 2.1dB$ device related uncertainty (see orange/green curve between 0s~120s). Around 120s time mark, LTE is set to all-up bits, taking away margin from mmW exposure gradually. Towards the end of the test, LTE is the dominant contributor towards RF exposure, i.e., corresponding normalized 1gSAR exposure value of $(100\% * 0.363 \text{ W/kg})/(1.6 \text{ W/kg}) = 22.7\% \pm 1dB$ design related uncertainty (see black curves approaching this level towards end of the test).

As can be seen, the power limiting enforcement is effective and the total normalized time-averaged RF exposure does not exceed 1.0. Therefore, Qualcomm[®] Smart Transmit time averaging feature is validated.

FCC ID: A3LSMA426U	Proved to be part of (() element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager
Document S/N:	Test Dates:	DUT Type:		Dage 02 of 09
1M2101040001-21.A3L	1/21/2021-3/2/2021	Portable Handset		Page 92 of 98
© 2021 PCTEST				REV 1.0

REV 1.0 04/06/2020

16 EQUIPMENT LIST

Manufacturer	Model	Description	Cal Date	Cal Interval	Cal Due	Serial Number
Agilent	8594A	(9kHz-2.9GHz) Spectrum Analyzer	N/A	N/A	N/A	3051A00187
Agilent	E4438C	ESG Vector Signal Generator	3/8/2019	Biennial	3/8/2021	MY42082385
Agilent	N9020A	MXA Signal Analyzer	9/22/2020	Annual	9/22/2021	MY54500644
Agilent	N5182A	MXG Vector Signal Generator	2/19/2020	Annual	2/19/2021	MY47420651
Agilent	8753ES	S-Parameter Network Analyzer	2/2/2021	Annual	2/2/2022	US39170122
Agilent	N5182A	MXG Vector Signal Generator	5/13/2020	Annual	5/13/2021	MY47420603
Agilent	E4438C	ESG Vector Signal Generator	3/8/2019	Biennial	3/8/2021	MY42082385
Agilent	E4438C	ESG Vector Signal Generator	3/11/2019	Biennial	3/11/2021	MY45090700
Agilent	8753ES	S-Parameter Vector Network Analyzer	12/15/2020	Annual	12/15/2021	MY40003841
Amplifier Research	15S1G6	Amplifier	CBT	N/A	CBT	433972
Amplifier Research	15S1G6	Amplifier	CBT	N/A	CBT	433974
Anritsu	ML2495A	Power Meter	1/18/2021	Annual	1/18/2022	941001
Anritsu	MA24106A	USB Power Sensor	6/8/2020	Annual	6/8/2021	1344555
Anritsu	MA24106A	USB Power Sensor	7/24/2020	Annual	7/24/2021	1344556
Anritsu	ML2496A	Power Meter	11/25/2020	Annual	11/25/2021	1405003
Anritsu	MA2411B	Pulse Power Sensor	7/28/2020	Annual	7/28/2021	1339018
Anritsu	MA2411B	Pulse Power Sensor	10/19/2020	Annual	10/19/2021	1339026
COMTECH	AR85729-5/5759B	Solid State Amplifier	CBT	N/A	CBT	M3W1A00-1002
COMTech	AR85729-5	Solid State Amplifier	CBT	N/A	CBT	M1S5A00-009
Control Company	4352	Long Stem Thermometer	5/16/2020	Biennial	5/16/2022	200294416
Control Company	4040	Therm./ Clock/ Humidity Monitor	3/6/2020	Biennial	3/6/2022	200170289
Control Company	4352	Long Stem Thermometer	6/26/2019	Biennial	6/26/2021	192282753
K & L	11SH10-1300/U4000	High Pass Filter	N/A	N/A	N/A	11SH10-1300/U4000 - 2
Keysight Technologies	772D	Dual Directional Coupler	CBT	N/A	CBT	MY52180215
Keysight Technologies	E7515B	UXM 5G Wireless Test Platform	6/11/2019	Biennial	6/11/2021	MY59150289
Keysight Technologies			10/6/2020	Annual	10/6/2021	MY59150289 MY59292534
	M1740A	mmWave Transceiver				
Keysight Technologies	M1740A	mmWave Transceiver	10/6/2020	Annual	10/6/2021	MY59292525
Keysight Technologies	E7770A	Common Interface Unit	N/A	N/A	N/A	MY58290483
Krytar	110067006	Directional Coupler, 10 - 67 GHz	N/A	N/A	N/A	200391
MCL	BW-N6W5+	6dB Attenuator	CBT	N/A	CBT	1139
Mini Circuits	ZA2PD2-63-S+	Power Splitter	CBT	N/A	CBT	SUU64901930
Mini Circuits	ZAPD-2-272-S+	Power Splitter	CBT	N/A	CBT	SF702001405
MIniCircuits	NLP-1200+	Low Pass Filter	N/A	N/A	N/A	VUU78201318
MiniCircuits	SLP-2400+	Low Pass Filter	CBT	N/A	CBT	R8979500903
MiniCircuits	VLF-6000+	Low Pass Filter	CBT	N/A	CBT	N/A
Mini-Circuits	BW-N20W5+	DC to 18 GHz Precision Fixed 20 dB Attenuator	CBT	N/A	CBT	N/A
Mini-Circuits	NLP-2950+	Low Pass Filter DC to 2700 MHz	CBT	N/A	CBT	N/A
Mini-Circuits	NLP-1200+	Low Pass Filter DC to 1000 MHz	CBT	N/A	CBT	N/A
Mini-Circuits	BW-N20W5	Power Attenuator	CBT	N/A	CBT	1226
Narda	4216-10	Directional Coupler, 0.5 to 8.0 GHz, 10 dB	CBT	N/A	CBT	01492
Narda	4216-10	Directional Coupler, 0.5 to 8.0 GHz, 10 dB	CBT	N/A	CBT	01493
Narda	4772-3	Attenuator	CBT	N/A	CBT	9406
Narda	BW-S3W2	Attenuator	CBT	N/A	CBT	120
Narda	BW-S10W2+	Attenuator	CBT	N/A	CBT	831
Narda	4014C-6	4 - 8 GHz SMA 6 dB Directional Coupler	CBT	N/A	CBT	N/A
Newmark System	NSC-G2	Motion Controller	CBT	N/A	CBT	1007-D
Pasternack	PE2208-6	Bidirectional Coupler	CBT	N/A	CBT	N/A
Pasternack	PE2209-10	Bidirectional Coupler	CBT	N/A	CBT	N/A
Rohde & Schwarz	CMW500	Radio Communication Tester	3/27/2020	Annual	3/27/2021	128633
Rohde & Schwarz	NRP8S	3-Path Dipole Power Sensor	5/27/2020	Biennial	5/27/2021	128655
Rohde & Schwarz	NRP85 NRP85	3-Path Dipole Power Sensor 3-Path Dipole Power Sensor	9/16/2019	Biennial	9/16/2021	108168
Rohde & Schwarz	NRP85	3-Path Dipole Power Sensor 3-Path Dipole Power Sensor	6/10/2020	Annual	6/10/2021	108523
Rohde & Schwarz	NRP85 NRP50S	3-Path Dipole Power Sensor 3-Path Dipole Power Sensor	6/10/2020	Biennial	6/10/2021	109322
SPEAG	5G Verification Source 30GHz	30GHz System Verification Antenna	12/10/2020	Annual	12/10/2021	101164
SPEAG	EUmmWV3	E-field Probe	6/24/2020	Annual	6/24/2021	9364
SPEAG	DAK-3.5	Dielectric Assessment Kit	10/14/2020	Annual	10/14/2021	1091
SPEAG	D1750V2	1750 MHz SAR Dipole	5/12/2020	Triennial	10/22/2021	1148
SPEAG	D1900V2	1900 MHz SAR Dipole	2/21/2019	Triennial	2/21/2022	5d148
SPEAG	D3700V2	3700 MHz SAR Dipole	1/21/2020	Biennial	1/21/2022	1067
SPEAG	DAE4	Dasy Data Acquisition Electronics	4/15/2020	Annual	4/15/2021	1582
SPEAG	DAE4	Dasy Data Acquisition Electronics	12/7/2020	Annual	12/7/2021	859
			12/15/2020	Annual	12/15/2021	7570
SPEAG	EX3DV4	SAR Probe	12/15/2020			
	EX3DV4 EX3DV4 BJ8827	SAR Probe SAR Probe Shielded Test Enclosure	3/18/2020 N/A	Annual N/A	3/18/2021 N/A	7526 F229647

Notes:

 CBT (Calibrated Before Testing). Prior to testing, the measurement paths containing a cable, amplifier, attenuator, coupler, or filter were connected to a calibrated source (i.e. a signal generator) to determine the losses of the measurement path. The power meter offset was then adjusted to compensate for the measurement system losses. This level offset is stored within the power meter before measurements are made. This calibration verification procedure applies to the system verification and output power measurements. The calibrated reading is then taken directly from the power meter after compensation of the losses for all final power measurements.

2. Each equipment item is used solely within its respective calibration period.

3. Due to the worldwide pandemic caused by the novel SAR-CoV-2 virus (COVID-19), special calibration extensions have been permitted by A2LA. Some equipment had its calibration period extended accordingly and will be calibrated when possible.

FCC ID: A3LSMA426U	PCTEST* Proud to be part of @ element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager
Document S/N:	Test Dates:	DUT Type:		Dage 02 of 09
1M2101040001-21.A3L	1/21/2021-3/2/2021	Portable Handset		Page 93 of 98
© 2021 PCTEST				REV 1.0

REV 1.0 04/06/2020

MEASUREMENT UNCERTAINTIES 17

For SAR Measurements

Measurements								
а	с	d	e=	f	g	h =	i =	k
			f(d,k)			c x f/e	c x g/e	
	Tol.	Prob.	-	Ci	Ci	1gm	10gms	
Uncertainty Component	(± %)	Dist.	Div.	1gm	10 gms	ui	ui	vi
				0	b	(± %)	(± %)	
Measurement System								•
Probe Calibration	6.55	Ν	1	1.0	1.0	6.6	6.6	∞
Axial Isotropy	0.25	Ν	1	0.7	0.7	0.2	0.2	8
Hemishperical Isotropy	1.3	Ν	1	0.7	0.7	0.9	0.9	8
Boundary Effect	2.0	R	1.73	1.0	1.0	1.2	1.2	x
Linearity	0.3	Ν	1	1.0	1.0	0.3	0.3	x
System Detection Limits	0.25	R	1.73	1.0	1.0	0.1	0.1	x
Readout Electronics	0.3	Ν	1	1.0	1.0	0.3	0.3	x
Response Time	0.8	R	1.73	1.0	1.0	0.5	0.5	x
Integration Time	2.6	R	1.73	1.0	1.0	1.5	1.5	x
RF Ambient Conditions - Noise	3.0	R	1.73	1.0	1.0	1.7	1.7	∞
RF Ambient Conditions - Reflections	3.0	R	1.73	1.0	1.0	1.7	1.7	∞
Probe Positioner Mechanical Tolerance	0.4	R	1.73	1.0	1.0	0.2	0.2	∞
Probe Positioning w/ respect to Phantom	6.7	R	1.73	1.0	1.0	3.9	3.9	∞
Extrapolation, Interpolation & Integration algorithms for Max. SAR Evaluation	4.0	R	1.73	1.0	1.0	2.3	2.3	x
Test Sample Related								
Test Sample Positioning	2.7	Ν	1	1.0	1.0	2.7	2.7	35
Device Holder Uncertainty	1.67	Ν	1	1.0	1.0	1.7	1.7	5
Output Power Variation - SAR drift measurement	5.0	R	1.73	1.0	1.0	2.9	2.9	x
SAR Scaling	0.0	R	1.73	1.0	1.0	0.0	0.0	∞
Phantom & Tissue Parameters								
Phantom Uncertainty (Shape & Thickness tolerances)	7.6	R	1.73	1.0	1.0	4.4	4.4	8
Liquid Conductivity - measurement uncertainty	4.2	N	1	0.78	0.71	3.3	3.0	10
Liquid Permittivity - measurement uncertainty	4.1	Ν	1	0.23	0.26	1.0	1.1	10
Liquid Conductivity - Temperature Uncertainty	3.4	R	1.73	0.78	0.71	1.5	1.4	x
Liquid Permittivity - Temperature Unceritainty	0.6	R	1.73	0.23	0.26	0.1	0.1	×
Liquid Conductivity - deviation from target values	5.0	R	1.73	0.64	0.43	1.8	1.2	x
Liquid Permittivity - deviation from target values	5.0	R	1.73	0.60	0.49	1.7	1.4	x
Combined Standard Uncertainty (k=1)		RSS				11.5	11.3	60
Expanded Uncertainty		k=2				23.0	22.6	
(95% CONFIDENCE LEVEL)								

FCC ID: A3LSMA426U	Proud to be part of @ element	PART 2 RF EXPOSURE EVALUATION REPORT	Approved by: Quality Manager				
Document S/N:	Test Dates:	DUT Type:					
1M2101040001-21.A3L	1/21/2021-3/2/2021	Portable Handset	Page 94 of 98				
© 2021 PCTEST REV 1.0 04/06/2020							

For PD Measurements

					f=	<u> </u>
а	b	С	d	e	b x e/d	g
	Unc.	Prob.			ui	
Uncertainty Component	(± dB)	Dist.	Div.	ci	(± dB)	vi
Calibration	0.49	N	1	1.0	0.49	∞
Probe correction	0	R	1.73	1.0	0.00	∞
Frequency Response (BW ≤ 1 GHz)	0.20	R	1.73	1.0	0.12	∞
Sensor cross coupling	0	R	1.73	1.0	0.00	∞
Isotropy	0.50	R	1.73	1.0	0.29	∞
Linearity	0.20	R	1.73	1.0	0.12	~
Probe Scattering	0	R	1.73	1.0	0	∞
Probe Positioning Offset	0.30	R	1.73	1.0	0.17	∞
Probe Positioning Repeatability	0.04	R	1.73	1.0	0.02	~
Sensor Mechanical Offset	0	R	1.73	1.0	0	~
Probe Spatial Resolution	0	R	1.73	1.0	0	∞
Field Impedance Dependence	0	R	1.73	1.0	0	∞
Amplitude and phase drift	0	R	1.73	1.0	0	∞
Amplitude and phase noise	0.04	R	1.73	1.0	0.02	∞
Measurement area truncation	0	R	1.73	1.0	0	∞
Data acquisition	0.03	Ν	1	1.0	0.03	∞
Sampling	0	R	1.73	1.0	0	∞
Field Reconstruction	0.60	R	1.73	1.0	0.35	∞
Forward Transformation	0	R	1.73	1.0	0	∞
Power Density Scaling	-	R	1.73	1.0	-	∞
Spatial Averaging	0.10	R	1.73	1.0	0.06	∞
System Detection Limit	0.04	R	1.73	1.0	0.02	∞
Test Sample and Environmental Factors					•	
Probe Coupling with DUT	0	R	1.73	1.0	0	~
Modulation Response	0.40	R	1.73	1.0	0.23	~
Integration Time	0	R	1.73	1.0	0	~
Response Time	0	R	1.73	1.0	0	~
Device Holder Influence	0.10	R	1.73	1.0	0.06	∞
DUT Alignment	0	R	1.73	1.0	0	∞
RF Ambient Conditions	0.04	R	1.73	1.0	0.02	8
Ambient Reflections	0.04	R	1.73	1.0	0.02	∞
Immunity / Secondary Reception	0	R	1.73	1.0	0	~
Drift of the DUT	0.22	R	1.73	1.0	0.13	~
Combined Standard Uncertainty (k=1)		RSS			0.76	∞
(95% CONFIDENCE LEVEL)		k	=2		1.53	

	FCC ID: A3LSMA426U	Proud to be part of @ element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager		
	Document S/N:	Test Dates:	DUT Type:		Dage 05 of 09		
	1M2101040001-21.A3L	1/21/2021-3/2/2021	Portable Handset		Page 95 of 98		
© 2021 PCTEST							

REV 1.0 04/06/2020

18 CONCLUSION

18.1 Measurement Conclusion

The SAR evaluation indicates that the DUT complies with the RF radiation exposure limits of the FCC and Innovation, Science, and Economic Development Canada, with respect to all parameters subject to this test. These measurements were taken to simulate the RF effects of RF exposure under worst-case conditions. Precise laboratory measures were taken to assure repeatability of the tests. The results and statements relate only to the item(s) tested.

Please note that the absorption and distribution of electromagnetic energy in the body are very complex phenomena that depend on the mass, shape, and size of the body, the orientation of the body with respect to the field vectors, and the electrical properties of both the body and the environment. Other variables that may play a substantial role in possible biological effects are those that characterize the environment (e.g. ambient temperature, air velocity, relative humidity, and body insulation) and those that characterize the individual (e.g. age, gender, activity level, debilitation, or disease). Because various factors may interact with one another to vary the specific biological outcome of an exposure to electromagnetic fields, any protection guide should consider maximal amplification of biological effects as a result of field-body interactions, environmental conditions, and physiological variables. [3]

FCC ID: A3LSMA426U	PCTEST* Proud to be part of @ element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager
Document S/N:	Test Dates:	DUT Type:		Dage 00 of 00
1M2101040001-21.A3L	1/21/2021-3/2/2021	Portable Handset		Page 96 of 98
2021 PCTEST				REV 1.0

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FCC ID: A3LSMA426U	Pour lo be part of @element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager
Document S/N:	Test Dates:	DUT Type:		Dage 07 of 09
1M2101040001-21.A3L	1/21/2021-3/2/2021	Portable Handset		Page 97 of 98
© 2021 PCTEST				REV 1.0

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FCC ID: A3LSMA426U	PCTEST* Proud to be part of @ element	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager
Document S/N:	Test Dates:	DUT Type:		Page 98 of 98
1M2101040001-21.A3L	1/21/2021-3/2/2021	Portable Handset		Fage 96 01 96
0 2021 PCTEST				REV 1 (

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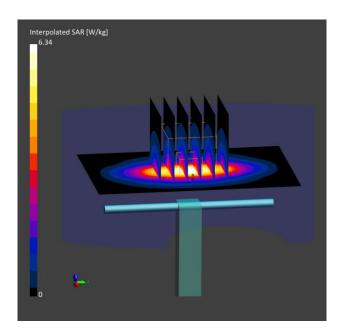
APPENDIX A: VERIFICATION PLOTS

PCTEST Date: 01-22-2021 1750 Body Verification

Medium

Meanann								
Frequency [MHz]	TSL	TSL Conductivity [S/m	1] Т	TSL Permittivity Ar		t Temperature [C]	Tissue Temperature [C]	
1750.0	1750 Body	1750 Body 1.47		3.3	23.1		21.5	
Exposure Con	ditions		1					
Phantom Section		Test Distance [mm]		Power [dBm]		Communication System	n, UID	
Flat	10			20.0		CW, 0		
Hardware Set	up							
Phantom		Dipole	Probe, Calil	Probe, Calibration Date		Conversion Factor	DAE, Calibration Date	
Twin-SAM V8.0 Right	n-SAM V8.0 Right - 1981 D1750V2 - SN1148		EX3DV4 - S	EX3DV4 - SN7570, 2020-12-15		8.46	DAE4 Sn859, 2020-12-07	
Scans Setup								
					Area Scan		Zoom Sca	
Grid Extents [mm]				(50.0 x 90.0	30.0 × 30.0 × 30.0		
Grid Steps [mm]					15.0 x 15.0	6.0 × 6.0 × 1.		
Sensor Surface [mm]					3.0)		
Graded Grid					No	o Ye		
Grading Ratio					n/a	1.5		

	Zoom Scan
psSAR1g [W/Kg]	3.47
psSAR10g [W/Kg]	1.84
Dev. 1g [%]	-4.41

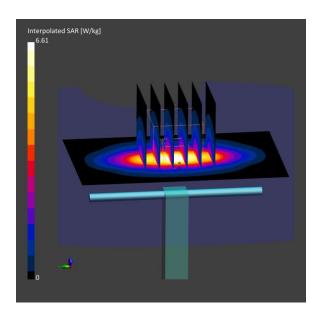


PCTEST Date: 01-29-2021 1750 Body Verification

Medium

Dev. 1g [%]

10		-	SL Permittivity 4.1 Power [dBm] 20.0	Ambient	: Temperature [C]	Tissue Temperature [C] 20.2 m, UID	
itions Te: 10	st Distance [mm]	5	Power [dBm]	21.4	Communication Syste		
Te:					Communication Syste	m, UID	
10					Communication Syste	m, UID	
)			20.0				
					CW, 0		
D					1		
i	pipole	Probe, Calil	bration Date		Conversion Factor	DAE, Calibration Date	
1981 D	01750V2 - SN1148	EX3DV4 - S	EX3DV4 - SN7570, 2020-12-15		8.46	DAE4 Sn859, 2020-12-07	
		1			1		
			Area Scan			Zoom Scan	
			6	60.0 x 90.0	30.0 × 30.0 × 30.0		
			15.0 x 15.0		6.0 x 6.0 x 1.		
				3.0	1.4		
				No	Yes		
Grading Ratio				n/a	1.5		
esults		I.		1			
						Zoom Scan	
psSAR1g [W/Kg]					3.60		
						1.91	
					Area Scan 60.0 x 90.0 15.0 x 15.0 3.0 No n/a	Area Scan 60.0 x 90.0 15.0 x 15.0 3.0 No n/a	



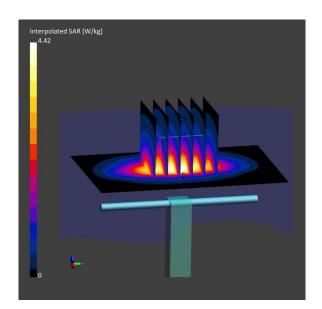
-0.83

PCTEST Date: 02-10-2021 1750 Body Verification

Medium

Medium											
Frequency [MHz]	TSL	TSL Conductivity [S/m]		[S/m]	TSI	L Permittivity Ambien		ent Tem	nt Temperature [C]		Tissue Temperature [C]
1750.0	1750 Bo	1750 Body 1.48			53.7 2		20.5	20.5			20.1
Exposure Con	ditions										
Phantom Section		Tes	t Distance [mm]			Power [dBm]		Co	mmunication Syst	em, UI	D
Flat		10				20.0		CW	/, 0		
Hardware Setu	р					1					
Phantom		Dipole		Probe, Calibr	ation	Date		Conver	sion Factor	DAE	, Calibration Date
Twin-SAM V8.0 - 1978	Twin-SAM V8.0 - 1978 D1750V2 - SN1148 EX3E			EX3DV4 – SN	DV4 - SN7526, 2020-03-18 7.62			7.62		DAE	4 Sn1582, 2020–04–15
Scans Setup	I										
						A	rea Scar	ı			Zoom Sca
Grid Extents [mm]					60.0 × 90.0)	30.0 × 30.0 × 30.0		
Grid Steps [mm]					15.0 x 15.0)	6.0 × 6.0 × 1.5		
Sensor Surface [mm]					3.0)	1.4		
Graded Grid					No)	Yes		
Grading Ratio				n/a			i	1.5			
Measurement	Results	5		1							
											Zoom Scar
psSAR1g [W/Kg]											3.66
psSAR10g [W/Kg]											1.9

Dev. 1g [%]



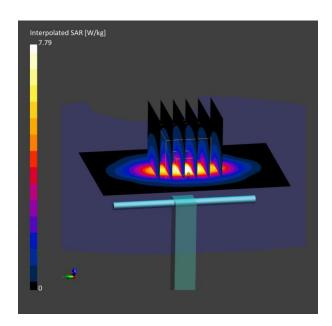
1.38

PCTEST Date: 02-02-2021 1900 Body Verification

Medium

Mcalalli								
Frequency [MHz]	TSL	TSL Conductivity [S/m	1] Т	SL Permittivity	Ambient	: Temperature [C]	Tissue Temperature [C]	
1900.0	1900 Body	1.55	5	5.6	21.2		20.0	
Exposure Con	ditions		1					
Phantom Section		Test Distance [mm]		Power [dBm]		Communication System	n, UID	
Flat		10		20.0		CW , 0		
Hardware Set	h			·				
Phantom		Dipole	Probe, Cal	ibration Date		Conversion Factor	DAE, Calibration Date	
Twin-SAM V8.0 Right	- 1981	D1900V2 - SN5d148	EX3DV4 -	EX3DV4 - SN7570, 2020-12-15		8.12	DAE4 Sn859, 2020-12-07	
Scans Setup								
				Ą	rea Scan	Zoom Scan		
Grid Extents [mm]				60.	.0 x 90.0	30.0 × 30.0 × 30.0		
Grid Steps [mm]				15.	.0 x 15.0	6.0 × 6.0 × 1.5		
Sensor Surface [mm]					3.0	1.4		
Graded Grid					No	Yes		
Grading Ratio					n/a	1.5		
Measurement	Results							
							Zoom Scar	
psSAR1g [W/Kg]							4.07	
psSAR10g [W/Kg]							2.10	

Dev. 1g [%]



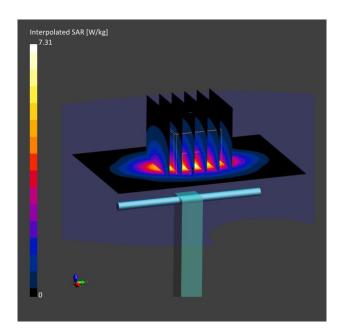
4.09

PCTEST Date: 02-05-2021 1900 Body Verification

Medium

incului i									
Frequency [MHz]	MHz] TSL TSL Conductivity [S/m]		T	TSL Permittivity A		Temperature [C]	Tissue Temperature [C]		
1900.0	1900 Body		3	52.3		22.6		20.3	
Exposure Con	ditions	"							
Phantom Section		Test Dista	ance [mm]		Power [dBm]		Communication System	n, UID	
Flat	10			20.0		CW, 0			
Hardware Set	up								
Phantom		Dipole		Probe, Calibration Date			Conversion Factor	DAE, Calibration Date	
Twin-SAM V8.0 Right	n-SAM V8.0 Right - 1981 D1900V2 - SN5d148		2 – SN5d148	EX3DV4 - SN7570, 2020-12-15		15	8.12	DAE4 Sn859, 2020-12-07	
Scans Setup									
						Area Scan		Zoom Scan	
Grid Extents [mm]				60.0 × 90.0			30.0 × 30.0 × 30.0		
Grid Steps [mm]			15.0 x 15.0			6.0 x 6.0 x 1.5			
Sensor Surface [mm]			3.0			3.0 1.4			
Graded Grid			No			No Yes			
Grading Ratio			n/a			1.5			

	Zoom Scan
psSAR1g [W/Kg]	3.81
psSAR10g [W/Kg]	1.97
Dev. 1g [%]	-2.56

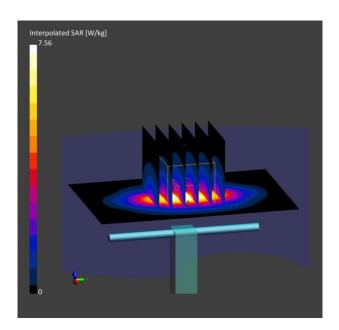


PCTEST Date: 02-15-2021 1900 Body Verification

Medium

MHz] TSL TSL Conductivity [S/m]] TS	TSL Permittivity Ambient		: Temperature [C]	Tissue Temperature [C]	
1900 Body	1.58	52	2.0	21.4		22.4	
ditions							
	Test Distance [mm]		Power [dBm]		Communication System	n, UID	
10			20.0		CW, 0		
hb			1		1		
	Dipole		Probe, Calibration Date		Conversion Factor	DAE, Calibration Date	
n-SAM V8.0 Right - 1981 D1900V2 - SN5d148		EX3DV4 - 5	EX3DV4 - SN7570, 2020-12-15		8.12	DAE4 Sn859, 2020-12-07	
				Area Scan		Zoom Scar	
			e	50.0 x 90.0	30.0 × 30.0 × 30.0		
Grid Steps [mm]			1	5.0 x 15.0	6.0 x 6.0 x 1.5		
Sensor Surface [mm]			3.0		1.		
Graded Grid				No	Ye.		
Grading Ratio				n/a	1.5		
	1900 Body ditions	1900 Body 1.58 Iditions Test Distance [mm] 10 10	1900 Body 1.58 52 iditions Test Distance [mm] 10 Jp Dipole Probe, Cali	1900 Body 1.58 52.0 Iditions Test Distance [mm] Power [dBm] 10 20.0 Jp Dipole Probe, Calibration Date - 1981 D1900V2 - SN5d148 EX3DV4 - SN7570, 2020-12	1900 Body 1.58 52.0 21.4 iditions Test Distance [mm] Power [dBm] 20.0 Jp 20.0 Jp Image: Dipole Probe, Calibration Date Area Scan Image: Dipole Area Scan 60.0 x 90.0 3.0 Image: Dipole Image: Dipole Area Scan 3.0 3.0	1900 Body 1.58 52.0 21.4 iditions Test Distance [mm] Power [dBm] Communication System 10 20.0 CW, 0 Jpole 10 20.0 CW, 0 Jp Dipole Probe, Calibration Date Conversion Factor - 1981 D1900V2 - SN5d148 EX3DV4 - SN7570, 2020-12-15 8.12 Area Scan Good System System System Conversion Factor System Area Scan System System System Area Scan System System<	

	Zoom Scan
psSAR1g [W/Kg]	3.93
psSAR10g [W/Kg]	2.03
Dev. 1g [%]	0.51

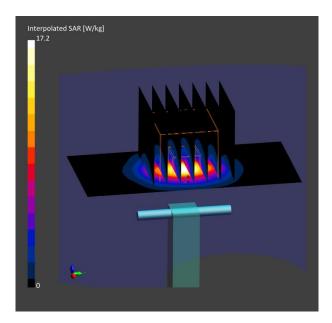


PCTEST Date: 02-25-2021 3700 Head Verification

Medium

Mculum								
Frequency [MHz]	TSL	TSL Conductivity [S	/m]	TSL Permittivity	Ambier	nt Temperature [C]	Tissue Temperature [C]	
3700.0	3600 Head	3.07		37.9	23.1		21.0	
Exposure Cor	nditions			I	1			
Phantom Section Tes		Test Distance [mm]		Power [dBm]	Power [dBm] Communication Sys		em, UID	
Flat 10		10	20.0			CW, 0		
Hardware Set	up							
Phantom		Dipole	Probe, C	alibration Date		Conversion Factor	DAE, Calibration Date	
Twin-SAM V8.0 (Left) – 1964		D3700V2 - SN1067	EX3DV4 - SN7570, 2020-12-15		15	6.96	DAE4 Sn859, 2020-12-07	
Scans Setup								
				Area So	an		Zoom Sca	
Grid Extents [mm]		40.0 x 80.0		0.0	28.0 x 28.0 x 28.0			
Grid Steps [mm]		10.0 x 10.0		5.0 x 5.0 x 1.4				
Sensor Surface [mm]		3.0		1.4				
Graded Grid		No		No	Yes			
Grading Ratio		n/a		ı/a	1.5			

	Zoom Scan
psSAR1g [W/Kg]	6.55
psSAR10g [W/Kg]	2.44
Dev. 1g [%]	-2.53



PCTEST

Date: 02/11/2021

30 GHz System Verification

Device Under Test Properties

DUT	Serial Number
30 GHz Verification Source	1045

Exposure Conditions

Phantom Section	Position	Test Distance [mm]	Band	Frequency [MHz]
5G	FRONT	5.55	Validation band	30000.0

Hardware Setup

Probe, Calibration Date	DAE, Calibration Date
EUmmWV3 - SN9364, 06/24/2020	DAE4 SN1582, 04/15/2020

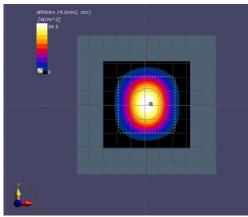
Software Setup

Software	Software Version
cDASY6 Module mmWave	2.2.0.76

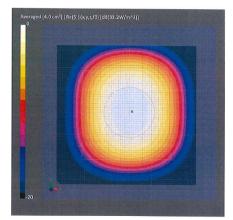
Scans Setup

•	
Scan Type	5G Scan
Grid Extents [mm]	60.0 × 60.0
Grid Steps [lambda]	0.25 x 0.25
Sensor Surface [mm]	5.55

Scan Type	5G Scan
Avg. Area [cm²]	4.00
pS _{tot} avg [W/m ²]	34.5
pS _n avg [W/m ²]	34.1
E _{peak} [V/m]	133
Deviation (dB)	0.17



30GHz System Verification



Calibration Certificate

PCTEST

Date: 02/15/2021

30 GHz System Verification

Device Under Test Properties

DUT	Serial Number
30 GHz Verification Source	1045

Exposure Conditions

Phantom Section	Position	Test Distance [mm]	Band	Frequency [MHz]
5G	FRONT	5.55	Validation band	30000.0

Hardware Setup

Probe, Calibration Date	DAE, Calibration Date
EUmmWV3 - SN9364, 06/24/2020	DAE4 SN1582, 04/15/2020

Software Setup

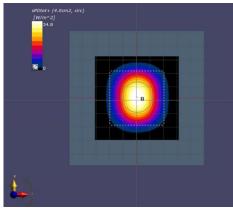
Software	Software Version
cDASY6 Module mmWave	2.2.0.76

Scans Setup

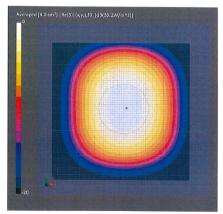
Scan Type	5G Scan
Grid Extents [mm]	60.0 × 60.0
Grid Steps [lambda]	0.25 x 0.25
Sensor Surface [mm]	5.55

Measurement Results

Scan Type	5G Scan
Avg. Area [cm²]	4.00
pS _{tot} avg [W/m²]	34.8
pSn avg [W/m²]	34.4
E _{peak} [V/m]	133
Deviation (dB)	0.20



30GHz System Verification



Calibration Certificate

PCTEST

Date: 02/23/2021

30 GHz System Verification

Device Under Test Properties

DUT	Serial Number
30 GHz Verification Source	1045

Exposure Conditions

Phantom Section	Position	Test Distance [mm]	Band	Frequency [MHz]
5G	FRONT	5.55	Validation band	30000.0

Hardware Setup

Probe, Calibration Date	DAE, Calibration Date
EUmmWV3 - SN9364, 06/24/2020	DAE4 SN1582, 04/15/2020

Software Setup

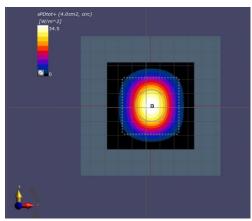
Software	Software Version
cDASY6 Module mmWave	2.2.0.76

Scans Setup

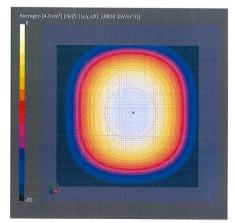
•	
Scan Type	5G Scan
Grid Extents [mm]	60.0 × 60.0
Grid Steps [lambda]	0.25 x 0.25
Sensor Surface [mm]	5.55

Measurement Results

Scan Type	5G Scan
Avg. Area [cm²]	4.00
pS _{tot} avg [W/m ²]	34.5
pS _n avg [W/m ²]	34.1
E _{peak} [V/m]	133
Deviation (dB)	0.17



30GHz System Verification



Calibration Certificate

PCTEST

Date: 02/25/2021

30 GHz System Verification

Device Under Test Properties

DUT	Serial Number
30 GHz Verification Source	1045

Exposure Conditions

Phantom Section	Position	Test Distance [mm]	Band	Frequency [MHz]
5G	FRONT	5.55	Validation band	30000.0

Hardware Setup

Probe, Calibration Date	DAE, Calibration Date
EUmmWV3 - SN9364, 06/24/2020	DAE4 SN1582, 04/15/2020

Software Setup

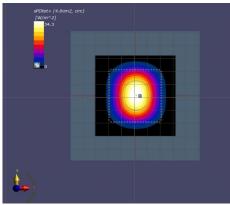
Software	Software Version
cDASY6 Module mmWave	2.2.0.76

Scans Setup

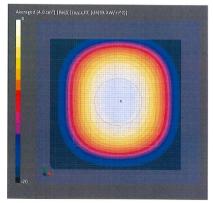
•	
Scan Type	5G Scan
Grid Extents [mm]	60.0 × 60.0
Grid Steps [lambda]	0.25 x 0.25
Sensor Surface [mm]	5.55

Measurement Results

Scan Type	5G Scan
Avg. Area [cm²]	4.00
pS _{tot} avg [W/m ²]	34.3
pS _n avg [W/m²]	33.9
E _{peak} [V/m]	133
Deviation (dB)	0.14



30GHz System Verification



Calibration Certificate

APPENDIX B: SAR TISSUE SPECIFICATIONS

Measurement Procedure for Tissue verification:

- 1) The network analyzer and probe system was configured and calibrated.
- 2) The probe was immersed in the tissue. The tissue was placed in a nonmetallic container. Trapped air bubbles beneath the flange were minimized by placing the probe at a slight angle.
- 3) The complex admittance with respect to the probe aperture was measured
- 4) The complex relative permittivity ε can be calculated from the below equation (Pournaropoulos and Misra):

$$Y = \frac{j2\omega\varepsilon_r\varepsilon_0}{\left[\ln(b/a)\right]^2} \int_a^b \int_a^b \int_0^\pi \cos\phi' \frac{\exp\left[-j\omega r(\mu_0\varepsilon_r\varepsilon_0)^{1/2}\right]}{r} d\phi' d\rho' d\rho$$

where Y is the admittance of the probe in contact with the sample, the primed and unprimed coordinates refer to

source and observation points, respectively, $r^2 = \rho^2 + {\rho'}^2 - 2\rho\rho' \cos\phi'$, ω is the angular frequency, and $j = \sqrt{-1}$.

3 Composition / Information on ingredients

3.2 Mixtures

©

Description: Aqueous solution with surfactants and inhibitors

Deciarable, or nazaruous compon	ents.	
CAS: 107-21-1	Ethanediol	>1.0-4.9%
EINECS: 203-473-3	STOT RE 2, H373;	
Reg.nr.: 01-2119456816-28-0000	Acute Tox. 4, H302	
CAS: 68608-26-4	Sodium petroleum sulfonate	< 2.9%
EINECS: 271-781-5	Eye Irrit. 2, H319	
Reg.nr.: 01-2119527859-22-0000		
CAS: 107-41-5	Hexylene Glycol / 2-Methyl-pentane-2,4-diol	< 2.9%
EINECS: 203-489-0	Skin Irrit. 2, H315; Eye Irrit. 2, H319	
Reg.nr.: 01-2119539582-35-0000		
CAS: 68920-66-1	Alkoxylated alcohol, > C ₁₆	< 2.0%
NLP: 500-236-9	Aquatic Chronic 2, H411;	
Reg.nr.: 01-2119489407-26-0000	Skin Irrit. 2, H315; Eye Irrit. 2, H319	

Additional information:

For the wording of the listed risk phrases refer to section 16. Not mentioned CAS-, EINECS- or registration numbers are to be regarded as Proprietary/Confidential. The specific chemical identity and/or exact percentage concentration of proprietary components is withheld as a trade secret.

Figure B -1

Note: Liquid recipes are proprietary SPEAG. Since the composition is approximate to the actual liquids utilized, the manufacturer tissue-equivalent liquid data sheets are provided below.

	FCC ID: A3LSMA426U	PART 2 RF EXPOSURE EVALUATION REPORT	Approved by: Quality Manager
	Test Dates:	DUT Type:	APPENDIX B:
	1/21/2021 - 3/2/2021	Portable Handset	Page 1 of 3
202	1 PCTEST		REV 1.0 04/06/2020

Schmid & Partner Engineering AG S peag

Zeughausstrasse 43, 8004 Zurich, Switzerland Phone +41 44 245 9700, Fax +41 44 245 9779 info@speag.com, http://www.speag.com

Measurement Certificate / Material Test

Item Name	Body Tissue Simulating Liquid (MBBL600-6000V6)
Product No.	SL AAM U16 BC (Batch: 181029-1)
Manufacturer	SPEAG

Measurement Method TSL dielectric parameters measured using calibrated DAK probe.

Target Parameters Target parameters as defined in the KDB 865664 compliance standard.

Ambient Condi	ion 22°C ; 30% humidity	
TSL Temperate	ire 22°C	
Test Date	30-Oct-18	
Operator	CL	
Additional Info	ormation	
TSL Density	No.	
TSL Heat-capa		

5500

5500

-0.4 -8.8 -0.5 -8.8 -1.8 -0.6 -1.9 -0.4 -2.0 -0.2 -2.2 0.8 -2.3 1.3 -2.5 1.8 -2.6

Results

Т

	Measu	ured		Targe	t	Diff.to Targ	get [%]	100000					
f [MHz]	e'	e"	sigma	eps	sigma	∆-eps	∆-sigma	15.0	100		55 510		
800	55.1	21.3	0.95	55.3	0.97	-0.4	-2.1	10.0	_	100	ALC: NO		
825	55.1	20.8	0.96	55.2	0.98	-0.3	-2.0						
835	55.1	20.6	0.96	55.1	0.99	0.0	-2.5	≈ 5.0	124				
850	55.1	20.4	0.96	55.2	0.99	-0.1	-3.0	0.0 tivit	-	-	100		1.10
900	55.0	19.7	0.98	55.0	1.05	0.0	-6.7	0.0 Permittivity					
1400	54.2	15.6	1.22	54.1	1.28	0.2	-4.7	a∰ -5.0					
1450	54.1	15.4	1.24	54.0	1.30	0.2	-4.6	-10.0			10.00	esecutives	
1500	54.1	15.3	1.27	53.9	1.33	0.3	-4.5		1				
1550	54.0	15.1	1.30	53.9	1.36	0.2	-4.4	-15.0	500	1500	2500	3500	4500
1600	53.9	15.0	1.33	53.8	1.39	0.2	-4.3			1000		ancy MHz	1000
1625	53.9	14.9	1.35	53.8	1.41	0.3	-4.3						
1640	53.9	14.9	1.36	53.7	1.42	0.3	-4.2	45.0					
1650	53.8	14.9	1.36	53.7	1.43	0.2	-4.9	15.0	12				
1700	53.8	14.8	1.40	53.6	1.46	0.4	-4.1	10.0	-				
1750	53.7	14.7	1.43	53.4	1.49	0.5	-4.0	2 50	100	Station .			
1800	53.7	14.6	1.46	53.3	1.52	0.8	-3.9	6.5.0	12/20		1		
1810	53.7	14.6	1.47	53.3	1.52	0.8	-3.3	0.0 Dev. Conductivity %			1		
1825	53.7	14.6	1.48	53.3	1.52	0.8	-2.6	Con co	Λ	2	1		1
1850	53.6	14.5	1.50	53.3	1.52	0.6	-1.3	O5.0	16	/	1		/
1900	53.5	14.5	1.53	53.3	1.52	0.4	0.7	-10.0	-		10 A 12	~	
1950	53.5	14.5	1.57	53.3	1.52	0.4	3.3	-15.0	1				
2000	53.4	14.4	1.60	53.3	1.52	0.2	5.3		00	1500	2500	3500	4500
2050	53.4	14.4	1.64	53.2	1.57	0.3	4.5			o openante.	Frequer	ncy MHz	
2100	53.3	14.4	1.68	53.2	1.62	0.2	3.7						
2150	53.3	14.4	1.72	53.1	1.66	0.4	3.6						
	Section 2.	14.4	1.76	53.0	1.71	0.3	2.9	3500	51.1	15.5	3.02	51.3	3.31
2200	53.2				1.76	0.2	2.8	3700	50.8	15.7	3.24	51.1	3.55
2200 2250	53.2 53.1	14.4	1.81	53.0	1.76			0100					
	THE STATE		1.81 1.85	53.0 52.9	1.81	0.4	2.2	5200	48.1	18.2	5.27	49.0	5.30
2250	53.1	14.4				0.4 0.3	2.2 2.2		48.1 48.0	18.2 18.3	5.27 5.34	49.0 49.0	5.30 5.36
2250 2300	53.1 53.1	14.4 14.4	1.85	52.9	1.81	0.0005.000	10000	5200					
2250 2300 2350	53.1 53.1 53.0	14.4 14.4 14.5	1.85 1.89	52.9 52.8	1.81 1.85	0.3	2.2	5200 5250	48.0	18.3	5.34	49.0	5.36
2250 2300 2350 2400	53.1 53.1 53.0 52.9	14.4 14.4 14.5 14.5	1.85 1.89 1.94	52.9 52.8 52.8	1.81 1.85 1.90	0.3 0.2	2.2 2.1	5200 5250 5300	48.0 47.9	18.3 18.4	5.34 5.41	49.0 48.9	5.36 5.42
2250 2300 2350 2400 2450	53.1 53.1 53.0 52.9 52.9	14.4 14.4 14.5 14.5 14.5	1.85 1.89 1.94 1.98	52.9 52.8 52.8 52.7	1.81 1.85 1.90 1.95	0.3 0.2 0.4	2.2 2.1 1.5	5200 5250 5300 5500	48.0 47.9 47.5	18.3 18.4 18.6	5.34 5.41 5.70	49.0 48.9 48.6	5.36 5.42 5.65

TSL Dielectric Parameters

Figure B-2 600 – 5800 MHz Body Tissue Equivalent Matter

	FCC ID: A3LSMA426U	PRT 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager
	Test Dates:	DUT Type:		APPENDIX B:
	1/21/2021 – 3/2/2021	Portable Handset		Page 2 of 3
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Schmid & Partner Engineering AG	S	p	e	а	a
Zeughausstrasse 43, 8004 Zurich, Switzerland Phone +41 44 245 9700, Fax +41 44 245 9779 info@speag.com, http://www.speag.com					

Measurement Certificate / Material Test

Item Name	Head Tissue Simulating Liquid (HBBL600-10000V6)	
Product No.	SL AAH U16 BC (Batch: 181031-2)	
Manufacturer	SPEAG	

Measurement Method TSL dielectric parameters measured using calibrated DAK probe.

Target Parameters Target parameters as defined in the IEEE 1528 and IEC 62209 compliance standards.

Test Condition		
Ambient Condition	22°C ; 30% humidity	
TSL Temperature	22°C	
Test Date	31-Oct-18	
Operator	CL	
Additional Inform	ation	
TSL Density		
TSL Heat-capacity		

Results

	Meas	ured		Targe	t	Diff.to Targ	get [%]	15.0							
f [MHz]	e'	e"	sigma	eps	sigma	∆-eps	∆-sigma	15.0		11952			a la alte		10
800	43.8	20.5	0.91	41.7	0.90	5.1	1.4	10.0)						-
825	43.8	20.1	0.92	41.6	0.91	5.3	1.5	× 5.0		-	_				
835	43.8	19.9	0.93	41.5	0.91	5.4	2.0	11 0.0	,			~			
850	43.7	19.7	0.93	41.5	0.92	5.3	1.5	E	200						
900	43.5	18.9	0.95	41.5	0.97	4.8	-2.1	a5.0 0-10.0							-
1400	42.5	15.0	1.17	40.6	1.18	4.7	-0.8	<u>0</u> 10.0							-
1450	42.5	14.8	1.19	40.5	1.20	4.9	-0.8	-15.0		13.511	1.	1			1
1600	42.2	14.3	1.27	40.3	1.28	4.7	-1.1		500 15	00 2500	3500 4 Freque	500 5500 ency MHz	6500 7500	8500 9	9500
1625	42.2	14.2	1.29	40.3	1.30	4.8	-0.7	45.0							-
1640	42.2	14.2	1.30	40.3	1.31	4.8	-0.5	15.0			45.44			-	
1650	42.1	14.2	1.30	40.2	1.31	4.6	-1.0	10.0	195001						
1700	42.1	14.0	1.33	40.2	1.34	4.8	-0.9	.≩ 5.0	-	Λ					
1750	42.0	13.9	1.36	40.1	1.37	4.8	-0.8	0.0 Inctiv		$\boldsymbol{\Lambda}$		-	-	-	-
1800	41.9	13.9	1.39	40.0	1.40	4.7	-0.7	Conductivity 0.0 0'2	p	- /		/			
			4 (4 0)	40.0	1.40	4.7	0.0	5.0	1223		~				
1810	41.9	13.8	1.40	40.0	1.40	4.7	0.0	m							
1810 1825	41.9 41.9	13.8 13.8	1.40	40.0	1.40	4.7	0.7	Å 10.0						-	
		1000	1000000				10.00011	-15.0							
1825	41.9	13.8	1.41	40.0	1.40	4.7	0.7	-15.0	500 150	10 2500	3500 45 Freque	00 5500 e	3500 7500	8500 9	500
1825 1850 1900	41.9 41.8	13.8 13.8	1.41 1.42	40.0 40.0	1.40 1.40	4.7 4.5	0.7 1.4	-15.0	500 150 36.3	15.8	3500 45 Freque	00 5500 6 ancy MHz 36.0	3500 7500 4.66	8500 9	
1825 1850 1900 1950	41.9 41.8 41.8	13.8 13.8 13.7	1.41 1.42 1.45	40.0 40.0 40.0	1.40 1.40 1.40	4.7 4.5 4.5	0.7 1.4 3.6	-15.0 £			Freque	ancy MHz		0.9	-1
1825 1850 1900 1950 2000 2050	41.9 41.8 41.8 41.7	13.8 13.8 13.7 13.7	1.41 1.42 1.45 1.48	40.0 40.0 40.0 40.0	1.40 1.40 1.40 1.40	4.7 4.5 4.5 4.3	0.7 1.4 3.6 5.7	-15.0 5200	36.3	15.8	4.57	36.0	4.66		-1 -1
1825 1850 1900 1950 2000 2050	41.9 41.8 41.8 41.7 41.6	13.8 13.8 13.7 13.7 13.6	1.41 1.42 1.45 1.48 1.51	40.0 40.0 40.0 40.0 40.0	1.40 1.40 1.40 1.40 1.40	4.7 4.5 4.3 4.0	0.7 1.4 3.6 5.7 7.9	-15.0 5200 5250	36.3 36.2	15.8 15.9	4.57 4.63	36.0 35.9	4.66 4.71	0.9 0.8	-1 -1 -1
1825 1850 1900 1950 2000 2050 2100 2150	41.9 41.8 41.7 41.6 41.6	13.8 13.8 13.7 13.7 13.6 13.6	1.41 1.42 1.45 1.48 1.51 1.55	40.0 40.0 40.0 40.0 40.0 39.9	1.40 1.40 1.40 1.40 1.40 1.44	4.7 4.5 4.3 4.0 4.2	0.7 1.4 3.6 5.7 7.9 7.3	-15.0 5200 5250 5300	36.3 36.2 36.1	15.8 15.9 15.9	4.57 4.63 4.69	36.0 35.9 35.9	4.66 4.71 4.76	0.9 0.8 0.7	-1 -1 -1 -0
1825 1850 1900 1950 2000 2050 2100 2150	41.9 41.8 41.7 41.6 41.6 41.6 41.5	13.8 13.8 13.7 13.7 13.6 13.6 13.5	1.41 1.42 1.45 1.48 1.51 1.55 1.58	40.0 40.0 40.0 40.0 39.9 39.8	1.40 1.40 1.40 1.40 1.40 1.44 1.49	4.7 4.5 4.3 4.0 4.2 4.2	0.7 1.4 3.6 5.7 7.9 7.3 6.1	-15.0 5200 5250 5300 5500	36.3 36.2 36.1 35.8	15.8 15.9 15.9 16.1	4.57 4.63 4.69 4.92	36.0 35.9 35.9 35.6	4.66 4.71 4.76 4.96	0.9 0.8 0.7 0.3	-1 -1 -1 -0 -0
1825 1850 1900 2000 2000 2100 2100 2150 2200 2250	41.9 41.8 41.8 41.7 41.6 41.6 41.5 41.4	13.8 13.7 13.7 13.6 13.6 13.5 13.5	1.41 1.42 1.45 1.48 1.51 1.55 1.58 1.62	40.0 40.0 40.0 40.0 39.9 39.8 39.7	1.40 1.40 1.40 1.40 1.40 1.44 1.49 1.53	4.7 4.5 4.3 4.0 4.2 4.2 4.2 4.2	0.7 1.4 3.6 5.7 7.9 7.3 6.1 5.7	-15.0 5200 5250 5300 5500 5600	36.3 36.2 36.1 35.8 35.6	15.8 15.9 15.9 16.1 16.2	4.57 4.63 4.69 4.92 5.04	36.0 35.9 35.9 35.6 35.5	4.66 4.71 4.76 4.96 5.07	0.9 0.8 0.7 0.3 0.1	500 -1 -1 -1 -0 -0 -0 0.
1825 1850 1900 2000 2050 2100 2150 2200 2250 2250	41.9 41.8 41.7 41.6 41.6 41.5 41.4 41.4	13.8 13.8 13.7 13.7 13.6 13.6 13.5 13.5 13.5	1.41 1.42 1.45 1.51 1.55 1.58 1.62 1.65	40.0 40.0 40.0 40.0 39.9 39.8 39.7 39.6	1.40 1.40 1.40 1.40 1.40 1.44 1.49 1.53 1.58	4.7 4.5 4.3 4.0 4.2 4.2 4.2 4.2 4.2 4.4	0.7 1.4 3.6 5.7 7.9 7.3 6.1 5.7 4.6	-15.0 5200 5250 5300 5500 5600 5700	36.3 36.2 36.1 35.8 35.6 35.4	15.8 15.9 15.9 16.1 16.2 16.2	Freque 4.57 4.63 4.69 4.92 5.04 5.15	36.0 35.9 35.9 35.6 35.5 35.4	4.66 4.71 4.76 4.96 5.07 5.17	0.9 0.8 0.7 0.3 0.1 0.0	-1 -1 -0 -0 -0
1825 1850 1900 2000 2050 2100 2150 2200 2250 2300 2350	41.9 41.8 41.7 41.6 41.6 41.5 41.4 41.4 41.4 41.3 41.2 41.1	13.8 13.8 13.7 13.7 13.6 13.6 13.5 13.5 13.5 13.5 13.5 13.5	1.41 1.42 1.45 1.48 1.51 1.55 1.58 1.62 1.65 1.69	40.0 40.0 40.0 39.9 39.8 39.7 39.6 39.6	1.40 1.40 1.40 1.40 1.40 1.44 1.49 1.53 1.58 1.58	4.7 4.5 4.3 4.0 4.2 4.2 4.2 4.2 4.2 4.4 4.4	0.7 1.4 3.6 5.7 7.9 7.3 6.1 5.7 4.6 4.2	-15.0 5200 5250 5300 5500 5600 5700 5800	36.3 36.2 36.1 35.8 35.6 35.4 35.2	15.8 15.9 15.9 16.1 16.2 16.2 16.3	Freque 4.57 4.63 4.69 4.92 5.04 5.15 5.27	36.0 35.9 35.9 35.6 35.5 35.4 35.3	4.66 4.71 4.76 4.96 5.07 5.17 5.27	0.9 0.8 0.7 0.3 0.1 0.0 -0.2	-1 -1 -0 -0 -0
1825 1850 1900 2000 2050 2150 2250 2250 2350 2350 2400	41.9 41.8 41.7 41.6 41.6 41.5 41.4 41.4 41.3 41.2	13.8 13.7 13.7 13.6 13.6 13.5 13.5 13.5 13.5 13.5	1.41 1.42 1.45 1.48 1.51 1.55 1.58 1.62 1.65 1.69 1.72	40.0 40.0 40.0 39.9 39.8 39.7 39.6 39.6 39.5	1.40 1.40 1.40 1.40 1.40 1.44 1.49 1.53 1.58 1.62 1.67	4.7 4.5 4.3 4.0 4.2 4.2 4.2 4.2 4.2 4.4 4.4 4.4	0.7 1.4 3.6 5.7 7.9 7.3 6.1 5.7 4.6 4.2 3.2	-15.0 g 5200 5250 5300 5500 5500 5600 5700 5800 6000	36.3 36.2 36.1 35.8 35.6 35.4 35.2 34.9	15.8 15.9 15.9 16.1 16.2 16.2 16.3 16.5	4.57 4.63 4.69 4.92 5.04 5.15 5.27 5.50	36.0 35.9 35.9 35.6 35.5 35.4 35.3 35.1	4.66 4.71 4.76 4.96 5.07 5.17 5.27 5.48	0.9 0.8 0.7 0.3 0.1 0.0 -0.2 -0.6	-1 -1 -0 -0 -0 0. 0.
1825 1850 1900 2000 2050 2150 2250 2250 2350 2350 2400	41.9 41.8 41.7 41.6 41.6 41.5 41.4 41.4 41.4 41.3 41.2 41.1	13.8 13.8 13.7 13.7 13.6 13.6 13.5 13.5 13.5 13.5 13.5 13.5	1.41 1.42 1.48 1.51 1.55 1.58 1.62 1.65 1.69 1.72 1.76 1.80	40.0 40.0 40.0 39.9 39.8 39.7 39.6 39.6 39.5 39.4	1.40 1.40 1.40 1.40 1.44 1.49 1.53 1.58 1.62 1.67 1.71	4.7 4.5 4.3 4.0 4.2 4.2 4.2 4.2 4.2 4.4 4.4 4.4 4.4	0.7 1.4 3.6 5.7 7.9 7.3 6.1 5.7 4.6 4.2 3.2 2.9	-15.0 5 5200 5250 5300 5500 5600 5700 5800 6000 6500	36.3 36.2 36.1 35.8 35.6 35.4 35.2 34.9 34.0	15.8 15.9 15.9 16.1 16.2 16.2 16.3 16.5 16.9	4.57 4.63 4.69 4.92 5.04 5.15 5.27 5.50 6.12	36.0 35.9 35.9 35.6 35.5 35.4 35.3 35.1 34.5	4.66 4.71 4.76 4.96 5.07 5.17 5.27 5.48 6.07	0.9 0.8 0.7 0.3 0.1 0.0 -0.2 -0.6 -1.4	-1 -1 -0 -0 -0 0. 0. 0.
1825 1850 1900 2000 2050 2100 2150 2200 2250 2350 2400 2450 2500	41.9 41.8 41.7 41.6 41.6 41.5 41.4 41.4 41.4 41.3 41.2 41.1 41.1	13.8 13.7 13.7 13.6 13.6 13.5 13.5 13.5 13.5 13.5 13.5 13.5 13.5	1.41 1.42 1.48 1.51 1.55 1.58 1.62 1.65 1.69 1.72 1.76 1.80 1.80 1.84	40.0 40.0 40.0 39.9 39.8 39.7 39.6 39.6 39.6 39.5 39.4 39.3	1.40 1.40 1.40 1.40 1.44 1.49 1.53 1.58 1.62 1.67 1.71 1.76	4.7 4.5 4.3 4.0 4.2 4.2 4.2 4.2 4.4 4.4 4.4 4.4 4.6	0.7 1.4 3.6 5.7 7.9 7.3 6.1 5.7 4.6 4.2 3.2 2.9 2.5	-15.0 g 5200 5250 5300 5500 5500 5500 5500 5600 6000 6500 7000	36.3 36.2 36.1 35.8 35.6 35.4 35.2 34.9 34.0 33.1	15.8 15.9 16.1 16.2 16.3 16.5 16.9	Freque 4.57 4.63 4.69 4.92 5.04 5.15 5.27 5.50 6.12 6.74	ancy MHz 36.0 35.9 35.9 35.6 35.5 35.4 35.3 35.1 34.5 33.9	4.66 4.71 4.76 5.07 5.17 5.27 5.48 6.07 6.65	0.9 0.8 0.7 0.3 0.1 0.0 -0.2 -0.6 -1.4 -2.3	-1 -1 -0 -0 -0 -0 .0 .0 .0 .0 .1 .1.
1825 1850 1900 2000 2050 2100 2150 2200 2250 2350 2400 2450 2500	41.9 41.8 41.7 41.6 41.6 41.5 41.4 41.4 41.4 41.3 41.2 41.1 41.1 41.1	13.8 13.7 13.7 13.6 13.6 13.5 13.5 13.5 13.5 13.5 13.5 13.5 13.5	1.41 1.42 1.45 1.51 1.55 1.58 1.62 1.65 1.69 1.72 1.76 1.80 1.84 1.88	40.0 40.0 40.0 39.9 39.8 39.7 39.6 39.6 39.6 39.5 39.4 39.3 39.2	1.40 1.40 1.40 1.40 1.44 1.49 1.53 1.58 1.62 1.67 1.71 1.76 1.80	4.7 4.5 4.3 4.0 4.2 4.2 4.2 4.2 4.2 4.2 4.4 4.4 4.4 4.4	0.7 1.4 3.6 5.7 7.9 7.3 6.1 5.7 4.6 4.2 3.2 2.9 2.5 2.2	-15.0 5200 5250 5300 5600 5700 5800 6000 6500 7000 7500	36.3 36.2 36.1 35.8 35.6 35.4 35.2 34.9 34.0 33.1 32.2	15.8 15.9 16.1 16.2 16.3 16.5 16.9 17.3 17.6	Freque 4.57 4.63 4.69 4.92 5.04 5.15 5.27 5.50 6.12 6.74 7.36	36.0 35.9 35.9 35.6 35.5 35.4 35.3 35.1 34.5 33.9 33.3	4.66 4.71 4.76 5.07 5.17 5.27 5.48 6.07 6.65 7.24	0.9 0.8 0.7 0.3 0.1 0.0 -0.2 -0.6 -1.4 -2.3 -3.2	-1 -1 -0 -0 -0 0. 0. 0. 1. 1. 1.
1825 1800 1900 2000 2010 2100 2100 2200 2200 2300 2300 2400 2500	41.9 41.8 41.7 41.6 41.6 41.5 41.4 41.4 41.3 41.2 41.1 41.1 41.0 40.9	13.8 13.7 13.7 13.6 13.6 13.5 13.5 13.5 13.5 13.5 13.5 13.5 13.5	1.41 1.42 1.45 1.48 1.51 1.55 1.58 1.62 1.65 1.69 1.72 1.76 1.80 1.84 1.88 1.92	40.0 40.0 40.0 40.0 39.9 39.8 39.7 39.6 39.6 39.5 39.4 39.3 39.2 39.2	1.40 1.40 1.40 1.40 1.44 1.49 1.53 1.58 1.62 1.67 1.71 1.76 1.80 1.85	4.7 4.5 4.3 4.0 4.2 4.2 4.2 4.2 4.2 4.4 4.4 4.4 4.4 4.4	0.7 1.4 3.6 5.7 7.9 7.3 6.1 5.7 4.6 4.2 3.2 2.9 2.5 2.2 1.4	-15.0 5200 5250 5300 5500 5500 5500 5700 5800 6000 6500 7000 7500 8000	36.3 36.2 36.1 35.8 35.6 35.4 35.2 34.9 34.0 33.1 32.2 31.4	15.8 15.9 15.9 16.1 16.2 16.2 16.3 16.5 16.9 17.3 17.6 17.9	Freque 4.57 4.63 4.92 5.04 5.15 5.27 5.50 6.12 6.74 7.36 7.97	36.0 35.9 35.9 35.6 35.5 35.4 35.3 35.1 34.5 33.9 33.3 32.7	4.66 4.71 4.76 5.07 5.17 5.27 5.48 6.07 6.65 7.24 7.84	0.9 0.8 0.7 0.3 0.1 0.0 -0.2 -0.6 -1.4 -2.3 -3.2 -4.1	-1 -1 -0 -0 -0 -0 0. 0. 1. 1. 1. 1.
1825 1850 1900 2000 2000 2100 2100 2150 2200 2250	41.9 41.8 41.7 41.6 41.5 41.4 41.5 41.4 41.3 41.2 41.1 41.1 41.0 40.9 40.8	13.8 13.7 13.7 13.6 13.6 13.5 13.5 13.5 13.5 13.5 13.5 13.5 13.5	1.41 1.42 1.45 1.45 1.45 1.51 1.55 1.58 1.62 1.65 1.69 1.72 1.80 1.84 1.84 1.92 1.92	40.0 40.0 40.0 40.0 39.9 39.8 39.7 39.6 39.7 39.6 39.5 39.4 39.3 39.2 39.2 39.2	1.40 1.40 1.40 1.40 1.44 1.49 1.53 1.58 1.62 1.67 1.71 1.76 1.80 1.85 1.91	4.7 4.5 4.3 4.0 4.2 4.2 4.2 4.2 4.2 4.4 4.4 4.4 4.4 4.6 4.6 4.5 4.4	0.7 1.4 3.6 5.7 7.9 7.3 6.1 5.7 4.6 4.2 3.2 2.9 2.9 2.2 1.4 0.6	-15.0 5250 5300 5500 5500 5500 5500 6000 6500 7000 7500 8000 8500	36.3 36.2 36.1 35.8 35.6 35.4 35.2 34.9 34.0 33.1 32.2 31.4 30.5 <th< td=""><td>15.8 15.9 15.9 16.1 16.2 16.2 16.3 16.5 16.9 17.3 17.6 17.9 18.2</td><td>Freque 4.57 4.63 4.92 5.04 5.15 5.27 5.50 6.12 6.74 7.36 7.97 8.59</td><td>36.0 35.9 35.9 35.6 35.5 35.4 35.3 35.1 34.5 33.9 33.3 32.7 32.1</td><td>4.66 4.71 4.76 4.96 5.07 5.17 5.27 5.48 6.07 6.65 7.24 7.84 8.45</td><td>0.9 0.8 0.7 0.3 0.1 0.0 -0.2 -0.6 -1.4 -2.3 -3.2 -4.1 -5.0</td><td>-1 -1 -0 -0 -0 -0 .0 .0 .0 .0 .0 .0 .1</td></th<>	15.8 15.9 15.9 16.1 16.2 16.2 16.3 16.5 16.9 17.3 17.6 17.9 18.2	Freque 4.57 4.63 4.92 5.04 5.15 5.27 5.50 6.12 6.74 7.36 7.97 8.59	36.0 35.9 35.9 35.6 35.5 35.4 35.3 35.1 34.5 33.9 33.3 32.7 32.1	4.66 4.71 4.76 4.96 5.07 5.17 5.27 5.48 6.07 6.65 7.24 7.84 8.45	0.9 0.8 0.7 0.3 0.1 0.0 -0.2 -0.6 -1.4 -2.3 -3.2 -4.1 -5.0	-1 -1 -0 -0 -0 -0 .0 .0 .0 .0 .0 .0 .1

TSL Dielectric Parameters

Figure B-3 600 – 5800 MHz Head Tissue Equivalent Matter

	FCC ID: A3LSMA426U		SAMSUNG	Approved by: Quality Manager
	Test Dates:	DUT Type:		APPENDIX B:
	1/21/2021 – 3/2/2021	Portable Handset		Page 3 of 3
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APPENDIX C: SAR SYSTEM VALIDATION

Per FCC KDB Publication 865664 D02v01r02, SAR system validation status should be documented to confirm measurement accuracy. The SAR systems (including SAR probes, system components and software versions) used for this device were validated against its performance specifications prior to the SAR measurements. Reference dipoles were used with the required tissue- equivalent media for system validation, according to the procedures outlined in FCC KDB Publication 865664 D01v01r04 and IEEE 1528-2013. Since SAR probe calibrations are frequency dependent, each probe calibration point was validated at a frequency within the valid frequency range of the probe calibration point, using the system that normally operates with the probe for routine SAR measurements and according to the required tissue-equivalent media.

A tabulated summary of the system validation status including the validation date(s), measurement frequencies, SAR probes and tissue dielectric parameters has been included.

	SAR System validation Summary – 1g													
SAR	Freq.		Probe	aha		Cond.	Perm.	CW	VALIDATI	ON	MOD	VALIDATIO	ON	
System	(MHz)	Date	SN	Probe C	Probe Cal Point		(Er)	SENSITIVITY	PROBE LINEARITY	PROBE ISOTROPY	MOD. TYPE	DUTY FACTOR	PAR	
М	3700	2/25/2021	7570	3700	Head	3.069	37.912	PASS	PASS	PASS	TDD	PASS	N/A	
М	1750	1/22/2021	7570	1750	Body	1.470	53.337	PASS	PASS	PASS	N/A	N/A	N/A	
Ν	1750	12/11/2020	7526	1750	Body	1.457	53.432	PASS	PASS	PASS	N/A	N/A	N/A	
М	1900	1/27/2021	7570	1900	Body	1.557	55.755	PASS	PASS	PASS	GMSK	PASS	N/A	

Table C-1 SAR System Validation Summary – 1g

NOTE: While the probes have been calibrated for both CW and modulated signals, all measurements were performed using communication systems calibrated for CW signals only. Modulations in the table above represent test configurations for which the measurement system has been validated per FCC KDB Publication 865664 D01v01r04 for scenarios when CW probe calibrations are used with other signal types. SAR systems were validated for modulated signals with a periodic duty cycle, such as GMSK, or with a high peak to average ratio (>5 dB), such as OFDM according to FCC KDB Publication 865664 D01v01r04.

PART 2 RF EXPOSURE EVALUATION REPORT	Quality Manager
DUT Type: Portable Handset	APPENDIX C: Page 1 of 1

APPENDIX E: TEST SEQUENCES

- 1. Test sequence is generated based on below parameters of the DUT:
 - a. Measured maximum power (Pmax)
 - b. Measured Tx_power_at_SAR_design_target (Plimit)
 - c. Reserve_power_margin (dB)
 - P_{reserve} (dBm) = measured P_{limit} (dBm) Reserve_power_margin (dB)
 - d. SAR_time_window (100s for FCC)
- 2. Test Sequence 1 Waveform:

Based on the parameters above, the Test Sequence 1 is generated with one transition between high and low Tx powers. Here, high power = P_{max} ; low power = $P_{max}/2$, and the transition occurs after 80 seconds at high power P_{max} . As long as the power enforcement is taking into effective during one 100s/60s time window, the validation test with this defined test sequence 1 is valid, otherwise, select other radio configuration (band/DSI within the same technology group) having lower P_{limit} for this test. The Test sequence 1 waveform is shown below:

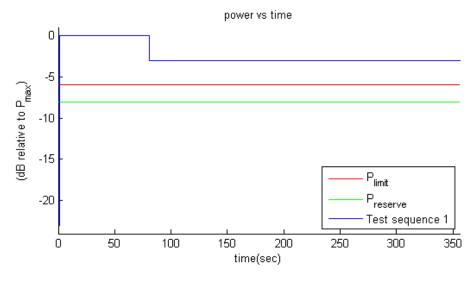


Figure E-1 Test sequence 1 waveform

	FCC ID: A3LSMA426U		SAMSUNG	Approved by: Quality Manager
	Test Dates:	DUT Type:		APPENDIX E:
	1/21/2021 - 3/2/2021	Portable Handset		Page 1 of 3
© 202	1 PCTEST			REV 1.0 04/06/2020

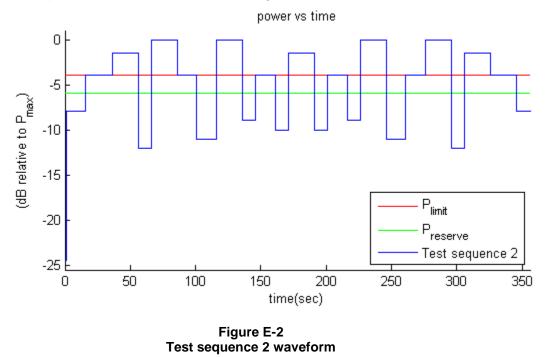
3. Test Sequence 2 Waveform:

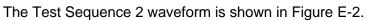
Based on the parameters described above, the Test Sequence 2 is generated as described in Table 10-1, which contains two 170 second-long sequences (yellow and green highlighted rows) that are mirrored around the center row of 20s, resulting in a total duration of 360 seconds:

Time duration (seconds)	dB relative to P _{limit} or P _{reserve}			
<mark>15</mark>	P _{reserve} – 2			
<mark>20</mark>	P _{limit}			
20	(<i>P_{limit}</i> + <i>P_{max})</i> /2 averaged in mW and rounded to nearest 0.1 dB step			
<mark>10</mark>	P _{reserve} – 6			
<mark>20</mark>	P _{max}			
<mark>15</mark>	P _{limit}			
<mark>15</mark>	P _{reserve} – 5			
20	P _{max}			
<mark>10</mark>	P _{reserve} – 3			
<mark>15</mark>	P _{limit}			
<mark>10</mark>	P _{reserve} – 4			
20	$(P_{limit} + P_{max})/2$ averaged in mW and rounded to nearest 0.1 dB step			
10	P _{reserve} – 4			
<mark>15</mark>	P _{limit}			
<mark>10</mark>	P _{reserve} – 3			
20	P _{max}			
<mark>15</mark>	P _{reserve} – 5			
<mark>15</mark>	P _{limit}			
20	P _{max}			
<mark>10</mark>	P _{reserve} – 6			
20	$(P_{limit} + P_{max})/2$ averaged in mW and rounded to nearest 0.1 dB step			
20	P _{iimit}			
<mark>15</mark>	P _{reserve} – 2			

Table E-1 Test Sequence 2

	FCC ID: A3LSMA426U	POCTEST [•] Poced to be part of @ element PART 2 RF EXPOSURE EVALUATION REPORT	Approved by: Quality Manager
	Test Dates:	DUT Type:	APPENDIX E:
	1/21/2021 – 3/2/2021	Portable Handset	Page 2 of 3
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	FCC ID: A3LSMA426U	POCTEST PART 2 RF EXPOSURE EVALUATION REPORT	Approved by: Quality Manager
	Test Dates:	DUT Type:	APPENDIX E:
	1/21/2021 – 3/2/2021	Portable Handset	Page 3 of 3
202	1 PCTEST		REV 1.0 04/06/2020

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APPENDIX F: TEST PROCEDURES FOR SUB6 NR + NR RADIO

Appendix F provides the test procedures for validating Qualcomm Smart Transmit feature for LTE + Sub6 NR non-standalone (NSA) mode transmission scenario, where sub-6GHz LTE link acts as an anchor.

F.1 Time-varying Tx power test for sub6 NR in NSA mode

Follows Section 4.2.1 to select test configurations for time-varying test. This test is performed with two pre-defined test sequences (described in Section 4.1) applied to Sub6 NR (with LTE on all-down bits or low power for the entire test after establishing the LTE+Sub6 NR call with the callbox). Follow the test procedures described in Section 4.3.1 to demonstrate the effectiveness of power limiting enforcement and that the time averaged Tx power of Sub6 NR when converted into 1gSAR values does not exceed the regulatory limit at all times (see Eq. (1a) and (1b)). Sub6 NR response to test sequence1 and test sequence2 will be similar to other technologies (say, LTE), and are shown in Sections 9.1.6 and 9.1.7.

F.2 Switch in SAR exposure between LTE vs. Sub6 NR during transmission

This test is to demonstrate that Smart Transmit feature accurately accounts for switching in exposures among SAR for LTE radio only, SAR from both LTE radio and sub6 NR, and SAR from sub6 NR only scenarios, and ensures total time-averaged RF exposure compliance with FCC limit.

Test procedure:

- 1. Measure conducted Tx power corresponding to P_{limit} for LTE and sub6 NR in selected band. Test condition to measure conducted P_{limit} is:
 - Establish device in call with the callbox for LTE in desired band. Measure conducted Tx power corresponding to LTE *P*_{limit} with Smart Transmit <u>enabled</u> and *Reserve_power_margin* set to 0 dB, callbox set to request maximum power.
 - Repeat above step to measure conducted Tx power corresponding to Sub6 NR <u>*Plimit*</u>. If testing LTE+Sub6 NR in non-standalone mode, then establish LTE+Sub6 NR call with callbox and request all down bits for radio1 LTE. In this scenario, with callbox requesting maximum power from Sub6 NR, measured conducted Tx power corresponds to radio2 <u>*Plimit*</u> (as radio1 LTE is at all-down bits)
- Set Reserve_power_margin to actual (intended) value with EUT setup for LTE + Sub6 NR call. First, establish LTE connection in all-up bits with the callbox, and then Sub6 NR connection is added with callbox requesting UE to transmit at maximum power in Sub6 NR. As soon as the Sub6 NR connection is established, request all-down bits on LTE link (otherwise, Sub6 NR will not have sufficient RF exposure margin to sustain the call with LTE in all-up bits). Continue LTE (all-down bits)+Sub6 NR transmission for more than one timewindow duration to test predominantly Sub6 NR SAR exposure scenario (as SAR exposure is negligible from all-down bits in LTE). After at least one time-window, request LTE to go allup bits to test LTE SAR and Sub6 NR SAR exposure scenario. After at least one more timewindow, drop (or request all-down bits) Sub6 NR transmission to test predominantly LTE

	FCC ID: A3LSMA426U	PART 2 RF EXPOSURE EVALUATION REPORT	SAMSUNG	Approved by: Quality Manager
	Test Dates:	DUT Type:		APPENDIX F
	1/21/2021 – 3/2/2021	Portable Handset		Page 1 of 2
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SAR exposure scenario. Continue the test for at least one more time-window. Record the conducted Tx powers for both LTE and Sub6 NR for the entire duration of this test.

- 2. Once the measurement is done, extract instantaneous Tx power versus time for both LTE and Sub6 NR links. Similar to technology/band switch test in Section 4.3.3, convert the conducted Tx power for both these radios into 1gSAR value (see Eq. (6a) and (6b)) using corresponding technology/band *P*_{limit} measured in Step 1, and then perform 100s running average to determine time-averaged 1gSAR versus time as illustrated in Figure 4-1. Note that here it is assumed both radios have Tx frequencies < 3GHz, otherwise, 60s running average should be performed for radios having Tx frequency between 3GHz and 6GHz.</p>
- 3. Make one plot containing: (a) instantaneous Tx power versus time measured in Step 2.
- Make another plot containing: (a) instantaneous 1gSAR versus time determined in Step 3, (b) computed time-averaged 1gSAR versus time determined in Step 3, and (c) corresponding regulatory 1gSAR_{limit} of 1.6W/kg.

The validation criteria is, at all times, the time-averaged 1gSAR versus time shall not exceed the regulatory *1gSAR*_{limit} of 1.6W/kg.

	FCC ID: A3LSMA426U		SAMSUNG	Approved by: Quality Manager
	Test Dates:	DUT Type:		APPENDIX F
	1/21/2021 - 3/2/2021	Portable Handset		Page 2 of 2
202	21 PCTEST			REV 1.0 04/06/2020

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APPENDIX G: CALIBRATION CERTIFICATES

Calibration Laboratory of Schmid & Partner Engineering AG Zeughausstrasse 43, 8004 Zurich, Switzerland

Accredited by the Swiss Accreditation Service (SAS)

The Swiss Accreditation Service is one of the signatories to the EA Multilateral Agreement for the recognition of calibration certificates

BC-MRA



S Schweizerischer Kalibrierdienst

- C Service suisse d'étalonnage
- S Servizio svizzero di taratura Swiss Calibration Service

Accreditation No.: SCS 0108

Client PC Test

Certificate No: 5G-Veri30-1045_Dec20

Dbject	5G Verification Source 30 GHz - SN: 1045						
			MARS sho				
Calibration procedure(s)	QA CAL-45.v3 Calibration procedure for sources in air above 6 GHz						
Calibration date:	December 10,						
The measurements and the unce	ertainties with confidence	national standards, which realize the physical units of e probability are given on the following pages and a atory facility: environment temperature (22 ± 3)°C at	re part of the certificate.				
Calibration Equipment used (M& Primary Standards	ID #) Cal Date (Certificate No.)	Scheduled Calibration				
Reference Probe EUmmWV3	22000 (1993) A	31-Dec-19 (No. EUmmWV3-9374_Dec19)	Dec-20 Aug-21				
Reference Probe EUmmWV3	SN: 9374 SN: 1602	31-Dec-19 (No. EUmmWV3-9374_Dec19) 11-Aug-20 (No. DAE4ip-1602_Aug20)	Dec-20 Aug-21				
Reference Probe EUmmWV3 DAE4ip	22000 (1993) A	· · · · · · · · · · · · · · · · · · ·					
	SN: 1602	11-Aug-20 (No. DAE4ip-1602_Aug20)	Aug-21				
Reference Probe EUmmWV3 DAE4ip	SN: 1602	11-Aug-20 (No. DAE4ip-1602_Aug20) Check Date (in house)	Aug-21 Scheduled Check				

Calibration Laboratory of Schmid & Partner Engineering AG Zeughausstrasse 43, 8004 Zurich, Switzerland





S

Schweizerischer Kalibrierdienst

C Service suisse d'étalonnage Servizio svizzero di taratura

S Swiss Calibration Service

Accreditation No.: SCS 0108

Accredited by the Swiss Accreditation Service (SAS) The Swiss Accreditation Service is one of the signatories to the EA Multilateral Agreement for the recognition of calibration certificates

Glossary

CW

Continuous wave

Calibration is Performed According to the Following Standards

- Internal procedure QA CAL-45-5Gsources
- IEC TR 63170 ED1, "Measurement procedure for the evaluation of power density related to human exposure to radio frequency fields from wireless communication devices operating between 6 GHz and 100 GHz", January 2018

Methods Applied and Interpretation of Parameters

- Coordinate System: z-axis in the waveguide horn boresight, x-axis is in the direction of the E-field, y-axis normal to the others in the field scanning plane parallel to the horn flare and horn flange.
- *Measurement Conditions: (1) 10 GHz:* The forward power to the horn antenna is measured prior and after the measurement with a power sensor. During the measurements, the horn is directly connected to the cable and the antenna ohmic and mismatch losses are determined by far-field measurements. (2) 30, 45, 60 and 90 GHz: The verification sources are switched on for at least 30 minutes. Absorbers are used around the probe cub and at the ceiling to minimize reflections.
- *Horn Positioning:* The waveguide horn is mounted vertically on the flange of the waveguide source to allow vertical positioning of the EUmmW probe during the scan. The plane is parallel to the phantom surface. Probe distance is verified using mechanical gauges positioned on the flare of the horn.
- E- field distribution: E field is measured in two x-y-plane (10mm, 10mm + λ/4) with a vectorial E-field probe. The E-field value stated as calibration value represents the E-field-maxima and the averaged (1cm² and 4cm²) power density values at 10mm in front of the horn.
- *Field polarization:* Above the open horn, linear polarization of the field is expected. This is verified graphically in the field representation.

Calibrated Quantity

Local peak E-field (V/m) and peak values of the total and normal component of the poynting vector [Re{S}] and n.Re{S} averaged over the surface area of 1 cm² (pStotavg1cm² and pSnavg1cm²) and 4cm² (pStotavg4cm² and pSnavg4cm²) at the nominal operational frequency of the verification source.

The reported uncertainty of measurement is stated as the standard uncertainty of measurement multiplied by the coverage factor k=2, which for a normal distribution corresponds to a coverage probability of approximately 95%.

Measurement Conditions

DASY system configuration, as far as not given on page 1.

DASY Version	cDASY6 Module mmWave	V2.0
Phantom	5G Phantom	
Distance Horn Aperture - plane	10 mm	
XY Scan Resolution	dx, dy = 2.5 mm	
Number of measured planes	2 (10mm, 10mm + λ/4)	
Frequency	30 GHz ± 10 MHz	

Calibration Parameters, 30 GHz

Distance Horn Aperture to Measured Plane	Prad ¹ (mW)	Max E-field (V/m)	Uncertainty (k = 2)	Avg Power Density n.Re{S}, Re{S} (W/m2)		Uncertainty (k = 2)
		22.7101		1 cm ²	4 cm ²	
10 mm	30.2	130	1.27 dB	37.7, 38.1	32.7, 33.2	1.28 dB

 $^{^{1}}$ derived from far-field data

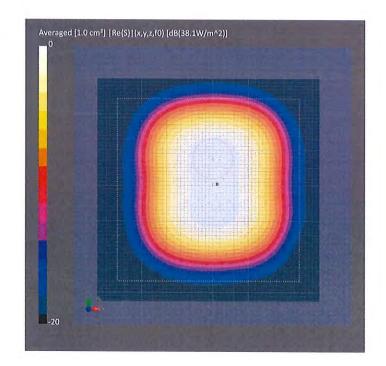
DASY Report

Measurement Report for 5G Verification Source 30 GHz, UID 0 -, Channel 30000 (30000.0MHz)

Device under Test Properties

Name, Manufacturer	Dimensions [mm]	IMEI	DUT Type	
5G Verification Source 30 G	Hz 100.0 x 100.0 x 1	100.0	SN: 1045	-	
Exposure Conditions					
Phantom Section	Position, Test Distance [mm]	Band	Group,	Frequency [MHz], Channel Number	Conversion Factor
5G -	5.55 mm	Validation band	CW	30000.0, 30000	1.0
Hardware Setup	Medium				
mmWave Phantom - 1002	Air		Probe, Calibra EUmmWV3 - 2019-12-31	ation Date SN9374_F1-78GHz,	DAE, Calibration Date DAE4ip Sn1602, 2020-08-11
Scan Setup			Measurem	ent Results	

	5G Scan		5G Scan
Grid Extents [mm]	60.0 x 60.0	Date	2020-12-10, 07:35
Grid Steps [lambda]	0.25 x 0.25	Avg. Area [cm ²]	1.00
Sensor Surface [mm]	5.55	pStot avg [W/m ²]	38.1
MAIA	MAIA not used	pSn avg [W/m ²]	37.7
		E _{peak} [V/m]	130
		Power Drift [dB]	-0.01



DASY Report

MAIA

Measurement Report for 5G Verification Source 30 GHz, UID 0 -, Channel 30000 (30000.0MHz)

Name, Manufacturer	Dimensions [mm		IMEI	DUT Type		
5G Verification Source 30 G	Hz 100.0 x 100.0 x 1	.00.0	SN: 1045	-		
Exposure Conditions						
Phantom Section	Position, Test Distance [mm]	Band	Group,	Frequency [MHz], Channel Number	Conversion I	actor
5G -	5.55 mm	Validation band	CW	30000.0, 30000	1.0	
Hardware Setup Phantom	Medium		Probe, Cali	bration Date	DAE, Calibration Date	3
mmWave Phantom - 1002	Air			3 - SN9374_F1-78GHz,	DAE4ip Sn1602, 2020-08-11	
Scan Setup		5G S		ment Results		
Grid Extents [mm]		60.0 x 6			2020-1	5G Scar
Grid Steps [lambda]		0.25 x 0.25 Avg. Area [cn		[cm ²]	2020-12-10, 07:35 4.00	
Sensor Surface [mm]			5.55 pStot avg			33.2

	5G Scan		5G Scan
m]	60.0 x 60.0	Date	2020-12-10, 07:35
oda]	0.25 x 0.25	Avg. Area [cm ²]	4.00
mm]	5.55	pStot avg [W/m ²]	33.2
	MAIA not used	pSn avg [W/m ²]	32.7
		E _{peak} [V/m]	130
		Power Drift [dB]	-0.01

